

# OPERATION MANUAL

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## TH2817B+

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LCR Meter

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**Announcement**

The description of the manual may not cover all contents of the instrument, and our company is subject to change and to improve the performance, function, inner structure, appearance, accessory and package of the instrument without notice. If there is puzzle caused by inconsistency of manual and instrument, then you can contact with our company by the address on the cover.

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# Chapter 1 Out of Box Audit

When you receive the instrument, some inspections are necessary, and the condition must be understood and available before installing the instrument.

## 1.1 To Inspect the package

Inspect the shipping container for damage after unpacking it. It is not recommended to power on the instrument in the case of a damaged container.

If the contents in the container do not conform to the packing list, notify us or your dealer.

## 1.2 Power connection

- 1) Power-supplying voltage range: 100~120Vac or 198~242Vac. It is related to the power settings on the rear panel.
- 2) Power-supplying frequency range: 47~63Hz.
- 3) Power-supplying power range: not less than 80VA.
- 4) Power supplying input phase line L, zero line N, ground lead E should be as same as the power plug of the instrument.
- 5) After careful design, the instrument can reduce the clutter jamming caused by AC power terminal input, however, it should be used under the environment with low-noise. Please install power filter if being unavoidable.

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**Warning: In order to prevent user and instrument from being hurt by leakage, it is necessary for user to guarantee the ground line of supply power being reliably grounded.**

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## 1.3 Fuse

The instrument has installed fuse, so operators should use the installed fuse of our company.

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**Warning: Be sure that the location of fuse is consistent with power-supplying voltage range before charging.**

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## 1.4 Environment

- 1) Please do not operate the instrument in the place that is vibrative, dusty, under direct sunlight or where there is corrosive air.

- 
- 2) The normal working temperature is  $0^{\circ}\text{C} \sim 40^{\circ}\text{C}$ , relative humidity  $\leq 75\%$ , so the instrument should be used under above condition to guarantee the accuracy.
  - 3) There is heat abstractor on the rear panel to avoid the inner temperature rising. In order to keep good airiness, please don't obstruct the left and right airiness holes to make the instrument maintain the accuracy.
  - 4) Although the instrument has been specially designed for reducing the noise caused by ac power, a place with low noise is still recommended. If this cannot be arranged, please make sure to use power filter for the instrument.
  - 5) Please store the instrument in the place where temperature is between  $5^{\circ}\text{C}$  and  $40^{\circ}\text{C}$ , humidity is less than 85%RH. If the instrument will not be put in use for a time, please have it properly packed with its original box or a similar box for storing.
  - 6) The instrument, especially the test cable should be far from strong electro-magnetic field, to avoid the jamming on measurement.

## 1.5 Use of Test Fixture

Please use the accessory test fixture or cable, **the test fixture made by user or from other company may cause the incorrect measurement result**. The test fixture or cable should be kept clean, as well as the pin of DUT, thus to guarantee the good connection between DUT and fixture.

Connect the fixture or cable to four test terminals Hcur, Hpot, Lcur, Lpot on the front panel. As for the DUT with shielding shell, connect shielding layer or ground “ $\perp$ ”.

Note: When test fixture or cable has not being installed, the instrument will display an unstable test result.

## 1.6 Warm-up

- 1) To guarantee the accurate measurement, the warm-up time is no less than 15min.
- 2) Please not turn on or off instrument frequently, in order to avoid the inner data fluster.

## 1.7 Other features

- 1) Power: consumption power  $\leq 80\text{VA}$
- 2) Dimension (W\*H\*D): 235mm\*105mm\*360mm
- 3) Rackmount Dimension (W\*H\*D): 215mm\*88mm\*335mm
- 4) Weight: About 3.6 kg



## Chapter 2 Introduction

In this chapter, the basic operation features of TH2817B+ series are described. Please read the content carefully before using TH2817B+ series instruments, thus you can learn the operation of TH2817B+.

### 2.1 Introduction to front panel

Figure 2-1 shows the front panel of TH2817B+.

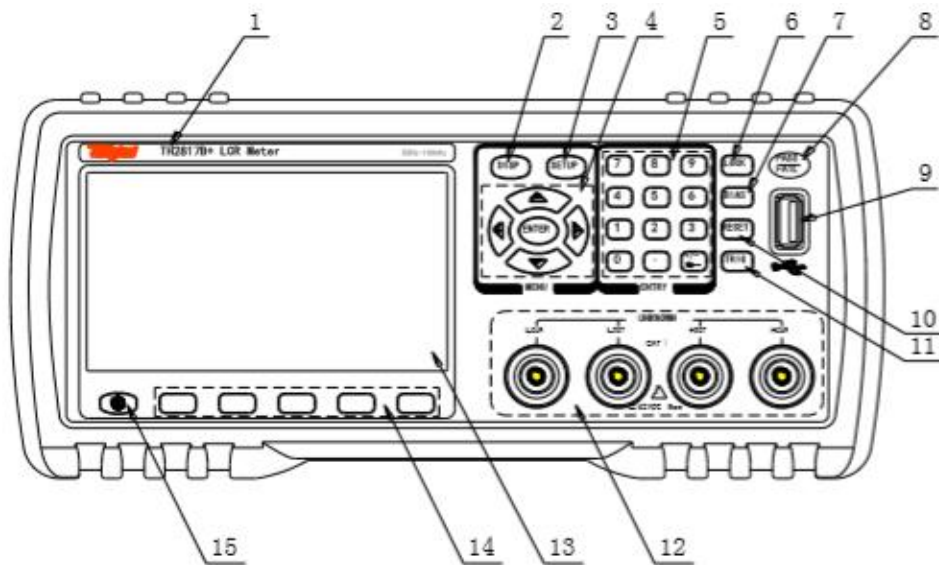


Figure 2-1 Front panel

- 1) Brand and model  
Brand and model.
- 2) [DISP]  
Press this key to enter into the corresponding measurement display page of instrument functions.
- 3) [SETUP]  
Press this key to enter into the corresponding measurement setup page of instrument functions.
- 4) CURSOR  
This key is used to move the cursor on the LCD displayed page. When the cursor moves to a zone, the corresponding zone will be lightened.
- 5) Numerical keys  
These keys are used to input data to the instrument. The key consists of numerical keys [0] to [9], decimal point [.] and [+/-] key.  
**(NOTE: long press [.] key is equivalent to copying screen function)** ←

- 
- 6) [KEYLOCK]  
Press [KEYLOCK], it will be lighted, which means the function of current panel is locked. Press it again, it will be off, which means discharging the lock status. If the password function is ON, it means correct password is necessary when discharging the key-lock, or the key cannot be unlocked.  
When the instrument is controlled by RS232, [KEYLOCK] will be lighted. Press [KEYLOCK] again, it will be off, which means returning to the local discharging lock status.
  - 7) [BIAS]  
This function key is reserved for future expansion.
  - 8) PASS/FAIL indicator  
PASS LED indicator shows the test result has passed.  
FAIL LED indicator shows the test result has failed.
  - 9) USB HOST interface  
Connect U flash disk so as to save or load the file.
  - 10) [RESET]  
Press this key to stop scanning only in transformer automatic scanning. No operation will be executed on other pages.
  - 11) [TRIGGER]  
When the trigger mode is set to MAN mode, press this key to trigger the instrument.
  - 12) Test terminals (UNKNOWN)  
4-terminal test pair is used to connect 4-terminal test fixture or cable to measure DUT.  
The 4 terminals are respectively as follows: Hcur, Hpot, Lpot and Lcur.
  - 13) LCD  
480\*272 colorful TFT LCD displays measurement results and conditions.
  - 14) Soft keys  
Five soft keys are used to select parameters. The corresponding function of each soft key has been displayed above. The function definition varies with different pages.
  - 15) POWER  
Power switch

## 2.2 Introduction to rear panel

Figure 2-2 shows the rear panel of TH2817B+.

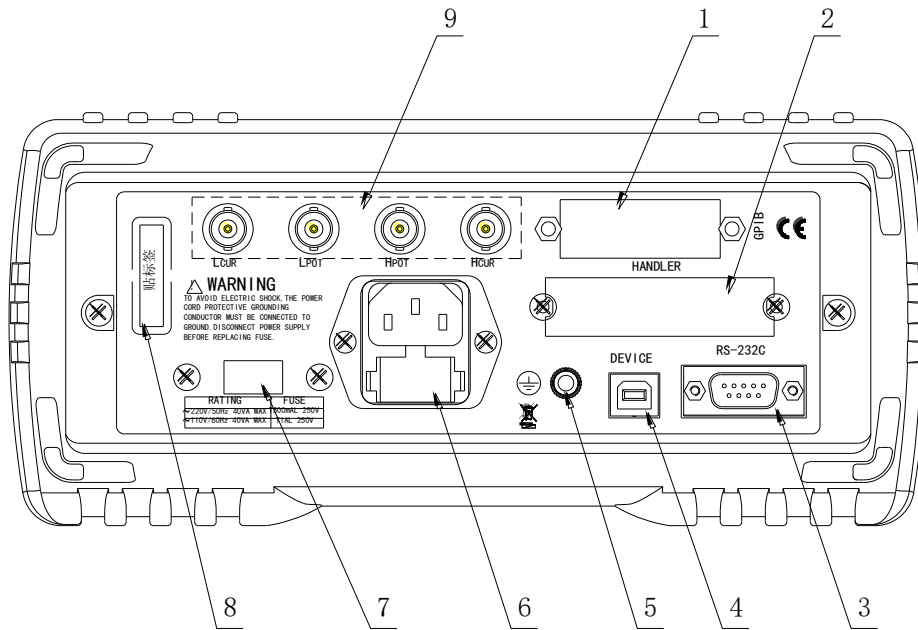


Figure 2-2 Rear panel

- 1) IEEE-488 (GPIB) interface  
The tester can communicate with PC through GPIB interface.
- 2) HANDLER interface  
Handler interface is used to realize the sorting output of test results.
- 3) RS232C interface  
Series communication interface can realize the communication with PC.
- 4) USB DEVICE interface  
The tester can communicate with PC through the USB DEVICE interface.
- 5) Ground terminal  
The ground terminal is connected with instrument casing, being available for protecting or shielding ground connection.
- 6) Power socket  
Input AC power.
- 7) Input power setting switch  
The instrument can be powered by 220Vac or 110Vac
- 8) Nameplate  
Information about production date, instrument number and manufacturer etc.

9) Rear panel output test terminals

The test terminal from the rear panel, which has the same function as the front panel test terminal. This interface is optional.

**Warning: Be sure that the direction of fuse is accordant with power-supply voltage range before charging.**

### 2.3 Introduction to display zone

TH2817B+ applies a 65k, 4.3-inch TFT display. The display screen is divided into the following zones:

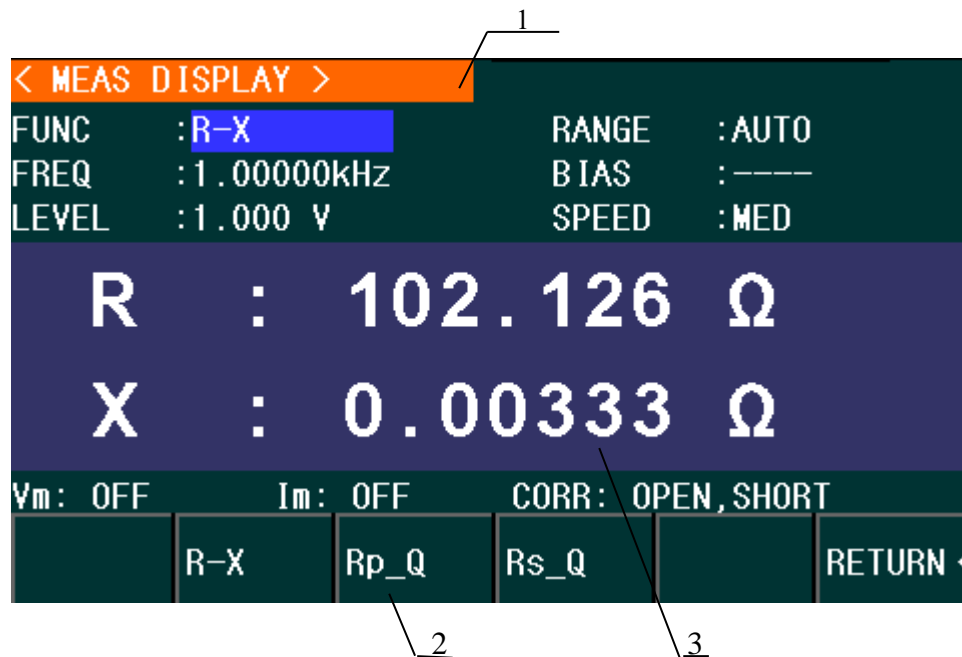


Figure 2-3 display zones

- 1) Display page name  
Indicate the name of the currently displayed page.
- 2) Soft keys  
The zone is used to display the function definition of soft key. The definition of soft key can be different as the difference of cursor's direction in the zone.
- 3) Test result/ condition display zone  
In this zone, test result information and current condition are displayed.

---

## 2.4 Main menu keys and corresponding displayed pages

### 2.4.1 [DISP]

When the LCR function is active, press this key-[DISP] to enter into the LCR measurement display page, the following soft keys will be displayed in the soft key zone.

<MEAS DISPLAY>

<BIN NO.>

<BIN COUNT>

<LIST SWEEP>

MORE ►

1/2

<FILE MANAGE>

<SAVE LOG>

MORE ►

2/2

---

**NOTE:** <SAVE LOG> key is valid in <MEAS DISPLAY> and <LIST SWEEP> interface. Press <SAVE LOG> after inserting the USB disk, the state changes to **ON** and the test data will be saved in .CSV format to the CSV directory in U disk. Press <SAVE LOG> again, the state changes to **OFF** and data storage is finished.

---

The instrument will automatically record the test data after inserting the USB disk in MEAS interface.

### 2.4.2 [PARAMETERS SETUP]

When the LCR function is active, press this key-[SETUP], the following soft keys will be displayed in the soft key zone on the LCR measurement setup page.

<MEAS SETUP>

<CORRECTION>

<LIMIT TABLE>

<LIST SETUP>

MORE ►

1/2

<FILE MANAGE>

<SYSTEM SETUP>

<TOOLS>

MORE ►

2/2

---

### 2.4.3 [SYSTEM SETUP]

This key-[SYSTEM SETUP] is used to enter into the system setup page. The following soft keys will be available:

<SYSTEM SETUP>

<MEAS SETUP>

<DEFAULT SETTING>

<SYSTEM RESET>

## 2.5 Basic Operation

Basic operation of TH2817B+ is as follows:

- Use menu keys ([DISP], [SETUP]) and soft keys to select the desired page.
- Use cursor keys ([←][→] [↑][↓]) to move the cursor to the desired zone. When the cursor moves to a specified zone, the zone will become reverse expression.
- The soft key functions corresponding to the current zone of the cursor will be displayed in the soft key zone. Users can select and use the desired soft keys, numeric keys, [+/- ←] to input data. When a numeric key is pressed down, the usable unit soft key will be displayed in the soft key zone. You can choose a unit soft key to end data inputting. [+/- ←] are used to input positive and negative data or delete data.

## 2.6 Start the instrument

Plug in 3-line power plug.

Caution: Keep the power-supply voltage and frequency conform to above specifications. Power input phase line L, zero line N, ground line E should be the same as that of the instrument.

Press the power switch at the left corner on the front panel and then a boot screen will appear which displays our company logo, instrument model, and the version number of the software.

TRIGGER = SETUP

**Tonghui** Share The Future Technology

# TH2817B+ LCR METER

Ver1.00 Copyright 2018-12-04  
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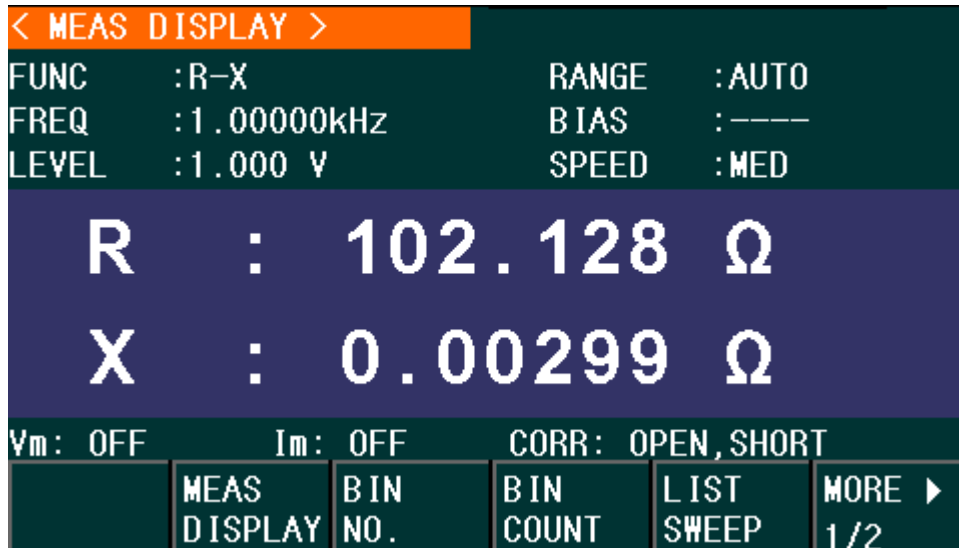
System Loading...

---

## Chapter 3 Introduction to [DISP]

### 3.1 <MEAS DISPLAY>

When the LCR function is applied, press [DISP], the <MEAS DISPLAY> page will be displayed on screen as shown in the following figure.



On this page, the test result is displayed in upper-case character. The measurement control parameters can be set on this page:

- Test function (FUNC)
- Test frequency (FREQ)
- Test level (LEVEL)
- Test range (RANGE)
- DC BIAS (BIAS)
- Test speed (SPEED)

There are 6 zones in this page: **FUNC**, **FREQ**, **LEVEL**, **RANG**, **BIAS** and **SPEED**. The details will be discussed later.

The test result/ condition display zone shows the information about test condition. These conditions can be set on <MEAS SETUP> page or <CORRECTION> page.

- Signal source voltage/ current monitor (**V<sub>m</sub>**, **I<sub>m</sub>**)
- Open, short, load correction ON/OFF status (**CORR**)

#### 3.1.1 Test function

In a measurement period, TH2817B+ can test two parameters for an impedance component: one primary parameter and one secondary parameter. Parameters that can be tested are as follows:

##### Primary parameters



- |Z| (Module of impedance)
- |Y| (Module of admittance)
- L (Inductance)
- C (Capacitance)
- R (Resistance)
- G (Conductance)

#### Secondary Parameters

- D (Dissipation factor)
- Q (Quality factor)
- $R_s$  (Equivalent Series Resistance ESR)
- $R_p$  (Equivalent Parallel Resistance EPR)
- X (Reactance)
- B (Susceptance)
- $\theta$  (Phase Angle)

Test results of primary and secondary parameters are respectively displayed in two lines in the form of upper-case characters. The primary parameter displays in the upper line while the secondary parameter displays in the lower line.

#### Operation steps for setting test function:

1) Move the cursor to FUNC zone, the following soft keys will be displayed on the screen.

- Cp-... ►
- Cs-... ►
- Lp-... ►
- Ls-... ►
- MORE ►
- 1/3

2) Press the soft key corresponding to Cp-... ►, the following parameters will be shown for your choice.

- Cp-D
- Cp-Q
- Cp-G
- Cp-Rp
- RETURN ◀
- Press the soft key corresponding to your desired parameter. Then press RETURN ◀ to return to upper soft key menu.

3) Press Cs-... ►, the following parameters will be shown for your choice.

- Cs-D
- Cs-Q
- Cs-Rs
- RETURN ◀
- Press the soft key corresponding to your desired parameter. Then press RETURN ◀ to return to upper soft key menu.

---

4) Press **Lp-... ▶**, the following parameters will be shown for your choice.

- **L<sub>p</sub>-Q**
- **L<sub>p</sub>-R<sub>p</sub>**
- **MORE ▶**  
**1/2**
- **RETURN ◀**

Press the soft key corresponding to your desired parameter. Then press **RETURN ◀** to return to upper soft key menu.

5) Press **MORE ▶**, the following parameters will be shown for your choice.

- **L<sub>p</sub>-D**
- **L<sub>p</sub>-G**
- **MORE ▶**  
**2/2**
- **RETURN ◀**

Press the soft key corresponding to your desired parameter. Then press **RETURN ◀** to return to upper soft key menu.

6) Press **Ls—... ▶**, the following parameters will be shown for your choice.

- **Ls-D**
- **Ls-Q**
- **Ls-Rs**
- **RETURN ◀**

Press the soft key corresponding to your desired parameter. Then press **RETURN ◀** to return to upper soft key menu.

7) Press **MORE ▶**, the following parameters will be shown for your choice.

- **Z—... ▶**
- **Y—... ▶**
- **R—... ▶**
- **G-B**

8) Press **Z—... ▶**, the following parameters will be shown for your choice.

- **Z-d**
- **Z-r**
- **RETURN ◀**

Press the soft key corresponding to your desired parameter. Then press **RETURN ◀** to return to upper soft key menu.

9) Press **Y—... ▶**, the following parameters will be shown for your choice.

- **Y-d**
- **Y-r**
- **RETURN ◀**

---

Press the soft key corresponding to your desired parameter. Then press **RETURN** ◀ to return to upper soft key menu.

10) Press **R—...▶**, the following parameters will be shown for your choice.

- **R-X**
- **Rp-Q**
- **R<sub>s</sub>-Q**
- **RETURN** ◀

Press the soft key corresponding to your desired parameter. Then press **RETURN** ◀ to return to upper soft key menu.

### 3.1.2 Test range

Measurement range should be selected in accordance with the impedance value of the tested LCR component.

TH2817B+ has 10 AC measurement ranges: 3Ω, 10Ω, 30Ω, 100Ω, 300Ω, 1kΩ, 3kΩ, 10kΩ, 30kΩ, 100kΩ.

#### Operation steps for setting test range:

- 1) Move the cursor to the **RANGE** zone, the following soft keys will be displayed:
  - **AUTO** The soft key is used to set the range mode to **AUTO**.
  - **HOLD** The soft key is used to switch the **AUTO** mode to the **HOLD** mode. When the range mode is set to **HOLD**, the range will be locked in the current measurement range. The current measurement range will be displayed in the range zone.
  - **DECR-** The soft key is used to decrease the range under **HOLD** mode.
  - **INCR+** The soft key is used to increase the range under **HOLD** mode.
- 2) Use soft keys to set measurement range.

### 3.1.3 Test frequency

The test frequency of the TH2817B+ series has four typical frequencies: 50Hz, 60Hz, 100Hz, 120Hz, 1kHz, 10kHz, 20kHz, 40kHz, 50kHz, 100kHz

#### Operation steps for setting test frequency:

TH2817B+ provides two methods to set measurement frequency. The first one is to use soft keys and the other one is to input data by using numeric keys.

- 1) Move the cursor to the **FREQ** zone, the following soft keys will be displayed.

- **INCR(++)**

This is a coarse adjustment soft key used to increase the frequency. Press this key, the frequency will change between the following 3 typical frequencies.

Model	Frequency point
TH2817B+	50Hz, 100Hz, 1kHz, 10kHz, 100kHz

---

- **INCR(+)**

This is a fine adjustment soft key used to increase the frequency. Each time this key is pressed, the frequency is increased to the next higher frequency point. The frequency points that can be set with this softkey are as follows:

50Hz, 60Hz, 100Hz, 120Hz, 1kHz, 10kHz, 20kHz, 40kHz, 50kHz, 100kHz

- **DECR(-)**

This is a fine adjustment soft key used to decrease the frequency. Each time this key is pressed, the frequency is increased to the next lower frequency point. The selectable frequencies are the same as that of **INCR(+)**.

- **DECR(--)**

This is a coarse adjustment soft key used to decrease the frequency. Each time this key is pressed, the frequency is increased to the next lower frequency point. The selectable frequencies are the same as that of **INCR(++)**.

- 2) Use soft keys or numeric keys to select or set frequency. When using numeric keys to input the required frequency value, the soft key displays the available frequency units (**Hz**, **kHz** and **MHz**). You can use unit soft key to input unit and data.

---

**NOTE: if the frequency point input is not within the frequency range, the value will be automatically modified to the nearest frequency point higher than the input frequency.**

---

### 3.1.4 Test level

The measurement level of TH2817B+ can be set according to the RMS value of sine wave signal. The frequency of sine wave signal is the test frequency which is generated by inner oscillator. You can set measurement voltage or current. The output impedance of TH2817B+ signal source can be 10Ω or 100Ω. The test level range is 0.1V, 0.3V, 1V.

#### Operation steps for setting test level:

TH2817B+ provides two methods to set the level of test signal source. The first one is to use soft keys, while the second one is to input data by numeric keys.

- 1) Move the cursor to **LEVEL**, the following soft keys will be displayed.

- **0.1V 0.3V 1V**

Press this softkey to select output level of the test signal source .

### 3.1.5 Test speed

The test speed of TH2817B+ is determined by the following factors:

- Integration time (A/D conversion)
- Average times (average test times per each test)
- Measurement delay (from startup to the start of measurement)

- 
- Display time of test results

You can select test mode as FAST, MED or SLOW. Generally, the test result is more stable and accurate in SLOW test mode.

#### Operation steps for setting test speed:

- 1) Move the cursor to **SPEED**, the following soft keys will be displayed:
  - **FAST**
  - **MED**
  - **SLOW**
- 2) Use above soft keys to set the test speed.

### 3.1.6 Tools

The test result of TH2817B+ is displayed as 6 floating-point digits. Decimal point lock function can make TH2817B+ output the test result in fixed way. Meanwhile this function can change the displayed count of test result.

#### Operation steps for tools

Set the display mode of decimal point in fixed mode according to the following operation steps.

- 1) Move the cursor to **MEAS RESULT DISP** zone, the following soft keys will be displayed:
  - **D.P. AUTO**
  - **D.P. FIX**
  - **D.P.POS INCR +**
  - **D.P.POS DECL-**
- 2) Press **D.P. AUTO** to reset the decimal position of the primary or the secondary parameter test result to its default setting.
- 3) Press **D.P. FIX** to lock the decimal location of primary or secondary parameter TEST result.
- 4) Press **D.P.POS INCR +** to increase the displayed digit by 1 digit.
- 5) Press **D.P.POS DECL -** to decrease the displayed digit by 1 digit.

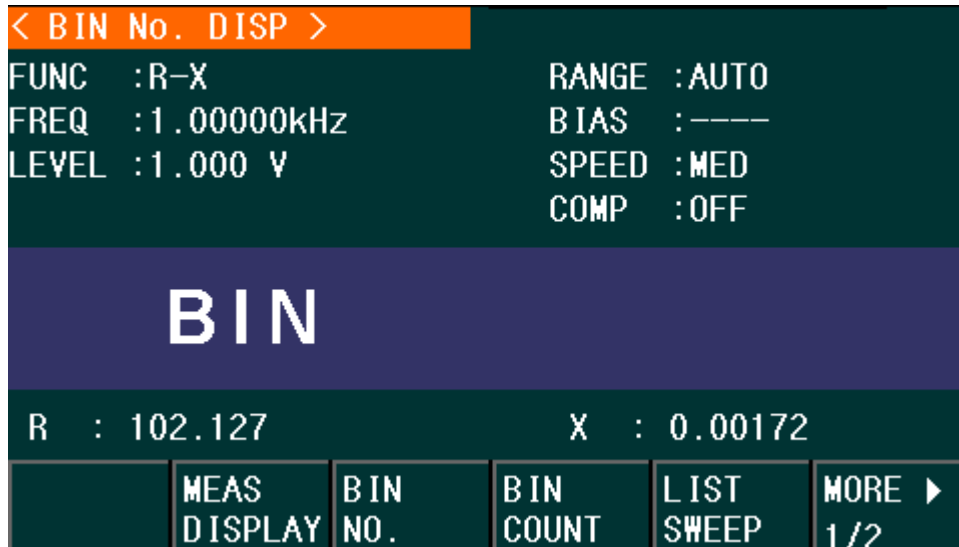
---

**NOTE:** Under the following circumstance, the function of decimal lock will be cancelled automatically to recover to floating decimal point status.

- Test function is changed.
  - In deviation test, the deviation test mode ( $\Delta$ ABS,  $\Delta$ %, OFF) is changed.
- 

## 3.2 <BIN NO. DISP>

Press [**DISP**] firstly and then the **BIN NO.** soft key to enter into <BIN NO. DISP> display page. On this page, BIN NO. is displayed in upper-case character while the test result, in lower-case character.



The following control parameters can be set on <BIN NO. DISP>.

- Compare function ON/OFF (COMP)

There are 2 zones: **BIN NO. DISP**, **COMP**. Their detailed information will be introduced as below. The following test conditions are displayed in the measurement result/condition zone. These zones cannot be set on this page but can be set on <MEAS SETUP>, <MEAS DISP> or <CORRECTION>.

- Test function (FUNC )
- Test frequency (FREQ)
- Test level (LEVEL)
- Test range (RANGE)
- BIAS
- Test speed (SPEED)
- ON/OFF set state of OPEN, SHORT, LOAD (CORR)

### 3.2.1 Comparator function

TH2817B+ has an inserted compare function which can divide DUT to up to 10 bins (from BIN1 to BIN9 and BIN OUT). Users can set 9 pairs of primary parameter limit and one pair of secondary bin limit. The sorting and PASS/FAIL indication rules after the comparison function is turned on are as table below. When TH2817B+ has installed a HANDLER interface, the compare result will be output into the automatic test system and further realizing auto-sorting test. These limits can only be set on the <LIMIT TABLE SETUP> page. Users can set the compare function to ON or OFF in the **COMP** zone.

AUX ON	AUX ON	AUX OFF
Primary parameter PASS	BIN1~BIN9	BIN1~BIN9
Secondary parameter PASS	PASS	PASS
Primary parameter FAIL	BIN AUTO	BIN1~BIN9

Secondary parameter PASS	FAIL	FAIL
Primary parameter PASS	BIN AUX	BIN OUT
Secondary parameter FAIL	PASS	FAIL
Primary parameter FAIL	BIN AUTO	BIN AUTO
Secondary parameter FAIL	PASS	FAIL

### Operation steps for compare function

- 1) Move the cursor to **COMP**, the following soft keys will be displayed.
  - ON
  - OFF
- 2) Select one of above soft keys to set the compare function as ON or OFF.

### 3.3 <BIN COUNT DISP>

Press [**DISP**] and then select the soft key of **BIN COUNT** to enter into the <BIN COUNT> page which shows the count of each bin.

The screenshot shows the <BIN COUNT DISP> page with the following data:

< BIN COUNT DISP >			
PARAM: R-X	NOM. : 0.00000pΩ	COUNT: OFF	
BIN	LOW [Ω]	HIGH [Ω]	COUNT
1	---	---	0
2	---	---	0
3	---	---	0
4	---	---	0
5	---	---	0
6	---	---	0
7	---	---	0
8	---	---	0
9	---	---	0
2nd	---	---	[Ω]
AUX :	OFF	OUT :	0

At the bottom of the screen, there are soft keys: MEAS DISPLAY, BIN NO., BIN COUNT, LIST SWEEP, and MORE ► (1/2).

The following control parameters can be set on the <BIN COUNT> page.

- Count function ON/OFF (**COUNT**)

There are 2 zones are displayed in this page: **BIN COUNT DISP**, **COUNT**. The function of each zone will be introduced as below.

The following test result/ condition can be displayed in this page but cannot be set in this page. Users can set them on the <LIMIT TABLE SETUP> page.

- Test parameter (PARAM)
- Nominal value (NOM)
- Bin limit value (HIGH/ LOW)

---

### 3.3.1 PARAM

Parameter zone shows the “Function” parameter, if user selects primary and secondary parameter swap compare mode, the parameter will be displayed as swap parameter, such as: “Cp-D” is displayed as “D-Cp”, which means the current D is compared as primary parameter while Cp is compared as secondary parameter.

### 3.3.2 NOM.

Nominal parameter is the nominal value used to make bin compare.

### 3.3.3 BIN

This zone shows the bin number of the limit list. “2nd” means the secondary parameter limit.

### 3.3.4 HIGH/LOW

This zone shows the high and the low limits of the limit list.

### 3.3.5 COUNT

This zone shows the count value of the current bin.

### 3.3.6 AUX

This zone shows the count value of the auxiliary bin.

### 3.3.7 OUT

This zone shows the count value of the out bin.

#### Operation steps for bin count function:

Execute the following operations to set the bin count function ON/OFF on <BIN COUNT DISP> page.

- 1) On <BIN COUNT DISP> page, move the cursor to **COUNT** zone, the following soft keys will be displayed.
  - **ON**
  - **OFF**
  - **RESET COUNT**
- 2) Press the soft key **ON** to turn on the count function.
- 3) Press the soft key **OFF** to turn off the count function.



- 4) Press the soft key **RESET COUNT**, “⊙ : Reset count, Sure?” will be displayed in the help zone. Then the following soft keys will be displayed.
  - **YES**
  - **NO**
- 5) Press the soft key **YES** to reset all bin counts to 0.
- 6) Press the soft key **NO** to cancel the reset operation.

### 3.4 <LIST SWEEP DISP>

Press down the menu key [MEAS DISPLAY] and then the soft key LIST SWEEP to enter into the <LIST SWEEP DISP> page, shown as below.

< LIST SWEEP DISP >					
MODE :SEQ					
No.	FREQ[Hz]	LEVEL[V]	R [Ω]	X [Ω]	CMP
001	---	---	---	---	-
002	---	---	---	---	-
003	---	---	---	---	-
004	---	---	---	---	-
005	---	---	---	---	-
006	---	---	---	---	-
007	---	---	---	---	-
008	---	---	---	---	-
009	---	---	---	---	-
010	---	---	---	---	-

MEAS DISPLAY	BIN NO.	BIN COUNT	LIST SWEEP	MORE ▶ 1/2
-----------------	------------	--------------	---------------	---------------

Test points will be automatically tested in a scanning mode. Meanwhile, comparison will be made between test results and limit values. In the process of list sweep test, “▶” denotes the current sweep test point. The following control parameters can be set on <LIST SWEEP DISP>.

- Sweep mode (**MODE**)

There are 2 zones on this page: **LIST SWEEP DISP** and **MODE**. List sweep points cannot be set on this page but can be set on <LIST SWEEP SETUP>.

#### 3.4.1 Sweep mode

The list sweep function of TH2817B+ can make automatic sweep test for up to 10 points’ test frequencies, test levels. Two sweep modes are available on TH2817B+: SEQ and STEP. In SEQ mode, each press of [TRIGGER] will direct TH2817B+ to automatically test all list sweep test points. In STEP mode, each press of [TRIGGER] will direct TH2817B+ to test one list sweep point.

**NOTE:** When the trigger mode is set to INT, sweep test modes of SEQ and STEP will not be controlled by [TRIGGER].

---

When the trigger mode is set to **MAN**, **[TRIGGER]** can be used to trigger the list sweep test.

---

### **Operation steps for setting the list sweep mode:**

Set the sweep mode on the **<LIST SWEEP DISP>** page as **SEQ** or **STEP**.

- 1) On the **< LIST SWEEP DISP >** page, move the cursor to the **MODE** zone, the following soft keys will be displayed:
  - **SEQ**
  - **STEP**
- 2) Press **SEQ** to set the sweep mode as sequential sweep test mode.
- 3) Press **STEP** to set the sweep mode as single step sweep test mode.

### **3.4.2   FREQ (Hz)**

This zone shows the currently swept parameter mode and its unit. What right below this item are parameters of the sweep list.

### **3.4.3   R[:] X[:]**

This zone is the currently swept Function parameter and its unit. What right below this item are the sweep results.

### **3.4.4   CMP (Compare)**

This zone indicates the compare results of the currently swept points. L means the result is lower than the standard and H is higher than the standard, while “ ” is neither lower nor higher.

## **3.5   <MEASURE SETUP>**

Press **[SETUP]** to enter into the **<MEASURE SETUP>** page shown as below:

< MEASURE SETUP >					
FUNC	: R-X	RANGE	: AUTO		
FREQ	: 1.00000kHz	BIAS	: ----		
LEVEL	: 1.000 V	SPEED	: MED		
TRIG	: INT	AVG	: 1		
Rsou.	: 10Ω	Vm/Im	: OFF		
TRIG DLY	: 0ms	STEP DLY	: 0ms		
DEV A	: OFF	REF A	: 0.00000pΩ		
B	: OFF	B	: 0.00000pΩ		
	MEAS SETUP	CORREC TION	LIMIT TABLE	LIST SETUP	MORE ▶ 1/2

In this page, the following control parameters can be set. (Items in parenthesis can be set)

- Test function (**FUNC**)
- Test frequency (**FREQ**)
- Test level (**LEVEL**)
- Test range (**RANGE**)
- Test speed (**SPEED**)
- Trigger Mode (**TRIG**)
- Output Resistance (**Rsou.**)
- Average times (**AVG**)
- Voltage/Current Level Monitor ON/ OFF (**Vm/Im**)
- Trigger delay (**TRIG DLY**)
- Step delay (**STEP DLY**)
- Deviation Test Mode A (**DEV A**)
- Deviation Test Mode B (**DEV B**)
- Deviation Test Reference Value A (**REF A**)
- Deviation Test Reference Value B (**REF B**)

Some zones listed below are as same as that on <MEAS DISPLAY> page, so it is not necessary to introduce in this section, but others will be introduced briefly in the following sections.

- Test function (**FUNC**)
- Test frequency (**FREQ**)
- Test level (**LEVEL**)
- Test range (**RANGE**)
- Test speed (**SPEED**)

### 3.5.1 Trigger mode

There are 4 trigger modes on TH2817B+: INT, MAN, EXT and BUS.

When the trigger mode is set as INT, TH2817B+ will make sequential and repeated tests.

When the trigger mode is set as MAN, press [TRIGGER] once, TH2817B+ will make one test.

---

When the trigger mode is set as EXT, once the HANDLER interface receives a positive impulse, TH2817B+ will execute one measurement.

When the trigger mode is set as BUS, once the IEEE 488 interface receives a **TRIGGER** command, TH2817B+ will execute a test. The BUS mode cannot be set on the front panel.

---

**Note:** In the process of testing, when TH2817B+ receives a trigger signal, it will be ignored. So the trigger signal should be sent after the test is done.

When optional HANDLER interface triggers TH2817B+, the trigger mode is set as EXT.

---

### Operation steps for the trigger mode setup

Execute the operation of other trigger modes except BUS trigger. If BUS trigger mode is necessary, then use IEEE4888 interface to send **TRIGger:SOURce BUS** command.

- 1) Move the cursor to the **TRIGGER** zone, the following soft keys will be displayed:
  - **INT**
  - **MAN**
  - **EXT**
- 2) Use above soft keys to set the trigger mode.

### 3.5.2 Average

The AVERAGE function can calculate the average value of two or more test results. The average times can be set from 1 to 255 with an increase or decrease of 1.

Operation steps for setting test average times.

- 1) Move the cursor to the **AVG** zone, the following soft keys are displayed.
  - **INCR (+)**  
This key is used to increase the average times.
  - **DECR (-)**  
This key is used to decrease the average times.
- 2) Use above soft keys to set the average times.

### 3.5.3 Voltage/Current Level Monitor function

The level monitor function can monitor the real voltage across DUT or real current through DUT. The monitored voltage value is displayed in **Vm** zone on <MEASURE DISP> page while the monitored current value is in **Im** zone.

---

**Note:** The correction function can influence the level monitor function, so when the correction data changes the level monitor value will change. When the correction is switched between OPEN or SHOR or LOAD, the level monitor value will be influenced as well

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### Operation steps for setting the level monitor function

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Execute the following operation steps to set the level monitor function as ON or OFF.

- 1) Move the cursor to **Vm/Im** zone, the following soft keys will be displayed.
  - **ON**
  - **OFF**
- 2) Press **ON** to set the voltage monitor function as ON while press **OFF** to set the voltage monitor function as OFF.

### 3.5.4 Trigger Delay

TH2817B+ trigger delay means the delay time from triggering to test-start. Delay function can set the trigger delay time. When the list sweep test function is used, all set delay time will be delayed at each sweep test point. The range of the trigger delay time can be set from 0s to 60s with 1ms as the resolution. The trigger delay function is great useful when the instrument is applied in an auto test system. When the instrument is triggered by HANDLER interface, the trigger delay time can ensure DUT and test terminal has a reliable contact.

#### Operation steps for setting the delay function

Execute the following steps to set the measurement delay time.

- 1) Move the cursor to the **DELAY** zone.
- 2) Use numeric keys to input delay time. After pressing a numeric key, the following unit keys will be displayed.
  - **msec**
  - **sec**

### 3.5.5 Step delay

TH2817B+ step delay means the delay time from outputting drive signal to test-start. Delay function can set the step delay time. The range of the step delay time can be set from 0s to 60s with 1ms as the resolution. When measuring DCR or Rd parameter, such as Lp-Rd, the step delay time can ensure accurate measurement while alternate measuring inductive devices by two drive signals.

#### Operation steps for setting the delay function

Execute the following steps to set the measurement delay time.

- 1) Move the cursor to the **STEP DLY** zone.
- 2) Use numeric keys to input delay time. After pressing a numeric key, the following unit keys will be displayed.
  - **msec**
  - **sec**

### 3.5.6 Output impedance

TH2817B+ provides two output impedances for your choice: 100  $\Omega$  and 10  $\Omega$ . When testing inductance, it is necessary to input the same output impedance so as to make data comparison with

---

other instruments.

**Note: When an optional bias board is selected, only 100Ω is available.**

#### **Operation steps for setting output resistance**

Execute the following operations to set output impedance

- 1) Move the cursor to the **Rsou** zone, the following soft keys will be displayed.
  - **100 Ω**
  - **10 Ω**
- 2) Press **100Ω** to select the output impedance as 100Ω. Press **10Ω** to select the output impedance as 10Ω.

### **3.5.7 Deviation test function**

The deviation test function can make the deviation value (instead of real test value) be directly displayed on the screen. The deviation value is equivalent to the real test value subtracting the pre-set reference value. This function brings great convenience to observe variations of component parameters with temperature, frequency, bias. Bias test function can be used for primary or secondary parameter or primary and secondary parameters meanwhile. The instrument provides two deviation test modes as below:

- **ΔABS (Absolute Deviation mode)**

The deviation currently displayed is the difference between the test value of the DUT and the preset reference value. The formula of calculating ΔABS is as below:

$$\Delta\text{ABS} = X - Y$$

Where, X is the test value of DUT

Y is the preset reference value.

- **Δ% (Percentage deviation mode)**

The deviation currently displayed is the percentage of the difference between the test value of DUT and the preset reference value divided by the reference value. Its calculating formula is as below:

$$\Delta\% = (X - Y) / Y * 100[\%]$$

Where, X is the test value of DUT.

Y is the preset reference value.

#### **Operation steps for setting deviation test function**

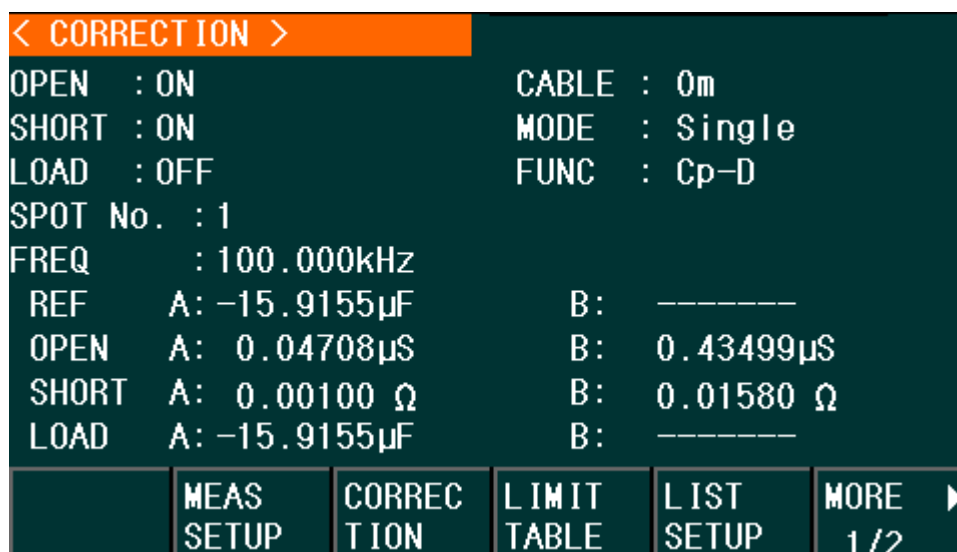
1. Move the cursor to the **REF A** zone to input the reference value of the primary parameter, the following soft key will be displayed.
  - **MEASURE**When the reference component is connected with the test terminal, you should press **MEASURE**. Then TH2817B+ will test the reference component and the test result will be automatically input as the value of **REF A**.
2. Use **MEASURE** or numeric keys to input the reference value of primary parameter.
3. Move the cursor to the **REF B** to input the reference value of the secondary parameter, the following soft key will be displayed.
  - **MEASURE**

When the reference component is connected to the test terminal, you should press **MEASURE**. Then TH2817B+ will test the reference component and the test result will be automatically input as the value of **REF B**.

4. Use MEAS or numeric keys to input the reference value of the secondary parameter. If the reference values of primary and secondary parameters have been set in steps 2), you can skip this step.
5. Move the cursor to the **DEV A** zone, the following soft keys will be displayed:
  - **ABS**
  - **%**
  - **OFF**
6. Use above soft keys to set the deviation mode of the primary parameter.
7. Move the cursor to the **DEV B** zone, the following soft keys will be displayed.
  - **ABS**
  - **%**
  - **OFF**
8. Use above soft keys to set the deviation mode of the secondary parameter.

### 3.6 <CORRECTION>

Press [SETUP] to select **CORRECTION** to enter into the <CORRECTION> page.



Open, short and load correction on the <CORRECTION> page can be used to eliminate the distribution capacitance, spurious impedance and other measurement errors. TH2817B+ provides two correction modes: the first one is executing open and short correction on all frequency points through interpolation method; the other one is executing open, short and load correction on the frequency point currently set. There are 10 calibration spots. The following measurement control parameters can be set on the <CORRECTION> page.

- Open correction (**OPEN**)
- Short correction (**SHORT**)
- Load correction (**LOAD**)
- Cable length selection (**CABLE**)

- Single/ multiple correction mode selection (**MODE**)
- Load correction test function (**FUNC**)
- Calibration spot numbers (**SPOT No.**)
- Frequency points of OPEN, SHOR and LOAD (**FREQ**)
- Reference values for frequency points ( **REF A, REF B**)
- Open values for frequency points (**OPEN A, OPEN B**)
- Short values for frequency points (**SHORT A, SHORT B**)
- Load values for frequency points (**LOAD A, LOAD B**)

There are 16 zones on this page: **Correction, Open, Short, Load, Cable, Mode, Function, SPOT No., FREQ, REFA, REF B, OPEN A, OPEN B, SHORT A, SHORT B, LOAD A, LOAD B**. Each control function zone will be introduced in the following paragraphs.

Besides above setting zones, the <CORRECTION> page will also display the following monitoring zones. The monitoring zones are similar with the setting zones, but the monitoring zones can only provide reference information and you cannot change state or parameter of these zones.

- Real test results of the open correction (**OPEN A, OPEN B**)
- Real test results of the short correction (**SHORT A, SHORT B**)
- Real test results of the load correction (**LOAD A, LOAD B**)

**NOTE:** The rule of user calibration is that if the open or short circuit is ON and the measurement frequency corresponding to the point frequency clearing is ON, the data of point frequency correction will be used first.

### 3.6.1 OPEN

The open correction function of TH2817B+ can eliminate the error caused by the stray admittance (G, B) parallel-connected with DUT, shown as figure 3-1 below.

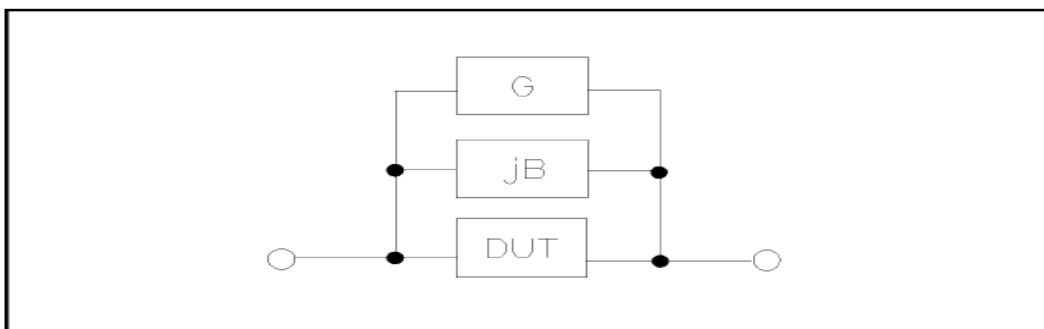


Figure 3-1 Stray Admittance

TH2817B+ adopts the following two kinds of open correction data:

- TH2817B+ will automatically make open correction test on 10 fixed frequency points within 50Hz~100kHz, no matter what the currently set frequency is. Move the cursor to **OPEN** and then used **MEAS OPEN** to execute full frequency open correction.
- 10 open correction spots can be set in **FREQ** and **SPOT No.** on <CORRECTION>. Move the cursor to **FREQ** and then use the **MEAS OPEN** soft key to execute open correction at the currently set frequency respectively.



---

### Operation steps of open correction function

The following steps are executing open correction on all frequency points through interpolation method. The operation method of open correction on single frequency, please refer to “load correction”.

1) Move the cursor to **OPEN**, the following soft keys will be displayed:

- **ON**
- **OFF**
- **MEAS OPEN**

2) Connect test fixture to test terminal. The fixture is open and not connecting to any DUT.

3) Press **MEAS OPEN**, TH2817B+ will test the open admittance (capacitance and inductance) under 4 frequencies. It will take about 4 seconds to finish the open full-frequency correction. In the process of correction, the following soft key will be displayed:

- **ABORT**

This soft key can be used to terminate the current open correction operation and reserve the formal open correction data.

4) Press **ON** to turn on the function of open-circuit correction, then TH2817B+ will perform open-circuit correction calculation in the later testing process. If **FREQ** is set as **OFF**, the open-circuit correction data of the current frequency will be calculated by interpolation method. When **FREQ** is set as **ON**, the value of the current test frequency will be that of **FREQ**, in this case, the open correction data of **FREQ** will be used to the calculation of open correction.

5) Press **OFF** to turn off the open correction function. In later measurement, no open correction calculation will be taken.

### 3.6.2 SHORT

The short correction function of TH2817B+ can eliminate the error caused by spurious inductance (R, X) in serial with DUT as shown in figure 3-1 below.

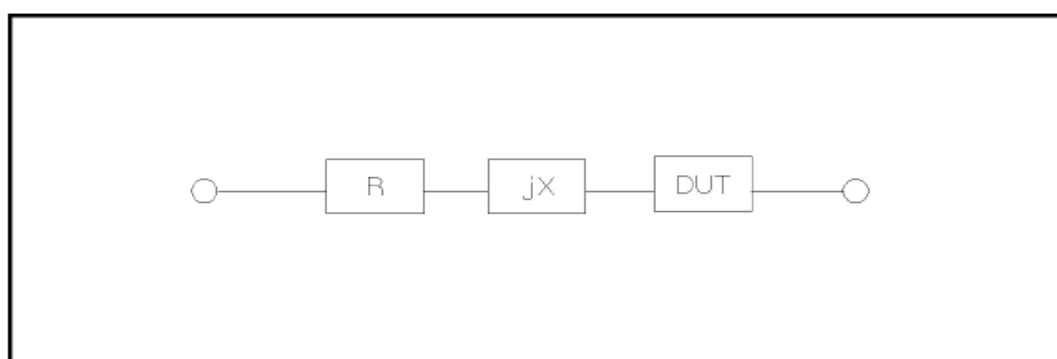


Figure 3-2 Spurious Inductance

TH2817B+ adopts two kinds of short correction data.

- TH2817B+ will automatically make short correction test on 10 fixed frequency points within 50Hz~100kHz, no matter what the currently set frequency is. Move the cursor to **SHORT** and then used **MEAS SHORT** to execute full frequency short correction.

- 10 short correction spots can be set in **FREQ** and **SPOT No.** on <CORRECTION>. Move the

---

cursor to **FREQ** and then use the **MEAS OPEN** soft key to execute short correction at the currently set frequency respectively.

### Operation steps of short correction function

The following steps are executing open correction on all frequency points through interpolation method. The operation method of open correction on single frequency, please refer to “load correction”.

- 1) Move the cursor to the **SHORT** zone, the following soft keys will be displayed:
  - **ON**
  - **OFF**
  - **MEAS SHORT**
- 2) Connect the test fixture to the test ports. Short the test fixture by using short plate.
- 3) Press the **MEAS SHORT** soft key, TH2817B+ will test the short spurious impedances (resistance and reactance) of 4 frequencies. Short full frequency correction takes about 4 seconds and in this process, the following soft keys will be displayed.
  - **ABORT**

This soft key can be used to cancel the current short correction operation and reserve the formal open correction data.
- 4) Press **ON** to validate the short correction function. TH2817B+ will make short correction calculation in latter test. If **FREQ** is set as OFF, the short-circuit correction data of the current frequency will be calculated by interpolation method. When **FREQ** is set as ON, the value of the current test frequency will be that of **FREQ**, in this case, the short correction data of **FREQ** will be used to the calculation of short correction.
- 5) Press **OFF** to turn off the short correction function. In latter test, no short correction calculation will be performed.

### 3.6.3 LOAD

By using transport coefficient between the real test value and the standard reference value at the preset frequency (**FREQ**), the load correction of TH2817B+ can eliminate the test error. It is obvious that open, short, and load correction can be performed at preset frequencies. 4 calculation points can be set in **SPOT No.** and the frequency can be set in the setup zones of **FREQ**. The standard reference values can be set in the setup zones of **REF A** and **REF B**. The standard test function must be set in the **FUNC** zone before setting standard reference value. When the cursor moves to **FREQ**, the **MEAS LOAD** soft key will be displayed. Press **MEAS LOAD** to perform the load correction test.

### Operation steps for setting load correction

According to the following steps, perform open/ short/ load correction test at preset frequencies.

- 1) Move the cursor to **FREQ**, the following soft keys will be displayed:
  - **ON**  
Press this soft key to make the open/short/load correction data be available.
  - **OFF**  
Press the soft key to make the open/short/load correction data be unavailable.

- 
- **MEAS OPEN**  
Press this soft key to execute open correction at **FREQ**.
  - **MEAS SHORT**  
Press this soft key to execute short correction at **FREQ**.
  - **MEAS LOAD**  
Press this soft key to execute the load correction at **FREQ**.
- 2) Press the soft key **ON**, the original preset open/short/load correction frequency is displayed on the frequency setting zone.
  - 3) Use numeric keys to input the correction frequency. After pressing any numeric key, the available unit keys (**Hz**, **kHz** and **MHz**) will be displayed on the soft key zone and press these soft keys to input correction frequency.
  - 4) Connect the test fixture to the test terminal.
  - 5) Make the test fixture be open.
  - 6) Press **MEAS OPEN** to perform open correction at the current set frequency. The test result (G, B) of the open correction test will be displayed in the help line (the bottom line).
  - 7) Move the cursor to **OPEN**.
  - 8) Press **ON** to perform the open correction calculation at preset frequency in latter measurements.
  - 9) Move the cursor to **FREQ** to set the required correction frequency.
  - 10) Make the test fixture be short.
  - 11) Press **MEAS SHORT** to perform short correction at preset frequency. The test result (R, X) of the short correction will be displayed in the help line (the bottom line).
  - 12) Move the cursor to **SHORT**.
  - 13) Press **ON** to perform the short correction calculation at preset frequency in latter measurements.
  - 14) Prepare a standard test component.
  - 15) Move the cursor to **FUNC**.
  - 16) Set the function parameters required to be set.
  - 17) Move the cursor to **REF A**.
  - 18) Use numeric keys and unit keys to input the primary reference values of the standard component.
  - 19) Move the cursor to **REF B**.
  - 20) Use numeric keys and unit keys to input the secondary reference value of the standard component.
  - 21) Move the cursor to the corresponding **FREQ**.
  - 22) Connect the standard component to the test fixture.
  - 23) Press **MEAS LOAD**, the instrument will execute a load correction. The real test results of the standard component will be displayed in **MEAS A** and **MEAS B**.
  - 24) Move the cursor to **LOAD**.
  - 25) Press **ON** to perform load correction calculation at preset frequencies in latter measurements.

### 3.6.4 Load correction test function

When performing load correction, the reference value of the standard component is required to be input in advance. The test parameters of reference value should be the same as the preset load correction test function.

Load correction function adopts the transport coefficient between the real test value of preset frequency and the standard reference value to eliminate the test error. Load correction function is only

available for calculating transport coefficient.

### 3.6.5 Point-frequency correction

The instrument provides 10 point frequency correction function. The specific steps refer to 3.6.3 load calibration process. Firstly, select the calibration point and then move the cursor to **FREQ**, select **ON** and input the corresponding frequency. Press **MEAS SHORT** to perform short correction at preset frequency. Press **MEAS OPEN** to perform open correction at the current set frequency.

**Note:** Since the status display of only one frequency point can be selected at a time, the complete status of 10 points could not be checked. Please pay attention to the problem, avoiding unknown error correction data reference.

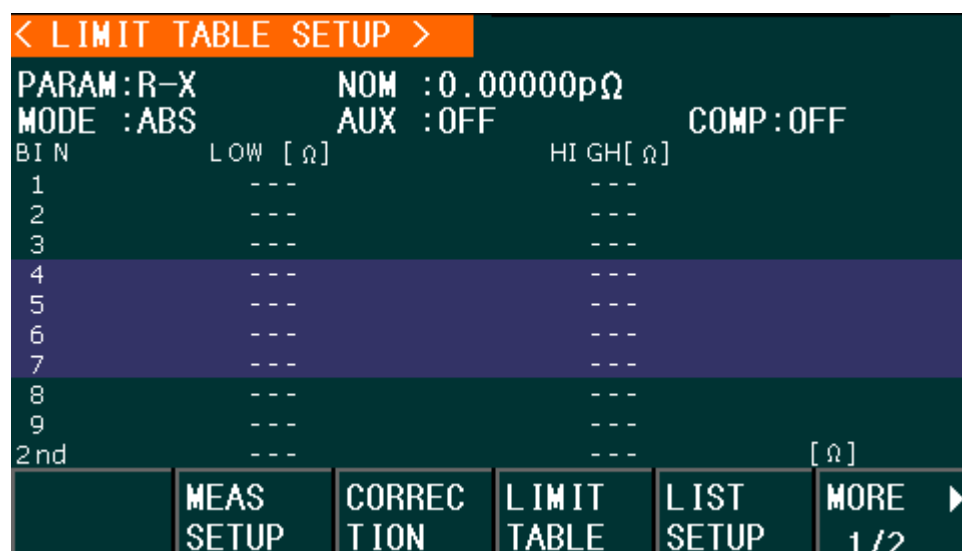
In response to the problem, the instrument provides rapid clearance and reset function for 10 dots of frequency correction data. With **CLEAR CORR** function in **TOOLS** page, you can reset and close the calibration data of 4 points.

### 3.6.6 Cable length selection

The available cable length is 0m.

## 3.7 <LIMIT TABLE>

Press **[SETUP]** and then **LIMIT TABLE** to enter into the **<LIMIT TABLE SETUP>** page as the following figure shown.



Compare function can be set on this page. TH2817B+ can set 9 bin limits of primary parameters and one of secondary parameters. The tested result can be divided into up to 10 bins (BIN 1 to BIN 9 and BIN OUT). If the primary parameter of DUT is within the limit range from BIN1 to BIN9, but the

---

secondary parameter is out of the limit range, in this case the DUT will be sorted into aux bin. When TH2817B+ installs the HANDLER interface and it is used in automatic sorting system, the compare function will be especially useful. The following limit parameter of compare function only be set on <LIMIT TABLE SETUP> page.

- Test parameter (**PARAM**)
- Limit mode of compare function (**MODE**)
- Nominal value (**NOM**)
- Auxiliary bin ON/OFF (**AUX**)
- Compare function ON/OFF (**COMP**)
- Low limit of each bin (**LOW**)
- High limit of each bin (**HIGH**)

### 3.7.1 Swap parameter

The swap parameter function can swap the primary and the secondary parameter in **PARAM**. For example, when the test parameter is Cp-D, the swap parameter function can change the test parameter as D-Cp. Then user can set 9 pairs of compare limits for D, but only 1 pair of compare limit can be set for Cp.

#### Operation steps for the swap parameter function

Execute the following operations to swap the primary and the secondary parameters.

- 1) Move the cursor to **PARAM**, the following soft key will be displayed.
  - **SWAP PARAM**
- 2) Press **SWAP PARAM** to swap the primary and the secondary parameters.
- 3) Press **SWAP PARAM** to swap the primary and the secondary parameter, which is to recover the formal setup.

### 3.7.2 Limit modes of compare function

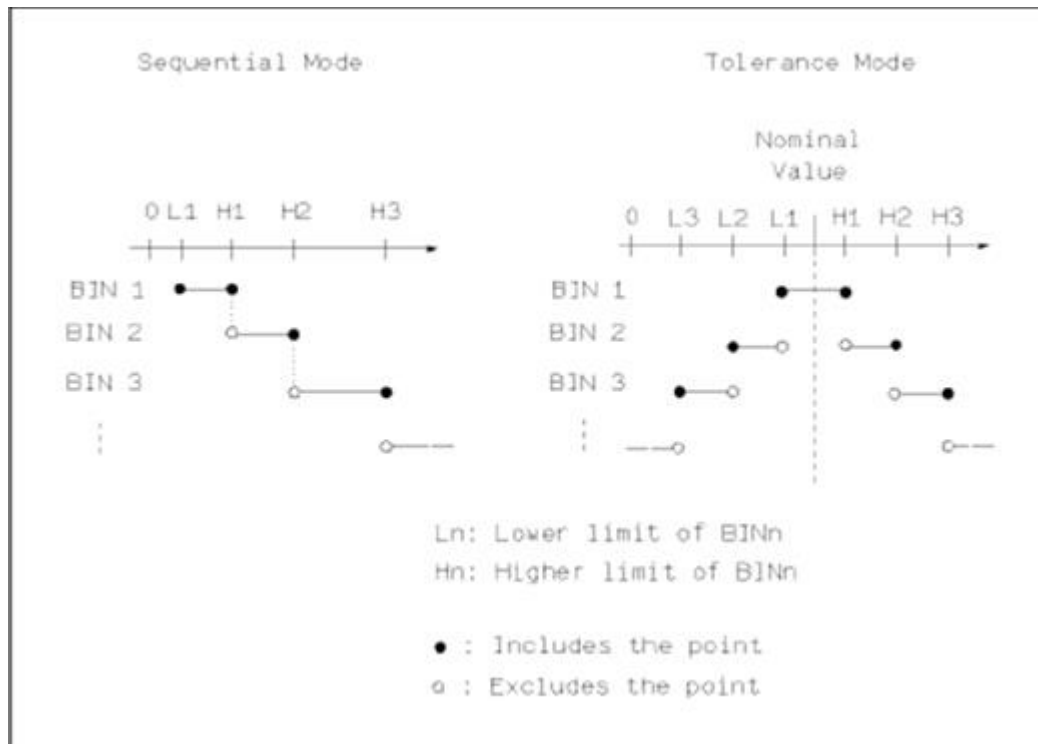
Compare functions has two limit setup modes for primary parameters as shown in figure 3-3.

#### ■ Tolerance mode

Under tolerance mode, set the deviation value of the nominal one (be set in the **NOM** zone) as the compare limit value. Deviation value has two modes: percentage deviation and absolute deviation.

#### ■ Sequential mode

Under sequential mode, the range of the test value is the compare limit value. The compare limit value should be set in the order from small to large.



**Figure 3-3 Tolerance mode and Sequential mode**

**Note:** When setting limit values of tolerance mode, the error range should be set in the order from small to large. If the error range of BIN1 is the largest one, then all DUT will sort into BIN 1. Under tolerance mode, the low limit is not necessary to be smaller than the nominal value and the high limit is not necessary to be larger than the nominal value. The limit range of each bin can be discontinues or overlapped.

**Operation steps for setting the limit mode of the compare function**

- 1) Move the cursor to the **MODE** zone, the following soft keys will be displayed.
  - **%TOL**  
This soft key is used to set the limit mode as the tolerance mode of percentage deviation (% TOL).
  - **ABS TOL**  
This soft key is used to set the limit mode as the tolerance mode of absolute deviation (ABS TOL).
  - **SEQ MODE**  
This soft key is used to set the limit mode as sequential mode.
- 2) Use above soft keys to set the limit mode.

**3.7.3 Set nominal value of tolerance mode**

When the tolerance mode is selected as the limit mode of the primary parameter, it is necessary to set the nominal value. The nominal value can be any one within the display range.

---

When the sequential mode is selected as the limit mode the primary parameter, the nominal value can be set, but it is not necessary to use it under this mode.

#### Operation steps for setting the nominal value

- 1) Move the cursor to **NOM**.
- 2) Use numeric keys to input nominal value. After inputting the data, the following soft keys (**p**, **n**, **u**, **m**, **k**, **M**, **\*1**) can replace the [ENTER] key to input the nominal value. When using [ENTER] to input the nominal value, the default unit is the same as that input last time. Press **\*1** to input nominal value, the instrument will select F, H or  $\Omega$  as the default unit of the nominal value according to primary parameter.

### 3.7.4 Comparator function ON/OFF

TH2817B+ can set 9 bin limits of primary parameters and 1 bin limit of secondary parameters. The tested results can be sorted into 10 bins (BIN 1 to BIN 9 and BIN OUT) at most. If the primary parameter of DUT is within the limit range from BIN 1 to BIN 9, but the secondary parameter is out of the limit range, in this case the DUT will be sorted into aux bin. When TH2817B+ installs the HANDLER interface and it is used in the automatic sorting system, the compare function will be especially useful.

#### Operation steps for setting the compare function ON/OFF

- 1) Move the cursor to **COMP**, the following soft keys will be displayed.
  - **ON**
  - **OFF**
- 2) Use above soft keys to set the compare function as ON or OFF.

### 3.7.5 Auxiliary bin ON/OFF

When it is necessary to sort the secondary parameters, the limits of the secondary parameter can be set in **HIGH** and **LOW** of the 2nd.

Three cases may occur in the process of secondary parameter sorting:

- On <LIMIT TABLE SETUP> page, no low / high limit of the secondary parameters has been set.
- On <LIMIT TABLE SETUP> page, the low/high limit of secondary parameters has been set but **AUX** function is set as OFF.

In this case, only those components whose secondary parameters are qualified can perform primary parameter sorting according to sorting limits. If the secondary parameters are unqualified and the corresponding primary parameters are within limit ranges, those components will be sorted into BIN OUT.

- On <LIMIT TABLE SETUP> page, the low/high limit of the secondary parameters has been set and the **AUX** function is set as ON.

If the primary parameter is out of the limit range, it is sorted into BIN OUT. If the primary parameter of DUT is within the limit range but its secondary parameter is out of the limit range, the DUT will be sorted into the **AUX** bin.

---

**Note:** When the secondary parameter only has low limit and the auxiliary bin is set as ON, if the primary parameter of DUT is within the limit range and the secondary parameter is smaller than or equal to its low limit, the DUT will be sorted into the auxiliary bin. When the secondary parameter only has high limit and the auxiliary bin is set as ON, if the primary parameter of DUT is within the limit range and the secondary parameter is larger than or equal to its high limit, the DUT will be sorted into the auxiliary bin.

---

### Operation steps for setting the auxiliary bin function ON/OFF

- 1) Move the cursor to **AUX**, the following soft keys will be displayed.
  - **ON**
  - **OFF**
- 2) Use above soft keys to set the **auxiliary function** as ON or OFF.

### 3.7.6 HIGH/LOW

TH2817B+ can set bin limits of 9 primary parameters and one secondary parameter. The test results can be sorted into 10 bins at most (BIN 1 to BIN 9 and BIN OUT). The high/low limits of primary parameters can be set in high limit and low limit of bins from BIN 1 to BIN 9. The limit of the secondary parameter can be set in **HIGH** and **LOW** of the 2<sup>nd</sup>.

### Operation steps for setting high/low limit

Execute the following steps to set sorting limits.

- 1) Set **PARAM** and **NOM** in the compare function menu and the limit **MODE** of the primary parameter.
- 2) Move the cursor to Low limit of BIN 1. If you select tolerance mode, the following operation steps should be from step 3 to step 6; if you select sequential mode, the following operation steps should be from step 7 to step 11.
- 3) User numeric keys to input low limit value in Low limit. After inputting the data, you can use (**p**, **n**, **μ**, **m**, **k**, **M**, **\*1**) to input the limit value. When pressing **\*1**, the default unit will be F, H or Ω. After inputting limit value in **LOW** of BIN 1, the low limit of BIN 1 will be automatically set as – (absolute limit) and the high limit will be + (absolute limit).
- 4) The cursor will automatically move to **LOW** of BIN 2. Repeat step 3 until the limits of BIN 9 are input. Then the cursor will automatically move **LOW** of the 2<sup>nd</sup>.
- 5) After inputting the low limit of the secondary parameter, the cursor will automatically move to **HIGH** of the 2<sup>nd</sup>.
- 6) Input the high limit of the secondary parameter.
- 7) In Low limit of BIN 1, use numeric keys to input the low limit. After inputting the data, you can use (**p**, **n**, **μ**, **m**, **k**, **M**, **\*1**) to input the limit value. When pressing **\*1**, the default unit will be F, H or Ω.
- 8) After inputting the low limit of BIN 1, the cursor will automatically move to **HIGH** of BIN 1. Input the high limit of BIN 1.
- 9) The cursor will automatically move **HIGH** of BIN 2. For the limit mode is sequential mode, the



low limit of BIN 2 will be the high limit of BIN 1. Input the high limit of BIN 2.

- 10) Repeat step 9 until the high limit of BIN 9 is input. Then the cursor will automatically move to **LOW** of 2<sup>nd</sup>. Input the low limit of the secondary parameter.
- 11) The cursor will automatically move to **HIGH** of the 2<sup>nd</sup>. Input the high limit of the secondary parameter.

### 3.8 <LIST SWEEP SETUP>

Press [SETUP] and then **LIST SETUP** to enter into the <LIST SWEEP SETUP> page as shown below.

< LIST SWEEP SETUP >						
MODE :SEQ						
No.	FREQ [Hz]	LEVEL [V]	LMT	LOW	HIGH	DELY [s]
001	---	---	--	---	---	---
002	---	---	--	---	---	---
003	---	---	--	---	---	---
004	---	---	--	---	---	---
005	---	---	--	---	---	---
006	---	---	--	---	---	---
007	---	---	--	---	---	---
008	---	---	--	---	---	---
009	---	---	--	---	---	---
010	---	---	--	---	---	---

MEAS SETUP    CORREC TION    LIMIT TABLE    LIST SETUP    MORE 1/2 ▶

The list sweep function of TH2817B+ can perform auto sweep test for the test frequency, test level or bias voltage of 4 points. On <LIST SWEEP SETUP> page, the following list sweep parameters can be set.

- Sweep mode (**MODE**)
- Sweep parameter setup (frequency [Hz], level [V], level [I], bias [V], bias [I])
- Sweep test point setup (sweep point)
- Selection of limit parameter (**LMT**)
- High/low limit (**HIGH**, **LOW**)

#### 3.8.1 MODE

Mode menu is the same as the mode on <List sweep display> page.

#### 3.8.2 Test parameter

Sweep parameters can be: frequency [Hz], level [V]. TH2817B+ provides double sweep parameters. The two parameters must be different and set values.

#### Operation steps for setting test parameter

- 1) Move the cursor the line following **MODE**; the following soft keys will be displayed.
  - **FREQ [Hz]**
  - **LEVEL [V]**
- 2) Press one of above soft keys to select the list sweep parameter.

### 3.8.3 Sweep parameter setup

Move the cursor to the table to perform the setup of each sweep parameter: **FREQ (HZ)**, **LMT**, **HIGH** and **LOW**. Use numeric keys on the front panel to input the data of test frequency/level/bias and high/low limit used to compare, as well as the selected primary/secondary use to compare. After setting, if some inputs are unnecessary, you can execute the function of “Delete line” in the soft key zone to delete the corresponding value.

In the bottom of the **LMT** zone, parameter A indicates that the primary parameters of the measurement result are use to compare with the high and low limits of the table. Parameter B indicates that the secondary parameters of the measurement result are used to compare with the high and low limits of the table. “---“ means no compare. The soft key zone has corresponding items. Press the soft key **LMT DATA A**, “A” will be displayed in the **LMT** zone. When press the soft key **LMT DATA B**, “B” will be displayed in the **LMT** zone. While press the soft key **OFF**, data in LMT zone and the corresponding high and low limits will be cleared and be displayed as “---”.

## 3.9 TOOLS

Press [SETUP] and press **TOOLS** to enter into the **<TOOLS>** page shown as below.



The TOOLS interface of TH2817B+ provides several specific functions and some custom design functions.

- CORR DATA
- NULL FIXTURE
- HOLD NOM RNG
- AUTO FETCH

---

### ■ HDL VALID TIME

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**Note:** After the hollow fixture is opened, when the data is read by the host computer, the return value will be zero. After the function is turned off, the return value returns to normal.

---

### 3.9.1 CORR DATA

Move the cursor to **CLEAR CORR**, press the soft key to clear all the correction data of 4 spots. The prompt box of operation instruction will be displayed.

### 3.9.2 NULL FIXTURE

This function helps check poor contact or short circuit conditions of the test fixture. If this function is enabled, the instrument automatically assumes NOM as the nominal value in the LIMIT TABLE interface, takes the value after the nominal value multiplied by 0.05 as the lower limit, and multiplies the nominal value by 100 as the upper limit. Values exceeding this upper and lower limit range are considered as open or short circuit of the fixture. The instrument will stop outputting the HANDLER sorting result signal to prevent the output of the wrong judgment result.

### 3.9.3 HOLD NOM RNG

This function is to lock the range for quick measurement. If this function is enabled, the instrument will lock the corresponding range according to the nominal value in the LIMIT TABLE interface, even if the range in the measurement setting interface is AUTO, the instrument will measure in locked range.

### 3.9.4 AUTO FETCH

This function works for data communication and transmits data through the RS-232C or USB interface. The general data transmission mode is to send the FETCH? command to the instrument and the instrument sends the measurement data through the communication port. Once AUTO FETCH is enabled, each measured data is automatically sent through the communication port without the FETCH? command.

**Note:** When using this function, please make sure the host computer is ready to accept the data continuously sent by the instrument.

### 3.9.5 HDL VALID TIME

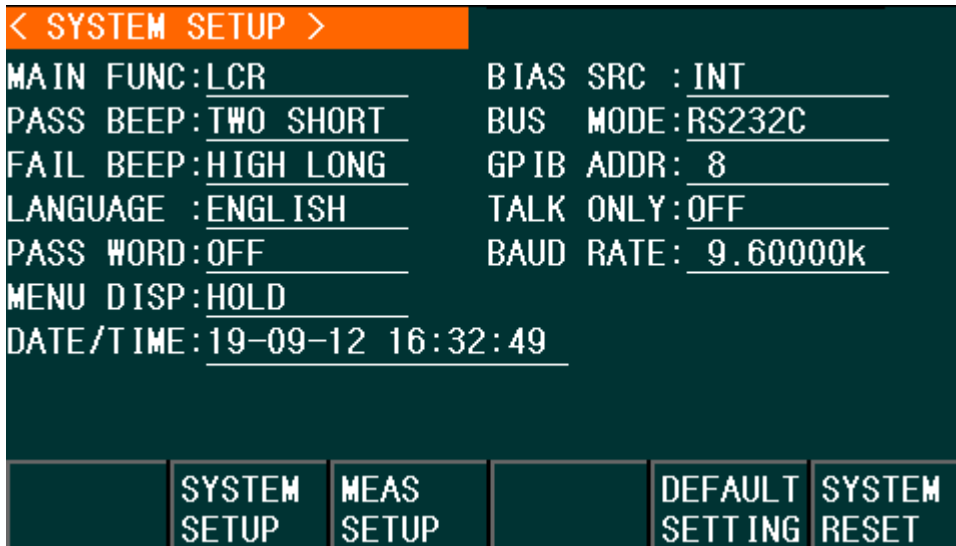
It is to set the level hold time for the output signal of the HANDLER interface. The HOLD state indicates that the output signal of the interface is maintained until there is a new change. Use the keyboard to input the hold time from 0 ~ 2S, 0 is the HOLD state.

---

## Chapter 4 [SYSTEM] and <FILE MANAGE>

### 4.1 <SYSTEM SETUP>

Press [SETUP] and then **SYSTEM SETUP** to enter into the <SYSTEM SETUP> page shown as below.



On this page, most system setup items are displayed, such as instrument main function, beeper, PASS beeper, FAIL beeper, language, PASS word, bus mode, GPIB address, TALK only, baud rate, menu display and data/time.

---

**NOTE:** system setup items will be saved automatically after finishing setting all the system items in this interface.

---

#### 4.1.1 MAIN FUNC

This item is reserved function.

#### 4.1.2 PASS BEEP

This zone is used to control and display the beep mode when the test result is qualified.

##### Operation steps for setting **PASS BEEP**

1) Move the cursor to **PASS BEEP**, the following soft keys will be displayed.

■ **HIGH LONG**

This soft key is used to select high and long beep.

■ **HIGH SHORT**

This soft key is used to select high and short beep.

---

- **LOW LONG**

This soft key is used to select low and long beep.

- **TWO SHORT**

This soft key is used to select two low and short beeps.

- **OFF**

This soft key is used to set the pass beep function OFF.

### 4.1.3 FAIL BEEP

This zone is used to control and display the beep mode as **FAIL BEEP** when the test result is unqualified.

#### Operation steps for setting **FAIL BEEP**

- 1) Move the cursor to **FAIL BEEP**, the following soft keys will be displayed.

- **HIGH LONG**

This soft key is used to select high and long beep.

- **HIGH SHORT**

This soft key is used to select high and short beep.

- **LOW LONG**

This soft key is used to select low and short beep.

- **TWO SHORT**

This soft key is used to select two low and short beeps.

- **OFF**

This soft key is used to set the fail beep mode OFF.

### 4.1.4 LANGUAGE

This zone is used to control and display the current language mode of the operating instrument.

#### Operation steps for setting language

- 1) Move the cursor to **LANGUAGE**, the following soft keys will be displayed.

- **ENGLISH**

This soft key is used to select English as the operation language.

- **CHINESE**

This soft key is used to select Chinese as the operation language.

### 4.1.5 PASS WORD

This zone is used to display the password-protection mode.

#### Operation steps for setting the password

- 1) Move the cursor to **PASS WORD**, the following soft keys will be displayed.

- **OFF**

This soft key is used to turn off the password protection mode.

- **LOCK SYSTEM**

This soft key is used to turn on the password protection function including file protection and

---

starting up password.

■ **LOCK FILE**

This soft key is used to protect user's file.

■ **MODIFY**

This soft key is used to modify the password. The operation steps are as follows:

Press **MODIFY** to input a new password. After inputting, the prompt information will appear on the screen to prompt you to confirm the new password. Input the new password again till the modification finishes.

---

Note: The default password is 0147852.

---

#### 4.1.6 BUS MODE

This mode is used to select RS232C, GPIB, USBTMC , USBCDC or RS485

##### Operation steps for setting bus mode

1) Move the cursor to **BUS**, the following soft keys will be displayed.

■ **RS232C**

■ **GPIB**

■ **USBTMC**

■ **USBCDC**

■ **RS485**

2) Use above soft keys to select the required interface bus.

---

**Note:** GPIB optional must be installed before GPIB mode is available, RS485 is also optional.

---

#### 4.1.7 GPIB ADDR (Reserved function)

This zone is used to control and display the current GPIB address.

Operation steps for setting GPIB address:

1) Move the cursor to **GPIB ADDR**, the following soft keys will be displayed.

■ ↑ (+)

This soft key is used to increase the GPIB address.

■ ↓ (-)

This soft key is used to decrease the GPIB address.

#### 4.1.8 TALK ONLY

The Talk only function is used to control the instrument to send each measurement result to bus

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through its interface of RS232C, GPIB, USBTMC, USBCDC or RS485. When the talk only function is ON, the instrument cannot be controlled by PC.

#### **Operation steps for setting the talk only function**

- 1) Move the cursor to **TALK ONLY**, the following soft keys will be displayed.
  - **ON**
  - **OFF**
- 2) Press **ON** to turn on the talk only function or **OFF** to turn off this function.

### **4.1.9 BAUD RATE**

Baud rate is used select the baud rate of the RS232C interface. The available baud rate of this instrument is from 9.600k to 115.200k.

#### **Operation steps for setting the baud rate**

Move the cursor to **BAUD RATE**, the following soft keys will be displayed.

- **↑ (+)**  
This soft key is used to increase the baud rate.
- **↓ (-)**  
This soft key is used to decrease the baud rate.

### **4.1.10 MENU DISP**

The soft key area of TH2817B+ can be set as HOLD or fixed time. When **MENU DISP** is set to HOLD, the soft key area will be displayed all the time. When **MENU DISP** is set to fixed time, the soft key area will be auto hided after holding to the setting time. When triggering any key in the operation panel again, the soft key area will be displayed again and restart timing.

#### **Operation steps for setting the menu display**

Move the cursor to **MENU DISP**, the following soft keys will be displayed.

- **↑ (+)**  
This soft key is used to increase the menu display.
- **↓ (-)**  
This soft key is used to decrease the menu display.

### **4.1.11 DATA/TIME**


When moving to the time zone, users can modify the system time.

## **4.2 LCR <FILE MANAGE>**

TH2817B+ series instrument can save the user-set parameter to the nonvolatile memory in the form of file, so when use the same setting next time user can load a corresponding file to obtain the parameter set and used last time. By doing so, it can save the time of setting parameter and improve the production efficiency.

Press [**FILE MANAGE**] to enter into the file manage page, shown as below:

[ LCR FILES LIST ]			
I:\			
NO.	LCR ID	TIME	LOAD
01	TH2832	20-05-20 05:56	
02			
03			
04			
05			
06			
07			
08			

LOAD    STORE    DEL    F IND    

#### 4.2.1 Setup file for single-group component (\*.STA)

40 groups of different single groups of component set file (\*.STA file) can be saved in the instrument, but external storage U-disk can display/operate 500 groups of different single groups of component set file (note: U-disc is an optional accessory).

Use **FILE MANAGE** function on the following File menus, the following data will be saved or loaded in the form of file, which are called \*.STA file.

- Control and setting parameter on <MEASURE SETUP> page
  - FUNCA
  - FREQ
  - LEVEL
  - RANGE
  - SPEED
  - TRIG
  - TRIG DLY
  - STEP DLY
  - Rsou
  - AVG
  - Vm
  - Im
  - DEV A
  - DEV B
  - REF A
  - REF B
- Control and set parameters on <BIN COUNT DISP> page
  - BIN COUNT (ON/OFF)
- Control and set parameter on <LIMIT TAABLE SETUP> page
  - PARAM (swap parameter)
  - NOM (reference value)



- 
- MODE (%-TOL/ABS-TOL/SEQ-MODE)
  - AUX (ON/OFF)
  - COM (ON/OFF)
  - High and low limits of each bin
  - Control and set parameters on <List Sweep Setup> page
    - List Sweep Mode (SEQ/STEP)
    - List Sweep Parameter (Frequency/Level/Bias)
    - Test points of all sweep parameters
    - High and low limits of all test points, including limit parameters (LIMIT-DATA A/LIMIT-DATA B)
  - Page format currently displayed

#### 4.2.2 U-disk manage performance

As described above, TH2817B+ has a standard configuration of USB HOST interface, so the external U-disk can be used as the memory media. In this condition, it breaks the memory limit of 40 groups of \*.LCR files. Meanwhile those files can be copied to IBM PC or compatible desk-top computer, laptop with USB interface to reach the infinite extension.

TH2817B+ supports the USB memory devices as below:

- Meet the USB 1.0/1.1 standard
- Capacity: 32MB/256MB/2GB/4GB
- File format: FAT16, FAT32 (Format the USB memory on Microsoft Windows operation system)

#### 4.2.3 Operation steps for file management

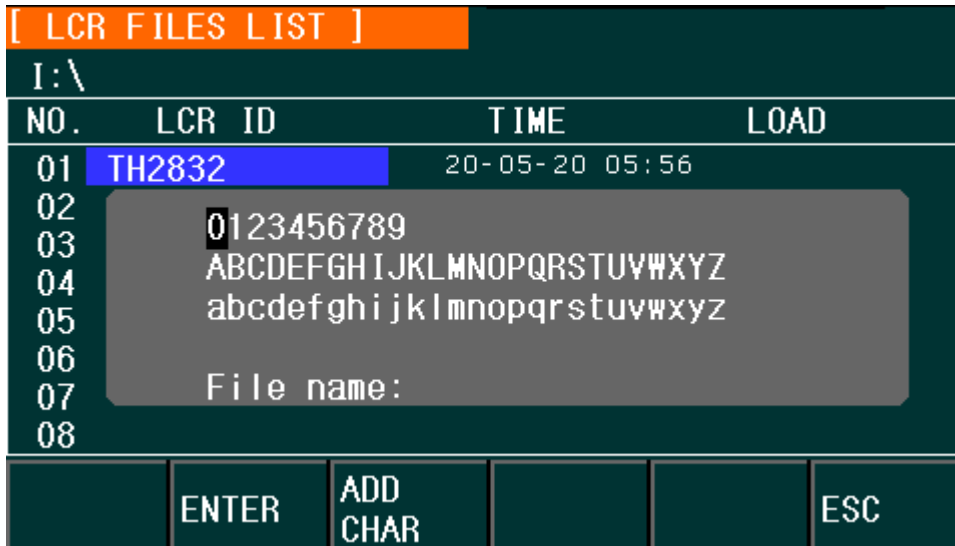
##### A. Search an existed file

- 1) Use the [↑] and [↓] to view one by one.
- 2) Use the [←] and [→] to view one page by one page.
- 3) Press the soft key **FIND**. Input the file character and then press the [ENTER] to search the target file.
- 4) Input the page number and press the [ENTER] to search the file.

##### B. Save the following control and setting parameters to a file by the following steps

- 1) Select and set all control and setting parameters on the desired page.
- 2) Move the cursor to **FILE MANAGE**, the following soft keys will be displayed.
  - **LOAD**
  - **STORE**
  - **DEL**
  - **COPY TO E:**
  - **FIND**
  - **EXT. FILE**
- 3) In the file list, move the cursor to the file-saved position or input the file number directly.
- 4) Press **STORE**, the following soft keys will be displayed.

- Yes
  - No
- 5) Press **No** to cancel the current save operation and return step 2.
  - 6) Press **Yes**, and LCR file name input operation interface will be displayed.



- 7) Move the cursor to select the character and press **ADD CHAR** to input the character. Press **ENTER** to save the current file name. Press **ESC** to quit the file name input interface.

#### C. Load the control and setting parameters from a file by the following steps

- 1) Press **FILE MANAGE**, the file list and the following soft keys will be displayed.
  - **LOAD**
  - **STORE**
  - **DEL**
  - **COPY TO E:**
  - **FIND**
  - **EXT. FILE**
- 2) In the file list, move the cursor to the file-saved position or input the file number directly.
- 3) Press **LOAD**, the following soft keys will be displayed.
  - **Yes**
  - **No**
- 4) Press **No** to cancel the current load operation and return step 1.
- 5) Press **Yes** to load the currently selected file. Then TH2817B+ will return the current display page.

#### D. Copy a file to an U disk by the following steps

- 1) Assuming that it is necessary to copy internal files 2 to external U-disk.
- 2) Press **FILE MANAGE**, the file list and the following soft keys will be displayed.
  - **LOAD**
  - **SAVE**

- 
- **DEL**
  - **COPY to E:**
  - **FIND**
  - **EXT. FILE**

- 3) Move the cursor the file to be copied and press[ENTER]to confirm (multiple files can be selected).
- 4) Press **COPY to E:** to copy the file the instrument.
- 5) While copying the file, the progress bar will present the progress of the file copy. When the progress bar is disappeared, the operation of the file copy is finished.

-----

**NOTE:** Please make sure that your U-disk meets the standard that described in this chapter and no write-read protection.

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## Chapter 5 Execute LCR operation and some examples

### 5.1 Correction operation

To execute correction operation (in order to prevent the stray impedance from affecting the test accuracy, it is necessary to make open/short correction), users can select one of the two correction modes.

#### 5.1.1 Sweep correction

- a) Press the menu key [SETUP] and then the soft key **CORRECTION**, the instrument will enter into the < **CORRECTION** > page.
- b) Move the cursor to the **OPEN** zone. **ON**, **OFF**, **MEAS OPEN** and **DCR OPEN** will be displayed in the soft key zone.
- c) Keep the test fixture in the open status, and then press **MEAS OPEN** to execute open correction till the prompt information zone displays that open correction is finished.
- d) Press **ON** to turn on the open correction function.
- e) Insert the short plate (26010) to the test fixture.
- f) Move the cursor to the **SHORT** zone. **ON**, **OFF**, **MEAS SHORT** and **DCR OPEN** will be displayed in the soft key zone.
- g) Press **MEAS SHORT** to execute the short correction till the prompt information zone displays that the short correction is finished.
- h) Press **ON** to turn the short correction function.
- i) Move the cursor to the **LOAD** zone. **ON**, **OFF** will be displayed in the soft key zone.
- j) Press **OFF** to turn off the load correction function.
- k) Move the cursor to the **FREQ** zone, **ON**, **OFF**, **MEAS OPEN**, **MEAS SHORT** and **MEAS LOAD** will be displayed in the soft key zone.
- l) Press **OFF** to turn off the point-frequency correction function of **FREQ**.

#### 5.1.2 Point-frequency correction

This function will gain better results in single-frequency test.

If the test frequency is 1kHz,

- a) Press the menu key [SETUP] and then **CORRECTION**, then instrument will display the <**CORRECTION**> function.
- b) Move the cursor to the **OPEN** zone, **ON**, **OFF**, **MEAS OPEN** and **DCR OPEN** will be displayed in the soft key zone.
- c) Press **ON** to turn on the open correction function.
- d) Move the cursor to the **SHORT** zone, **ON**, **OFF**, **MEAS OPEN** and **DCR SHORT** will be displayed in the soft key zone.
- e) Press **ON** to turn on the short correction function.
- f) Move the cursor to the **LOAD** zone, **ON**, **OFF** will be displayed in the soft key zone.

- 
- g) Press **OFF** to turn off the load correction function.
  - h) Move the cursor to the **Spot No.** zone to select the correction point.
  - i) Move the cursor to the **FREQ** zone, **ON**, **OFF**, **MEAS OPEN**, **MEAS SHORT** and **MEAS LOAD** will be displayed in the soft key zone.
  - j) Press **ON** to turn on the point-frequency correction function of **FREQ**.
  - k) Press [1], at the bottom of the screen meanwhile the available units (**Hz**, **kHz** and **MHz**) will be displayed in the soft key zone. Press **kHz**, the **FREQ** zone will be changed as 1.00000kHz (be the same as that of test frequency).
  - l) Keep the test fixture be in open status and press **MEAS OPEN** to execute open correction.
  - m) Insert the short plate (26010) to the test fixture.
  - n) Press **MEAS SHORT** to execute short correction.

## 5.2 Correct connection of DUT

There are 4 pairs of test terminal: Hcur, Lcur, Hpot, Lpot and corresponding shielding terminal of each terminal.

Each terminal contains shielding layer whose function is to reduce the influence of the ground stray capacitance and the interference of the electromagnetic field. In the process of testing, Hcur, Hpot and Lpot, Lcur should be connected with DUT lead to form a complete 4-terminal measurement, thus reducing the effect of the lead and the connection points on the test results (especially the dissipation measurement). When testing low-ohm components, Hpot, Lpot should be connected to the lead terminal so as to avoid the impedance being added to the lead impedance and the connection principle is that the Hpot and Lpot test should be the actual existed voltage on DUT.

In other words, before connecting to DUT, it is not recommended to connect Hcur, Hpot with Lpot, Lcur, for doing this will increase test error.

If the connection point and the lead resistance  $R_{lead}$  are far weaker than the tested impedance (for example:  $R_{lead} < Z_x / 1000$ , the accuracy error is required to be less than 0.1%), before connecting to DUT, it is recommended to connect Hcur, Hpot and Lpot, Lcur (Two terminal test).

In the test with high accuracy requirement, using Kelvin test fixture (standard accessory) will gain better results than using test leads. When Kelvin test lead is used under 10kHz, a better measurement result can be obtained. However, when the frequency is higher than 10kHz, it cannot meet the measurement demand. In high frequency, the change of the clearance between test leads will directly change stray capacitance and inductance on test terminals and this problem is unavoidable, because the test leads cannot be fixed in a position.

So, the use of the test fixture should be used as possible in high frequency. If the test fixture is unavailable or cannot be used, the status of test leads should be the same in the processes of correction and test.

No matter the standard Kelvin test fixture or Kelvin test leads or user-made fixture is used, the following requirements should be met.

1. Distribution impedance must be reduced to the Min. especially when testing high impedance components.
2. Contact resistance must be reduced to Min.
3. Short and open must be available between contact points. Open and short correction can easily reduce the influence of distribution impedance of the test fixture on measurement. For open correction,

the clearance between test terminals should be the same with that when they connects with DUT. For short correction, the short plate of low impedance should be connected between test terminals. Another way is to directly connect Hc with Lc or Hp with Lp, then connect both.

**Note:** When the DUT is a polarity component, before testing, the high potential terminal should be connected to the terminal with mark “+”, “Hc” or “Hp” and the low terminal should be connected to the terminal with mark “-”, “Lc” or “Lp”.

**Warning:** Before testing, please discharge the tested polarity component so as to avoid the damage to the instrument.

### 5.3 Eliminate the influence of stray impedance

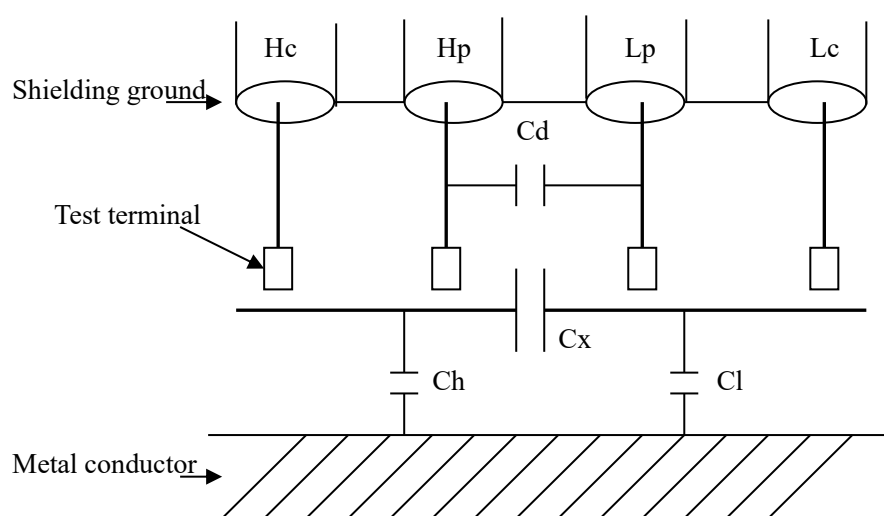


Figure 5-1 Influence of stray capacitance

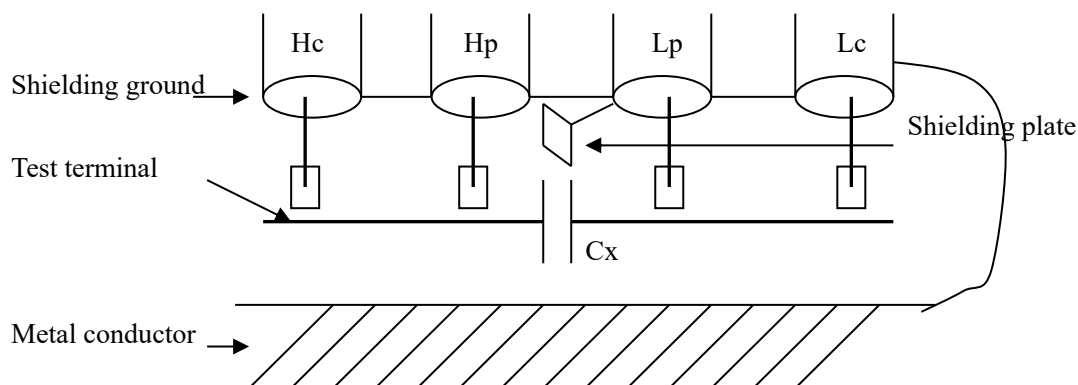


Figure 5-2 Eliminate the influence of stray capacitance

When the DUT has high impedance(such as small capacitance), the influence of stray

---

capacitance cannot be ignored. Figure 5-1 is an example of the use of 4 terminal pair measurement. In this figure,  $C_d$  is connected with  $C_x$  in a parallel way and when a conductance plate is positioned under DUT, capacitance  $C_h$  will connect with  $C_x$  in parallel after connecting with  $C_l$  in series and by this way the measurement result will have errors. If a ground conductor is installed between high and low terminals,  $C_d$  can be reduced to Min. Meanwhile if the ground terminal is connected to the conductance plate, the influence of  $C_h$  and  $C_l$  will be eliminated.

When the DUT is low impedance (such as small inductance, large capacitance), a large current will flow through test leads  $H_c$  and  $L_c$ . In this case, **electromagnetic coupling between test leads becomes the main source of test errors** except the influence of the contact resistance on test terminals. If this coupling cannot be eliminated, it will bring unexpected influence on test results. Generally, contact resistance affects the resistance of impedance and electromagnetic affects the reactance of impedance. Test terminals can adopt 4TP connection method. For 4TP connection, the currents flow through  $H_c$  and  $L_c$  are equal in value and opposite in direction with those flowing through each shielding terminals. By this way, the magnetic fields produced by these currents can be mutually offset and further eliminate the influence of mutual inductance coupling on test results.

## 5.4 Operation example for testing inductance with TH2817B+

### Test Condition

Function: Ls-Q

Frequency: 10kHz

Level: 0.3Vrms

Internal impedance: 100 $\Omega$

### Operation steps

- 1) Turn on the instrument.
- 2) Set basic parameters
  - a) Press [DISP] to enter into the <MEAS DISP> page.
  - b) Move the cursor to FUNC, the current item is displayed as Cp-D. Meanwhile Cp-...►, Cs-...►, Lp-...►, Ls-...►, More ► will be displayed in the soft key zone.
  - c) Press the soft key Ls-...►. Ls-D, Ls-Q, Ls-Rs will be displayed.
  - d) Press Ls-Q to select the Ls-Q function.
  - e) Move the cursor to **FREQ**, the current frequency is 1.0000kHz.
  - f) Press [1][0], 10 will be displayed in the prompt information zone at the bottom of the screen. The available units Hz, kHz and MHz will be displayed in the soft key zone. Press kHz, the frequency will be changed as 10.000kHz.
  - g) Move the cursor to **LEVEL**, the current displayed level will be 1.000V.
  - h) Press [0][.][3], 0.3 will be displayed in the prompt information zone at the bottom of the screen. The available units mV, V,  $\mu$ A, mA and A will be displayed in the soft key zone. Press [V], the level will be changed as 0.3V.
  - i) Press [SETUP] to enter into the <MEAS SETUP> page.
  - j) Move the cursor to **R<sub>sou</sub>** zone, 100 $\Omega$ , 10 $\Omega$  will be displayed in the soft key zone.
  - k) Press 100 $\Omega$  to select 100 $\Omega$  as the signal internal impedance.
- 3) Connect the test fixture (TH26048) to the test terminals of TH2817B+.

- 4) Execute correction (To avoid the influence of stray impedance on measurement accuracy, Open/Short correction must be operated) (refer to 5.1.2 “Point-frequency correction”)
- 5) Mount the tested inductance to the test fixture.
- 6) Execute test operation.

Press [DISP] to enter into the <MEAS DISP> page. The instrument can test continuously and the test result will be displayed in upper case character in the center of the page.

- 7) If the test result is obviously incorrect, please check the following items.
  - a) Check the tested inductance is in good connection with the test fixture or not.
  - b) Check the test fixture is in good connection with the test terminals of the instrument or not.
  - c) Redo the open/short correction.

**\*NOTE:** When the sweep open/short correction is used, the point-frequency correction function should be set as OFF. Refer to Correction operation in this chapter.

## 5.5 Operation example of testing capacitance by multi-frequency list sweep

### Test condition:

Function: Cp-D

Level: 1Vrms

Other parameters

Frequency	Compare parameter	Low limit	High limit
1kHz	Cp (capacitance)	325.0nF	333.0nF
10kHz	D (Dissipation)	0.0001	0.0003
100kHz	D (Dissipation)	0.0060	0.0100

Beep: HIGH LONG

Alarm mode: OUT

### Operation steps

- 1) Turn on the instrument.
- 2) Set basic parameters.
  - a) Press [DISP] to enter into the <MEAS DISP> page.
  - b) The FUNC zone is currently displayed as Cp-D and the Level zone is 1.000V.
  - c) Press [SETUP] to enter into the <MEAS SETUP> page, meanwhile the following soft keys will be displayed in the soft key zone: MEAS SETUP, CORRECTION, LIMIT SETUP, SWEEP SETUP and FILE MANAGE.
  - d) Press LIST SETUP to enter into the <LIST SWEEP SETUP> page.
  - e) Move the cursor to the SWEEP PARAM zone. Then this zone will be displayed as FREQ[Hz].
  - f) Move the cursor to the parameter zone of sweep point 1, then this zone will displayed as --.
  - g) Press [1], +1 will be displayed in the prompt information zone and the soft key zone will display available units: Hz, kHz and MHz. Press kHz, this zone will be changed as 1.00000k.
  - h) Press [→] to move the cursor to the LMT zone of sweep point 1, then this zone will be



- 
- displayed as ---. The soft key zone will display: **LIMIT DATA A**, **LIMIT DATA B** and **OFF**.
- i) Press **LIMIT DATA A** to select the compare primary parameter Cp function. This zone will be display **A** and the cursor will automatically move the low limit zone of sweep point 1.
  - j) Press [3][2][5], +325 will be displayed in the prompt information zone and the following available units will be displayed in the soft key zone: **p**, **n**, **μ**, **m** and **k**. Press **n**, this zone will be changed as 325.000n. Then the cursor will automatically move the high limit zone of the sweep point 1.
  - k) Press [3] [3] [3], +333 will be displayed in the prompt information zone and the following units will be displayed in the soft key zone: **p**, **n**, **μ**, **m** and **k**. Press **n**, this zone will be changed as 333.000n and the cursor will automatically move to the parameter zone of sweep point 2.
  - l) Press [10], +10 will be displayed in the prompt information zone and the soft key zone will display the following available units: **Hz**, **kHz** and **MHz**. Press **kHz**, this zone will be displayed as 10.0000k.
  - m) Press [→] to move the cursor to the LMT zone of sweep point 2, this zone will be displayed as---. The following soft key will be displayed in the soft key zone: **LIMIT DATA A**, **LIMIT DATA B** and **OFF**.
  - n) Press **LIMIT DATA B** to select the compare secondary parameter D function. This zone will be displayed as **B** and the cursor will be automatically moved to the low limit zone of the sweep point 2.
  - o) Press [0][.][0][0][0][1], +0.0001 will be displayed in the prompt information zone and the soft key zone will display the following available units: **p**, **n**, **μ**, **m** and **k**, **M**, **\*1**. Press [**\*1**], this zone will be changed as 100.000μ and the cursor will automatically move to the high limit zone of sweep point 2.
  - p) Press [0][.][0][0][0][3], +0.0003 will be displayed in the prompt information zone and the soft key zone will display the following available units: **p**, **n**, **μ**, **m** and **k**, **M**, **\*1**. Press [**\*1**], this zone will be changed as 300.000μ and the cursor will automatically move to the parameter zone of sweep point 3.
  - q) Based on 1-p steps, input 100kHz, B, 0.0060 and 0.0100 for the 3rd sweep point.
- 3) Alarm setup
    - a) Press [SYSTEM] to enter into the <System Setup> page.
    - b) Move the cursor to the **FAIL BEEP** zone to select **HIGH LONG**.
  - 4) Connect test fixture (TH26048) to the test terminals of TH2817B+.
  - 5) Execute correction function (To avoid the influence of the stray impedance on the measurement accuracy, it is necessary to execute open/short correction (refer to chapter 5.1.1 Sweep Correction)).
  - 6) Insert the tested capacitor to the test fixture.
  - 7) Execute test operations.
- Press [DISP] and then press **List Sweep** to enter into the <List Sweep Display> page. The instrument will test continuously and then display the test and the compare results on page. If the compare result is H (higher than the high limit) or L (lower than the low limit), there is a beep alarm. The following figure shows the measurement display page.
- 8) If the test result is obviously incorrect, please check the following items.
    - a) Check the tested inductance is in good connection with the test fixture or not.

- b) Check the test fixture is in good connection with the test terminals of the instrument or not.
- c) Redo the open/short correction.

**\*NOTE:** When the sweep open/short correction is used, the point-frequency correction function should be set as OFF. Refer to Correction operation in this chapter.

## 5.6 Setup example of comparator

TH2817B+ provides complete comparator function. It is convenient for component measurement and judgment, incoming and outgoing quality inspection in production line. Standard configuration of HANDLER interface makes it realize automatic sorting measurement system.

The concept and specific operation of the comparator has been described in the preceding chapter. Here are two setup examples.

### 5.6.1 Capacitor sorting

**Capacitor type:** 0805CG271

**Basic requirements:** the capacitance is divided into two bins: BIN J and BIN K. When the capacitance passes and the loss fails, it will be sorted additionally.

**Measurement parameters:** frequency of 10kHz, level of 1Vrms, SLOW, FAIL alarm and external trigger.

**Sorting parameters:** J bin -4.6% ~ +4.8%, K bin -9% ~ +10%, loss  $\text{tg}\delta < 0.15\%$ .

The parameters needed to be set in this example are listed below:

Primary parameter (FUN1)	Cp
Secondary parameter (FUN2)	D
Frequency (FRQ)	100kHz
Level (LEV)	1V
Speed (SPEED)	SLOW
Switch of auxiliary bin (AUX)	ON
Tolerance Mode of primary parameter (MODE)	%TOL (percentage tolerance mode)
Nominal value (NOMINAL)	270pF
Lower limit of BIN1 (BIN1 LOW)	-4.6%
Upper limit of BIN1 (BIN1 HIGH)	4.8%
Lower limit of BIN2 (BIN2 LOW)	-9%
Upper limit of BIN2 (BIN2 HIGH)	10%
Lower limit of secondary parameter (2nd LOW)	0.0000
Lower limit of secondary parameter (2nd LOW)	0.0015
Trigger mode (TRIG)	EXT (external)
Alarm mode (CMP ALARM)	Fail Beep (HIGH LONG)

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**Instruction:**

1. For small capacitance, its impedance of 100kHz is over 1 k $\Omega$ , so equivalent parallel mode should be selected.
2. When any bin of the capacitance passes but loss fails, it will be archived additionally. Now, auxiliary bin should be set as ON and it will be sorted into AUX BIN. If the AUX BIN is set as OFF, it will be judged as FAIL when loss fails.
3. Because the given upper and lower limit is based on the percentage tolerance of nominal value 2.7nF, the primary parameter should select %TOL percentage mode.

**Specific setup:**

- 1) In MEAS DISP page, select Cp-D and set the frequency, level and speed.
- 2) Press **SETUP** key to enter into the MEAS SETUP page and change the TRIGGER MODE as EXT (external trigger).
- 3) Press **SETUP**---**LIMIT** to enter into the LIMIT TABLE SETUP page and set the nominal value, primary parameter tolerance mode, upper/lower limit parameter, comparator switch and auxiliary bin switch.
- 4) Press **SYSTEM** key to enter into the SYSTEM SETUP page (System Config), find FAIL BEEP item and set it as HIGH LONG.
- 5) Return to the MEAS **DISP** page after setup.

## 5.6.2 Operation example of load correction

### 1) Operation steps

**Test condition**

Frequency: 100kHz Cp: 11nF D: 0.0005

- a) Press **[SETUP]**, the following soft keys will be displayed in the soft key zone: **MEAS SETUP**, **CORRECTION**, **LIMIT TABLE**, **LIST SETUP**, **FILE MANAGE** and **TOOLS**.
- b) Press **CORRECTION** to enter into the <CORRECTION> page.
- c) Move the cursor to **OPEN**, the following soft keys will be displayed in the soft key zone: **ON**, **OFF** and **MEAS OPEN**
- d) Press **ON** to turn on the open correction function.
- e) Move the cursor to **SHORT**, the following soft keys will be displayed in the soft key zone: **ON**, **OFF** and **MEAS SHORT**
- f) Press **ON** to turn on the short correction function.
- g) Move the cursor to **LOAD**, the following soft keys will be displayed in the soft key zone: **ON** and **OFF**.
- h) Press **ON** to turn on the load correction function.
- i) Move the cursor to **FUNC**, this zone will display **Cp-D**. Meanwhile **Cp**---...→, **Cs**---...→, **Lp**---...→, **Ls**---...→, **Z**---...→, ↓ will be displayed in the soft key zone.
- j) Press **Cp-D** to select the Cp-D function.
- k) Move the cursor to **FREQ** zone, the following soft keys will be displayed in the soft key zone: **ON**, **OFF**, **MEAS OPEN**, **MEAS SHORT** and **MEAS LOAD**.
- l) Press **ON** to turn on the point-frequency correction function of **FREQ**.
- m) Press **[1][0]**, +10 will be displayed in the prompt information zone and the soft key zone will

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display the following available units: Hz, kHz and MHz. Press kHz, the **FREQ** zone will be changed as 10.000kHz (the same with the test frequency).

- n) Move the cursor to the **REF A:** zone of the frequency 1. Press [1][1], +11 will be displayed in the prompt information zone and the following available units will be displayed in the soft key zone: p, n,  $\mu$ , m and k. Press n, this zone will be changed as 11.0000nF.
- o) Move the cursor the **REF B:** zone of the frequency 1. Press [0][.][0][0][0][5], +0.0005 will be displayed in the prompt information zone and the following available units will be displayed in the soft key zone: p, n,  $\mu$ , m and k. Press [ENTER], this zone will be changed as 0.00050.
- p) Move the cursor to Freq 1. The following soft keys will be displayed: ON, OFF, MEAS OPEN, MEAS SHORT and MEAS LOAD.
- q) Hold the test fixture in open status and keep user's hands or other interference source far away from the test fixture. Press the soft key MEAS OPEN to execute open correction.
- r) Insert the short plate (TH26010) into the test fixture. Please ensure that the short plate and the reeds of the test fixture have good contact.
- s) Press the soft key MEAS SHORT to execute short correction.
- t) Insert a standard capacitance into the test fixture. Please ensure that the pins of the standard capacitance have good connection with the reeds of the test fixture.
- u) Press the soft key MEAS LOAD to execute load correction.

**2) Note**

- a) Because of the different software editions, the soft keys and status information may be different from this book, but it may not affect users' understanding.
- b) The load correction is only valid for the components with the same specification. If the specification is changed, it is required to redo load correction.

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## Chapter 6 Performance and Test

### 6.1 Test function

#### 6.1.1 Parameter and symbol

C: capacitance      L: inductance  
R: resistance      Z: impedance      Y: admittance  
X: reactance      B: susceptance      G: conductance  
D: dissipation       $\theta$ : phase angle      Q: quality factor  
DCR: DC resistance

#### Test combination

Parameters described above are combined in the following modes:

Primary parameter	Z, Y	L, C	R	G
Secondary parameter	$\theta$ (deg phase), $\theta$ (rad radian)	D, Q, R <sub>S</sub> , R <sub>P</sub> , G,	X	B

Mathematical operation

Operation between the measurement value and the programmable nominal value: absolute deviation  $\Delta$ ABS and percent deviation  $\Delta\%$ .

#### 6.1.2 Equivalent mode

Serial and parallel

#### 6.1.3 Range

Auto, Manual (Hold, increase and decrease)

#### 6.1.4 Trigger

Internal, external and manual

Internal: Test DUT constantly and display the result

Manual: Press TRIGGER to test once then the result will be displayed.

External: After HANDLER receiving “start” signal, perform a measurement and output test result.

#### 6.1.5 Delay time

Delay time: time from trigger to start. 0 to 60s are programmable with a resolution of 1ms.

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## 6.1.6 Connection modes of test terminals

TH2817B+ adopts 4-terminal test method.

HD(Hcur): current sample high terminal

LD(Lcur): Current sample low terminal

HS(Hpot): voltage sample high terminal

LS(Lpot): Voltage sample low terminal

## 6.1.7 Test speed (Frequency $\geq$ 10kHz)

Fast: about 53 times/s (19ms/time)

Medium: about 12 times/s (83ms/time)

Slow: about 3 times/s (333ms/time)

The fast and middle speed will be slow down when frequency  $<10\text{kHz}$ .

The instrument adds the speed increase function at low frequency.

## 6.1.8 Average

Be programmable from 1 to 255.

## 6.1.9 Display digit

6 digits, max. displayed digit: 999999

## Test signal

### 6.1.10 Test signal frequency

Test signal is sine wave, accuracy: 0.01%

Frequency range: 50Hz-100kHz

### 6.1.11 Signal mode

Normal: When testing, on measurement display page, voltage across test terminals may be smaller than preset voltage.

### 6.1.12 Test signal level

0.1V,0.3V,1.0V  $\pm 10\%$

### 6.1.13 Output impedance

10Ω and 100Ω±1% are selectable.

### 6.1.14 Monitor for test signal level

Mode	Range	Accuracy
Voltage	5mV <sub>RMS</sub> —1V <sub>RMS</sub>	± (3%×reading+0.5mV)
	0.01mV <sub>RMS</sub> —5mV <sub>RMS</sub>	± (12%×reading +0.1mV)
Current	50μA <sub>RMS</sub> —10mA <sub>RMS</sub>	± (3%×reading +5μA)
	0.001μA <sub>RMS</sub> —50μA <sub>RMS</sub>	± (12%×reading +1μA)

### 6.1.15 Maximum measurement display range

Parameter	Measurement display range
L、Lk	0.00001μH ~ 99.999kH
C	0.00001pF ~ 9.99999F
Z、R、X、DCR	0.00001Ω~ 99.9999MΩ
Y、B、G	0.00001μs ~ 99.9999S
D	0.00001 — 9.99999
Q	0.00001 — 99999.9
θ	Deg -179.999°~179.999°
	Rad -3.14159 ~ 3.14159

## Measurement accuracy

Test accuracy includes stability、temperature coefficient、linear degree、test repeatability and calibration inter-error.

Check the accuracy of instrument should be under the following circumstances:

- a. warm-up time: ≥ 30 min
- b. cable: 0m, 1m
- c. correct open and short correction after warming up
- d. The range works in “AUTO” to select correct test range

### 6.1.16 Accuracies of |Z|, |Y|, L, C, R, X, G, B

The accuracy A<sub>e</sub> of |Z|, |Y|, L, C, R, X, G and B are expressed as:

$$A_e = \pm[A + (K_a + K_b + K_c) \times 100 + K_d + K_f] \times K_e \quad [\%]$$

A: basic test accuracy (figure A)

K<sub>a</sub>: impedance rate factor (table A)

K<sub>b</sub>: impedance rate factor (table A)

$K_c$ : calibrated inter-factor (table B)  
 $K_d$ : cable length factor (table D)  
 $K_e$ : temperature factor (table E)  
 $K_f$ : scan fixture modification factor (no add:  $K_f = 0$ , add:  $K_f = 0.2$ )  
 L, C, X, B accuracy using condition:  $D_x$  (Test value)  $\leq 0.1$   
 R, G accuracy using condition:  $Q_x$  (Q test value)  $\leq 0.1$

When  $D_x \geq 0.1$ , L, C, X, B accuracy factor  $A_e$  should be multiplied by  $\sqrt{1 + D_x^2}$

When  $Q_x \geq 0.1$ , R, G accuracy factor  $A_e$  should be multiplied by  $\sqrt{1 + Q_x^2}$   
 Accuracy of G can only be available in G-B combination.

### 6.1.17 Accuracy of D

The accuracy of D is given by  $D_e$ :

$$D_e = \pm \frac{A_e}{100}$$

The formula is only available when  $D_x \leq 0.1$ .

When  $D_x > 0.1$ ,  $D_e$  should be multiplied by  $(1 + D_x)$

### 6.1.18 Accuracy of Q

The accuracy of Q is given by the formula below:

$$Q_e = \pm \frac{Q_x \times D_e}{1 \mp Q_x \times D_e}$$

Where,  $Q_x$  is the value of the tested Q.

$D_e$  is the accuracy of D

Above formula should be used when  $Q_x \times D_e < 1$ .

### 6.1.19 Accuracy of $\theta$

The accuracy of  $\theta$  is given by the formula below:

$$\theta_e = \frac{180}{\pi} \times \frac{A_e}{100} \quad [\text{deg}]$$

### 6.1.20 Accuracy of G

When  $D_x$  (tested value of D)  $\leq 0.1$

The accuracy of G is given by the formula below:

$$G_e = B_x \times D_e \quad [S]$$

$$B_x = 2\pi f C_x = \frac{1}{2\pi f L_x}$$

Where,  $B_x$  is the value of tested B with the unit [S].



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$C_x$  is the value of tested C with the unit [F].

$L_x$  is the value of tested L with the unit [H].

$D_e$  is the accuracy of D.

F is test frequency.

The accuracy of G is only available in  $C_p$ -G and  $L_p$ -G combination

### 6.1.21 Accuracy of $R_p$

When  $D_x$  (value of tested D)  $\leq 0.1$

The accuracy of  $R_p$  is given by the formula below:

$$R_p = \pm \frac{R_{px} \times D_e}{D_x \mp D_e} \quad [\Omega]$$

Where,  $R_{px}$  is the value of tested  $R_p$  with the unit [S].

$D_x$  is the value of test D with the unit [F].

$D_e$  is the accuracy of D.

### 6.1.22 The accuracy of $R_s$

When  $D_x$  (value of tested D)  $\leq 0.1$

The accuracy of  $R_s$  is given by the formula below:

$$R_{se} = X_x \times D_e \quad [\Omega]$$

$$X_x = 2\pi f L_x = \frac{1}{2\pi f C_x}$$

Where,  $X_x$  is the value of test X with the unit [S].

$C_x$  is the value of test C with the unit [F].

$L_x$  is the value of test L with the unit [H].

$D_e$  is the accuracy of D

F is test frequency

### 6.1.23 Accuracy factor

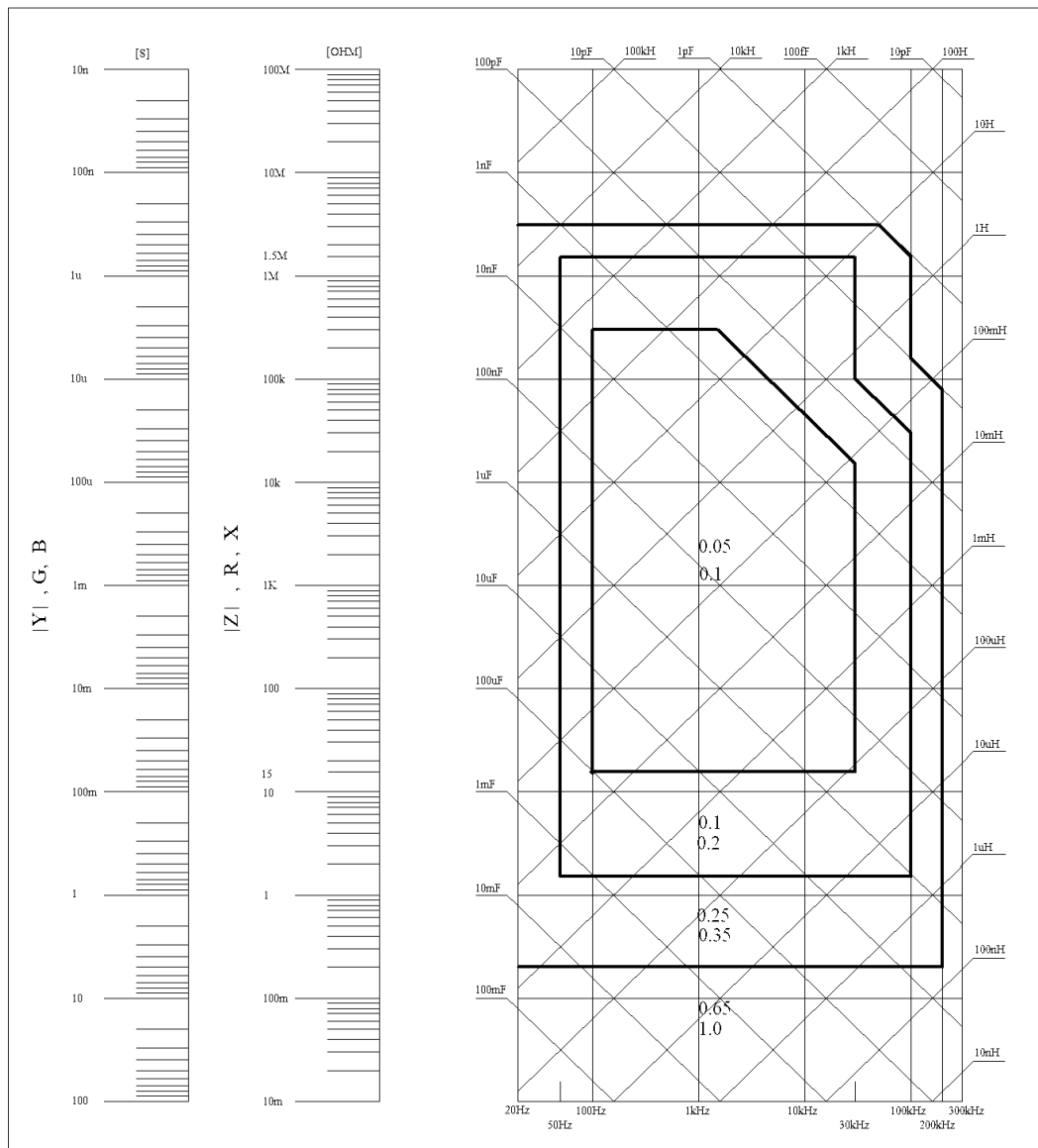


Figure A shows the basic measurement accuracy A.

In figure A, select a smaller value on boundary line.

In this figure, the basic accuracy value A can be obtained by the following methods:

0.05---When  $0.4V_{rms} \leq V_s \leq 1.2V_{rms}$ , the test speed is the value A of medium, slow and fast.

0.1---When  $0.4V_{rms} \leq V_s \leq 1.2V_{rms}$ , the test speed is the value A of fast.

When  $V_s < 0.4V_{rms}$  or  $V_s > 1.2V_{rms}$ , the calculation method of value A is as the following steps:

1. Obtain A according to the current measurement speed;
2. According to the current test signal voltage to select the accuracy modification coefficient  $A_r$  (refer to figure B), the current basic measurement accuracy A is obtained by multiplying A got in step 1 with  $A_r$ .

Figure B is the basic accuracy modification curve, where  $V_s$  is the test signal voltage.

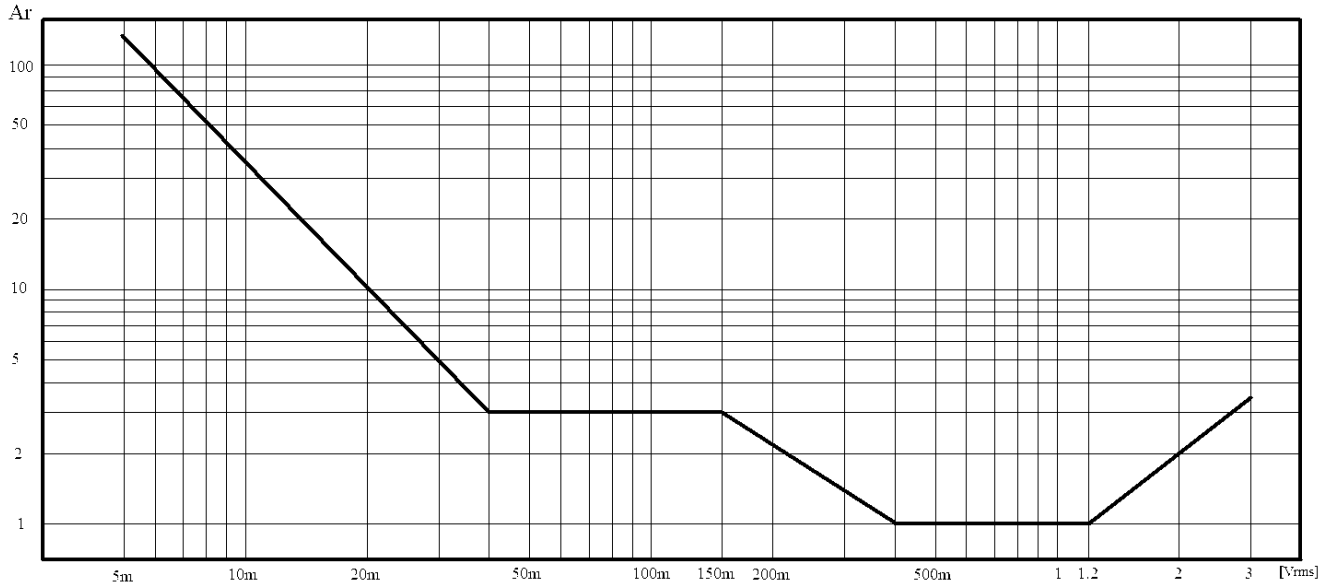


Table A Impedance rate factors:  $K_a$ ,  $K_b$

Speed	Frequency	$K_a$	$K_b$
Medium Slow	$f_m < 100\text{Hz}$	$(\frac{1 \times 10^{-3}}{ Z_m })(1 + \frac{200}{V_s})(1 + \sqrt{\frac{100}{f_m}})$	$ Z_m (1 \times 10^{-9})(1 + \frac{70}{V_s})(1 + \sqrt{\frac{100}{f_m}})$
	$100\text{Hz} \leq f_m \leq 100\text{kHz}$	$(\frac{1 \times 10^{-3}}{ Z_m })(1 + \frac{200}{V_s})$	$ Z_m (1 \times 10^{-9})(1 + \frac{70}{V_s})$
	$100\text{kHz} < f_m \leq 200\text{kHz}$	$(\frac{1 \times 10^{-3}}{ Z_m })(2 + \frac{200}{V_s})$	$ Z_m (3 \times 10^{-9})(1 + \frac{70}{V_s})$
Fast	$f_m < 100\text{Hz}$	$(\frac{2.5 \times 10^{-3}}{ Z_m })(1 + \frac{400}{V_s})(1 + \sqrt{\frac{100}{f_m}})$	$ Z_m (2 \times 10^{-9})(1 + \frac{100}{V_s})(1 + \sqrt{\frac{100}{f_m}})$
	$100\text{Hz} \leq f_m \leq 100\text{kHz}$	$(\frac{2.5 \times 10^{-3}}{ Z_m })(1 + \frac{400}{V_s})$	$ Z_m (2 \times 10^{-9})(1 + \frac{100}{V_s})$
	$100\text{kHz} < f_m \leq 200\text{kHz}$	$(\frac{2.5 \times 10^{-3}}{ Z_m })(2 + \frac{400}{V_s})$	$ Z_m (6 \times 10^{-9})(1 + \frac{100}{V_s})$

Where,  $f_m$  is the test frequency and the unit is [Hz].

The unit of the tested impedance is [ $\Omega$ ].

The unit of the test signal voltage is [ $\text{mV}_{\text{rms}}$ ].

When the impedance is smaller than  $500\Omega$ ,  $K_a$ ,  $K_b$  is unavailable.

When the impedance is larger than  $500\Omega$ ,  $K_b$ ,  $K_a$  is unavailable.

Table B calibrated interpolating factor  $K_c$

Test frequency	$K_c$
Direct calibrated frequency	0
Other frequency	0.0003

Table C Direct Calibrated frequency

		50	60	100	120	[Hz]
1	10	20	40	50	100	[kHz]

Table D Cable length factor  $K_d$

Test signal level	Cable length		
	0m	1m	2m
$\leq 1.5V_{\text{rms}}$	0	$2.5 \times 10^{-4} (1+50 \times f_m)$	$5 \times 10^{-4} (1+50 \times f_m)$
$> 1.5V_{\text{rms}}$	0	$2.5 \times 10^{-3} (1+16 \times f_m)$	$5 \times 10^{-3} (1+50 \times f_m)$
$f_m$ : test frequency [MHz]			

When using the scan jig, take the correction factor  $K_d$  when the cable length is 2m.

Table E Temperature factor  $K_e$

Temperature ( $^{\circ}\text{C}$ )	5		8		18		28		38	
$K_e$	6	4	2	1	2	4	2	4	2	4

### 6.1.24 The accuracy of LK

Inductance L accuracy +0.2%

## 6.2 Safety requirement

The instrument is the I class safety instrument.

### 6.2.1 Insulation resistance

Under reference working condition, the insulation resistance between power terminal and instrument

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jacket should not be smaller than 50MΩ.

Under humidity condition, the insulation resistance between voltage terminal and instrument jacket should not be smaller than 2 MΩ.

### 6.2.2 Insulation intensity

Under reference working condition, the insulation between the power terminal and the instrument jacket should bear an AC voltage (50Hz frequency and 1.5kV rated voltage) for 1 minute and there is no breakdown and flashover.

### 6.2.3 Leakage current

The leakage current should not be larger than 3.5mA (AC effective value).

## 6.3 Electromagnetic compatibility

- Transient sensitivity, based on the requirement of GB6833.4.
- Conductive sensibility, based on the requirement of GB6833.6.
- Radiated interference, based on the requirement of GB6833.10.

## 6.4 Performance test

### 6.4.1 Working condition

All tests should be performed under the working condition listed in Chapter 1. In this part, only the main indexes are listed. Users can make test under the specified condition mentioned in this manual. Performance test can be worked in the warm up conditions discussed in Chapter 1.

### 6.4.2 The used instruments and devices

No.	Instrument and Device	Specification	
1	Standard capacitor	100pF	0.02 % D is known
		1000pF	
		10000pF	
		10nF	
		0.1uF	
		1uF	
2	AC standard resistor	10Ω	0.02 %
		100Ω	

		1k $\Omega$	
		10k $\Omega$	
		100k $\Omega$	
3	DC standard resistor	0.1 $\Omega$	0.02%
		1 $\Omega$	
		10 $\Omega$	
		100 $\Omega$	
		1k $\Omega$	
		10k $\Omega$	
		100k $\Omega$	
4	Standard inductor	100 $\mu$ H	0.02%
		1mH	
		10mH	
		100mH	
5	Frequency counter		(0~1000) MHz
6	Digital Multimeter		0.5%
7	Insulation resistance meter		500V 10 levels
8	Hipot Tester		0.25kW (0~500) V

### 6.4.3 Function check

Ensure function keys, display and terminal etc. can work normally.

### 6.4.4 Test signal level

Adjust multimeter in AC voltage range, where one test cable is connected to H<sub>CUR</sub> and the other is connected to ground terminal. Change level as: 100mV, 300mV, 1V, the reading should meet the demand of test signal level in this chapter.

### 6.4.5 Frequency

Connect frequency meter to ground terminal. The test terminal of the frequency meter is connected with H<sub>CUR</sub>. Change the frequency as: 50Hz, 100Hz, 1kHz, 10kHz, 100kHz, the reading of frequency meter should meet the demand of the test signal frequency in this chapter.

### 6.4.6 Measurement accuracy

Basic parameters are R, L, C and D, so measurement accuracy is mainly about R, L, C and D.

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### 6.4.7 Accuracy of C and D

Function	C <sub>p</sub> -D				
Test frequency	100Hz	1kHz	10kHz	100kHz	Test respectively
Level	1V				
Range	AUTO				
Bias	0V				
Speed	Slow				

Open and short correction should be made before testing. Connect standard capacitors: 100pF, 1000pF, 10nF, 0.1uF, 1uF and change the frequency. The error capacitance C between reading and nominal value should be in the range ruled in this chapter, dissipation D should be in the range ruled in this chapter.

### 6.4.8 Accuracy of L

Test condition:

Function	L <sub>s</sub> -Q			
Test frequency	100Hz	1kHz		Test respectively
Level	1V			
Range	AUTO			
Bias	0V			
Speed	Slow			

Open and short correction should be made before testing. Connect standard inductors: 100μH, 1mH, 10mH, 100mH and change the frequency. The error between reading and nominal value should be in the range ruled in this chapter.

### 6.4.9 Accuracy of Z

Test condition:

Function	Z-θ				
Test frequency	100Hz	1kHz	10kHz	100kHz	Test respectively
Level	1V				
Range	AUTO				
Bias	0V				
Speed	Slow				

Open and short correction should be made before testing. Connect standard AC resistors: 10Ω, 100Ω, 1kΩ, 10kΩ, 100kΩ and change the frequency. The error between reading and nominal value should be in the range ruled in this chapter.

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# Chapter 7 Command Reference

The signs in this manual are as follows:

NR1: integer, e.g.:123

NR2: fix-point number, e.g.: 12.3

NR3: floating-point number, e.g.: 12.3E+5

NL: carriage key, ASCII code: 10

^END: EOI signal in IEEE-488

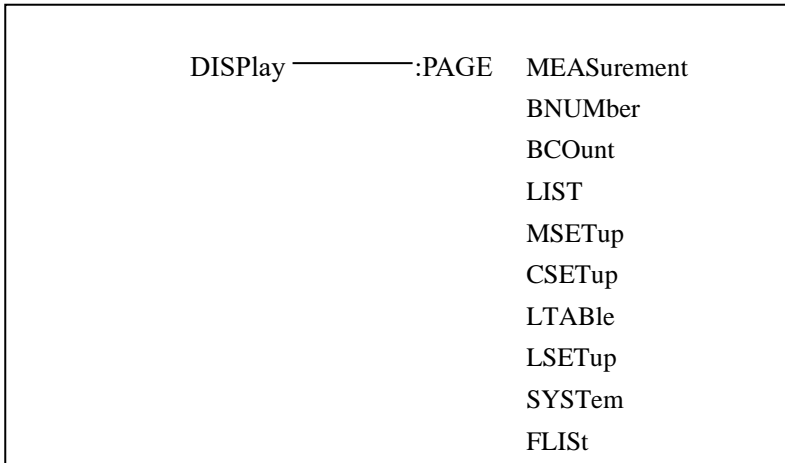
## 7.1 Subsystem commands for TH2817B+

- DISPlay    ●ORESister    ●TRIGger    ●CORRection
- FREQUency    ●INITiate    ●COMParator    ●VOLTage
- FUNCTion    ●FETCh?    ●Mass MEMory    ●CURRent
- LIST        ●ABORT

### 7.1.1 DISPlay subsystem commands

MEASlay subsystem commands are mainly used to set the display page for the instrument. The :DISPlay? Query returns the current page.

Command tree:



The :PAGE command sets the display page.

The :DISPlay:PAGE? query returns the current page.

Command syntax: DISPlay:PAGE<page name>

<Page name> can be set as the following items:

- MEASurement    Set the display page as the LCR measurement display.
- BNUMber        Set the display page as the bin number display.



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BCOut	Set the display page as the bin count display.
LIST	Set the display page as the list sweep display.
MSETup	Set the display page as the measurement display.
CSETup	Set the display page as the correction setup.
LTABLE	Set the display page as the limit table setup.
LSETup	Set the display page as the list sweep setup.
SYSTEM	Set the display page as the system setup page.
FLIS	Set the display page as the file list page.

For example: WrtCmd(“DISP:PAGE MEAS”), Set the display page as the LCR measurement display page.

Query syntax:DISPlay:PAGE?

Return format: <page name><NL^END>

<page name> can be set as the following items:

<LCR MEAS MEAS>	The current page is the LCR measurement display page.
<BIN No. MEAS>	The current page is the bin number display page.
<BIN COUNT MEAS>	The current page is the bin count display page.
<LIST SWEEP MEAS>	The current page is the list sweep display page.
<MEAS SETUP>	The current page is the measurement setup page.
<CORRECTION>	The current page is the correction page.
<LIMIT TABLE SETUP>	The current page is the limit table setup page.
<LIST SWEEP SETUP>	The current page is the list sweep setup page.
<SYSTEM SETUP>	The current page is the system setup page.
<FILE LIST>	The current page is the file list page.

## 7.1.2 FREQuency subsystem commands

The FREQuency subsystem commands are mainly used to set the measurement frequency of the instrument. The :FREQuency query returns the current measurement frequency.

Command syntax:      FREQuency       $\left\{ \begin{array}{l} \text{<value>} \\ \text{MIN} \\ \text{MAX} \end{array} \right.$

Where,

<value>      NR1, NR2 or NR3 data format followed by Hz, kHz, MHz.

MIN            Set the measurement frequency as 100Hz

MAX            Set the measurement frequency as 10kHz

For example: WrtCmd(“FREQ 1KHZ”)      Set the frequency as 1000Hz.

Query syntax: FREQuency?

Return format: <NR3><NL^END>

---

### 7.1.3 VOLTage subsystem commands

The VOLTage subsystem commands are mainly used to set the measurement voltage. The VOLTage? query returns the current measurement voltage.

Command syntax:

VOLTage { <value>  
          MIN  
          MAX

Where,

<value> NR1, NR2 or NR3 data format followed by V.

MIN Set the measurement voltage as 100mV.

MAX Set the measurement voltage as 1V.

For example: WrtCmd("VOLT 1V") Set the measurement voltage as 1V.

Query syntax: VOLTage?

Return format: <NR3><NL^END>

### 7.1.4 Output RESister subsystem commands

The Output RESister subsystem commands are mainly used to set the output internal resistor mode. The Output RESister? query returns the current output internal resistance status.

Command syntax:

ORESister { 10  
            100

For example: WrtCmd("ORES 10"); Set the output internal resistance is 10 OHM.

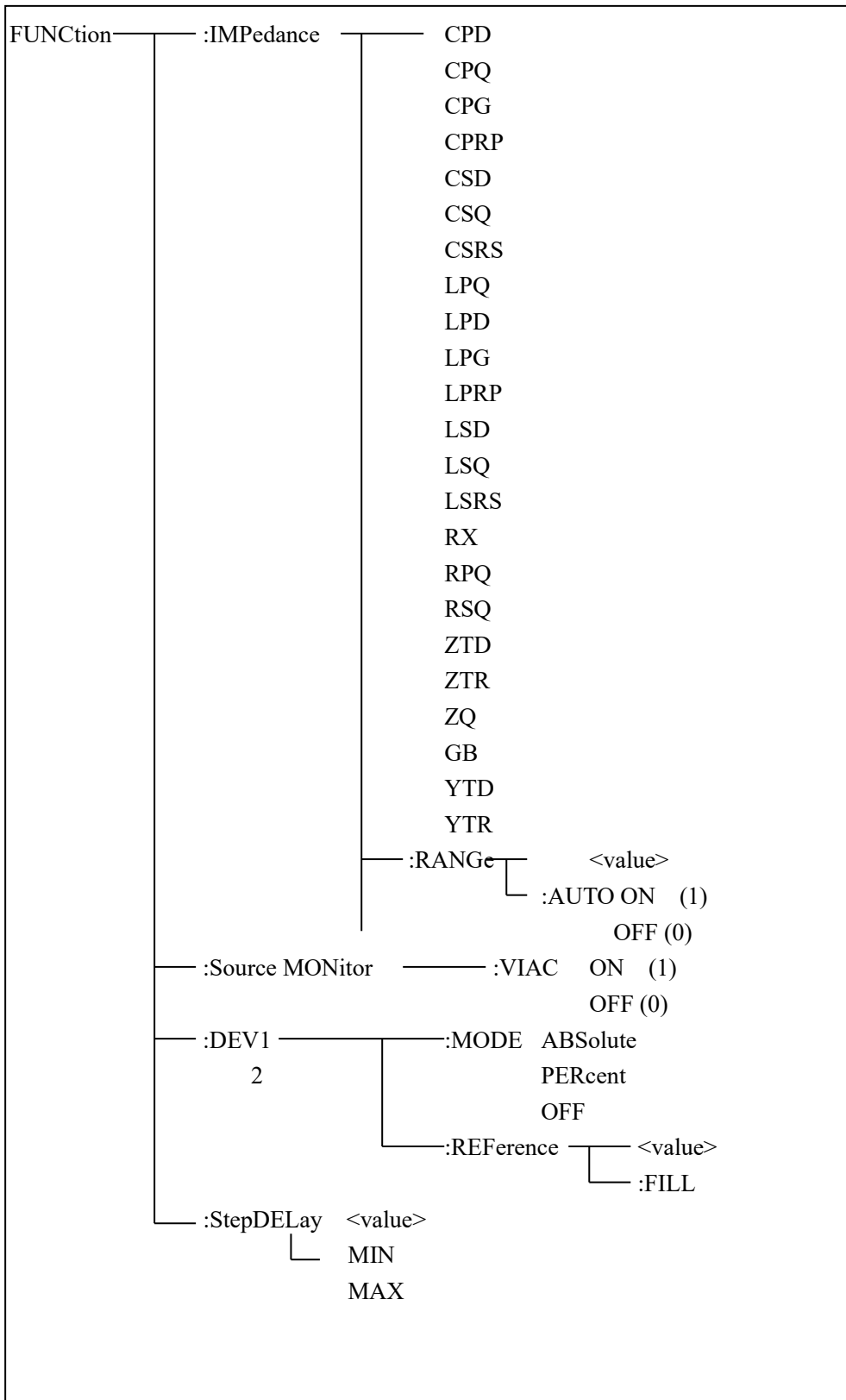
Query syntax: ORESister?

Return format: <NR1><NL^END>

### 7.1.5 FUNCTION subsystem commands

The FUNCtion subsystem commands are mainly used to set measurement functions, range, current/voltage monitor ON/OFF, deviation display mode, nominal setting.

**Command tree:**



The FUNction:IMPedance command is used to set instrument functions. The FUNction:IMPedance?

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query returns the current function parameters.

Command syntax: FUNCtion:IMPedance <function>

<function> can be one of the following items.

CPD	Set the function as Cp-D	LPRP	Set the function as Lp-Rp
CPQ	Set the function as Cp-Q	LSD	Set the function as Ls-D
CPG	Set the function as Cp-G	LSQ	Set the function as Ls-Q
CPRP	Set the function as Cp-Rp	LSRS	Set the function as Ls-Rs
CSD	Set the function as Cs-D	RX	Set the function as R-X
CSQ	Set the function as Cs-Q	ZTD	Set the function as Z- $\theta^\circ$
CSRS	Set the function as Cs-Rs	ZTR	Set the function as Z- $\theta_r$
LPQ	Set the function as Lp-Q	GB	Set the function as G-B
LPD	Set the function as Lp-D	YTD	Set the function as Y- $\theta^\circ$
LPG	Set the function as Lp-G	YTR	Set the function as Y- $\theta_r$
RPQ	Set the function as Rp-Q	RSQ	Set the function as Rs-Q

For example: WrtCmd (“FUNC:IMP RX”) Set the function as R-X.

Query syntax: FUNCtion:IMPedance?

Return format: <function><NL^END>

The FUNCtion:IMPedance:RANGe command is used to set the range. The FUNCtion:IMPedance:RANGe? query returns the current range.

Command syntax: FUNCtion:IMPedance:RANGe <value>

Where, <value> can be the impedance of the DUT or NR1, NR2 or NR3 data format followed by OHM or KOHM.

For example: WrtCmd (“FUNC:IMP:RANG 1KOHM”) Set the range as 1kOHM.

Query syntax: FUNCtion:IMPedance:RANGe?

Return format: <value><NL^END>

Where, <value> can be

3	10	30	
100	300	1000	3000
10000	30000	100000	

The FUNCtion:IMPedance:RANGe:AUTO command is used to set the automatic range selection status. The FUNCtion:IMPedance:RANGe:AUTO? query returns the current range status.

Command syntax:

FUNCtion:IMPedance:RANGe:AUTO  $\left\{ \begin{array}{l} \text{ON (1)} \\ \text{OFF (0)} \end{array} \right.$

Where,

Character 1 (49) is equal to ON.

---

Character 0 (48) is equal to OFF.

For example: WrtCmd (“FUNC:IMP:RANG:AUTO ON”) Set the automatic range as ON.

Query syntax: FUNCTION:IMPedance:RANGe:AUTO?

Return format: <NR1><NL^END>

The FUNCTION:Source MONitor:VIAC command is used to set the voltage monitor ON or OFF. The FUNCTION:Source MONitor:VIAC? query returns the current voltage monitor status.

FUNCTION:SMONitor:VIAC  $\left\{ \begin{array}{l} \text{ON (1)} \\ \text{OFF (0)} \end{array} \right.$

Where,

Character 1 (49) is equal to ON.

Character 0 (48) is equal to OFF.

For example: WrtCmd (“FUNC:SMON:VIAC ON”) Set the voltage monitor as ON.

Query syntax: FUNCTION:SMONitor:VIAC?

Return format: <NR1><NL^END>

The FUNCTION:DEV<n>:MODE command is used to set the deviation measurement mode. The FUNCTION:DEV<n>:MODE? query returns the current deviation measurement mode.

Command syntax:

FUNCTION:DEV<n>:MODE  $\left\{ \begin{array}{l} \text{ABSolute} \\ \text{PERCent} \\ \text{OFF} \end{array} \right.$

Where,

ABSolute Absolute value deviation display

PERCent Percent deviation display

OFF Real value display

Where, <n> is

Character 1 (49) is equal to the nominal value of primary parameter.

Character 2 (50) is equal to the nominal value of the secondary parameter.

For example: WrtCmd (“FUNC:DEV1:MODE ABS”)

Query syntax: FUNCTION:DEV<n>:MODE?

Return format:

ABX  
PERC } <NL^END>  
OFF }

The FUNCTION:DEV<n>:REFerence<value> command is used to set the nominal value of the deviation. The FUNCTION:DEV<n>:REFerence<value>? query returns the current nominal value of

---

the deviation.

Command syntax: FUNCtion:DEV<n>:REFerence<value>

Where,

<value> is NR1, NR2 or NR3 data format.

<n> is

Character 1 (49) is equal to the nominal value of primary parameter.

Or Character 2 (50) is equal to the nominal value of the secondary parameter.

For example: WrtCmd (“FUNC:DEV1:REF 10”)

Query syntax: FUNCtion:DEV<n>:REFerence?

Return format: <NR3><NL^END>

The FUNCtion:DEV<n>:REFerence:FILL command is used to set the nominal value of the deviation.

This command directs the instrument to make a test and then copies the results of the primary and the secondary parameters as the nominal values of the deviation.

Command syntax: FUNCtion:DEV<n>:REFerence:FILL

Where,

Character 1 (49) or character 2 (50) is equal to the nominal values of the primary and secondary parameters.

For example: WrtCmd (“FUNC:DEV1:REF:FILL”)

The FUNCtion:StepDELay command is used to set the step delay time. The :StepDELay? query returns the step delay time.

Command syntax:

StepDELay  $\left\{ \begin{array}{l} \text{<value>} \\ \text{MIN} \\ \text{MAX} \end{array} \right.$

Where,

<value> NR1, NR2 or NR3 data format, 0-60s with the resolution of 1mS.

MIN Set the delay time as 0s.

MAX Set the delay time as 60s.

For example: WrtCmd (“FUNC:SDEL 5S”) Set the delay time as 5s.

Query syntax: FUNC:SDEL?

Return format: <NR3><NL^END>

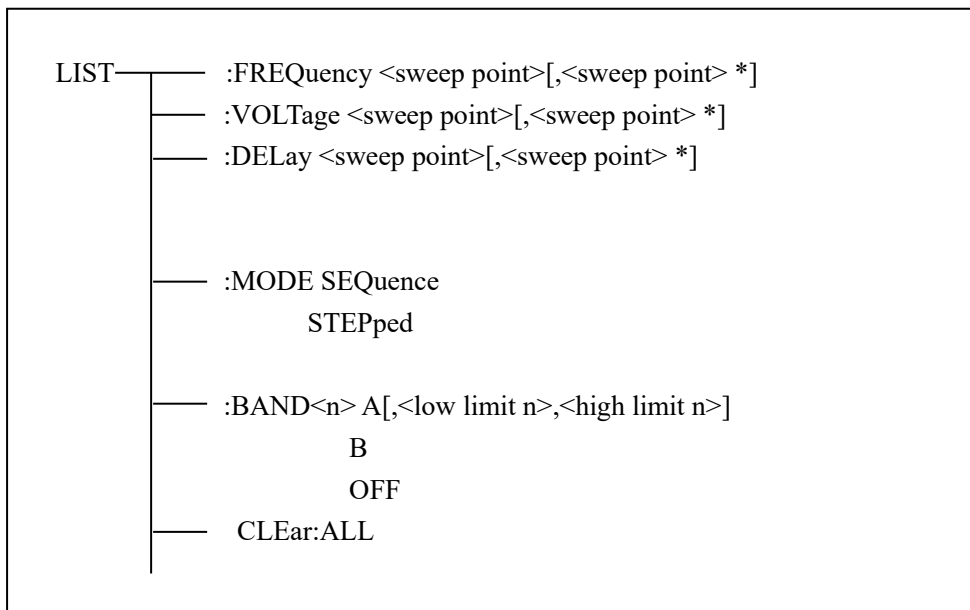
## 7.1.6 LIST subsystem commands

The LIST subsystem commands are mainly used to set the list sweep function, sweep points, sweep

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mode, sweep limits.

Command tree:



The LIST:FREQUency command is used to clear the original sweep points and set the frequencies of the sweep points. The LIST:FREQUency? query returns the current frequency of each sweep point.

Command syntax: LIST:FREQUency<value>[,<value>\*]

**NOTE: \* part means 10 sweep points at most can be set.**

Where,

<value> is NR1, NR2 or NR3 data format.

**<value> should be within the allowable frequency of the device, or return format will report errors.**

For example: WrtCmd("LIST:FREQ 1E3, 1E4")

Set the frequency of the sweep point 1 as 1KHZ;

Set the frequency of the sweep point 2 as 10KHZ;

**NOTE: HZ(hertz) is the suffix unit, MAHZ and MHZ is MHz (1E6 Hz).**

Query syntax: LIST:FREQUency?

Return format: <NR3>, [,<NR3>\*]<NL^END>

The LIST:VOLTage command is used to clear the original voltage of the each sweep point and reset the voltage. The LIST:VOLTage? query returns the current voltage of each sweep point.

Command syntax: LIST:VOLTage<value>[,<value>\*]

---

**NOTE: \* part means 10 sweep points at most can be set.**

Where,

<value> is NR1, NR2 or NR3 data format.

For example: WrtCmd (“LIST:VOLT 1.0”)

Set the frequency of the sweep point 1 as 1.0V.

WrtCmd (“LIST:VOLT 1E-1, 1E0”)

Set the frequencies of sweep point 1, 2 respectively as 100mV, 1V

**NOTE: This command can be followed by suffix unit V.**

Query syntax: LIST:VOLTage?

Return format:<NR3>[,<NR3>\*]<NL^END>

**NOTE: <value> should be set as 0.1V, 0.3V, 1V, or return format will report errors.**

The LIST:DElay command is used to clear the original list sweep point delay. Can query the current list for each sweep point delay.

Command syntax:LIST:DElay <value>[,<value> \*]

**NOTE: \* part means 10 sweep points at most can be set.**

Where,

<value> is NR1, NR2 or NR3 data format.

For example: WrtCmd(“LIST:DEL 1.0”) Set the delay of sweep point 1 as 1s.

WrtCmd(“LIST:DEL 1E1,1E0”) Set the delay of sweep point 1, 2 respectively as 10s, 1s

Query syntax:LIST: DElay?

Return format:<NR3>[,<NR3>\*]<NL^END>

**NOTE: <value> should be set within 0-60s,or return format will report errors.**

The LIST:MODE command is used to set the list sweep mode. The LIST:MODE? query returns the current list sweep mode.

Command syntax:

LIST:MODE  $\left\{ \begin{array}{l} \text{SEquence} \\ \text{STEPped} \end{array} \right\}$

Where,

SEquence means sequential mode.

STEPped means single step mode.

For example: WrtCmd (“LIST:MODE SEQ”)

Query syntax: LIST:MODE?

Return format:

$\left\{ \begin{array}{l} \text{SEQ} \\ \text{STEP} \end{array} \right\}$  <NL^END>

The LIST:BAND<n> command is used to set the limits of list sweep table. The LIST:BAND<n>? query returns the current limits.



---

Command syntax: LIST:BAND<n><parameter>[,<low limit n>,<high limit n>]

Where,

<n> 1 to 10 (NR1 format): sweep points on the n<sup>th</sup> line

<parameter> A Compare the primary parameter of the test results with the high and the low limits.

B Compare the secondary parameter of the test results with the high and the low limits.

OFF No comparison

<low limit n> NR1, NR2 or NR3 data format, low limit of the sweep point on the n<sup>th</sup> line.

<high limit n> NR1, NR2 or NR3 data format, high limit of the sweep point on the n<sup>th</sup> line.

For example: WrtCmd (“LIST:BAND1 A, 10, 20”)

WrtCmd (“LIST:BAND3 OFF”)

Query syntax: LIST:BAND<n>?

Return Format: <parameter>, <low limit n>, <high limit n>

The LIST:CLear command is used to clear all the data in list sweep mode.

Command syntax:

LIST:CLEAR:ALL

For example: WrtCmd (“LIST:CLEAR:ALL”)

### 7.1.7 APERture subsystem commands

The APERture subsystem commands are mainly used to set the measurement speed, average times used in measurement. The APERture? query returns the current measurement speed, average times.

Command syntax:

APERture  $\left\{ \begin{array}{l} \text{FAST} \\ \text{MEDium} \\ \text{SLOW} \end{array} \right\} [,<value>]$

Where,

FAST: 53 times/sec

MEDium: 12 times/sec

SLOW: 3 times/sec

<value> 1 to 255 in NR1

For example: WrtCmd (“APER MED, 55”)

Query syntax: APERture?

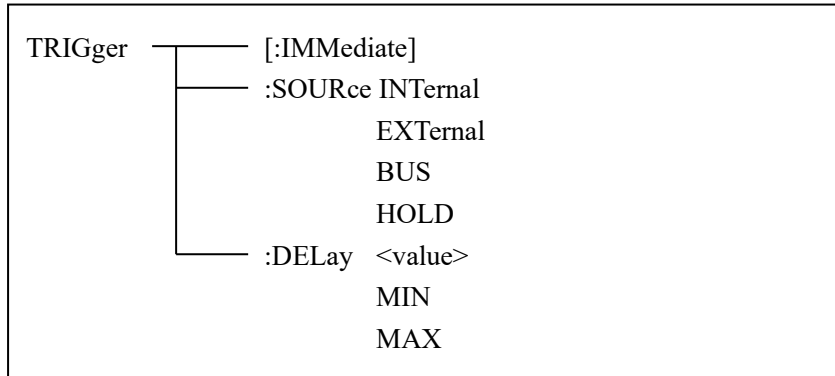
Return format:

$\left\{ \begin{array}{l} \text{FAST} \\ \text{MED} \\ \text{SLOW} \end{array} \right\} , <NR1><NL^END>$

## 7.1.8 TRIGger subsystem commands

The TRIGger subsystem commands are mainly used to set the instrument trigger source, trigger delay and trigger measurement.

Command tree:



The TRIGger[:IMMEDIATE] command is used to trigger a test.

Command syntax: TRIGger[:IMMEDIATE]

For example: WrtCmd("TRIG")

The TRIGger:SOURce command is used to set the trigger source mode. The TRIGger:SOURce? query returns the current trigger source mode.

Command syntax:

TRIGger:SOURce {  
 INTERNAL  
 EXTernal  
 BUS  
 HOLD

Where,

- INTERNAL The default trigger mode.
- EXTernal Triggered by HANDLER interface.
- BUS Triggered by RS232C interface or GPIB interface
- HOLD Triggered by pressing **TRIGGER**.

For example: WrtCmd ("TRIG:SOUR BUS")

Query syntax: TRIGger:SOURce?

Return format:

{  
 INT  
 EXT  
 BUS  
 HOLD } <NL^END>

The TRIGger:DELay command is used to set the delay time after triggering. The TRIGger:DELay? query returns the current delay time.

Command syntax:

{  
 <value>  
 77

---

TRIGger:DELay    MIN  
MAX

Where,

<value>    In NR1, NR2 or NR3 data format, from 0 to 60s with 1ms as the resolution.

MIN        Set the delay time as 0s.

MAX        Set the delay time as 60s.

For example: WrtCmd (“TRIG:DEL 5s”)    Set the delay time as 5s.

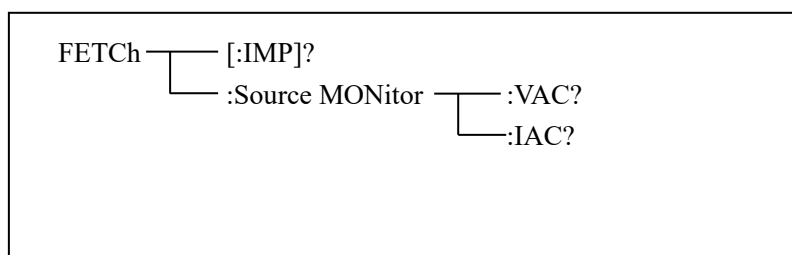
Query syntax: TRIGger:DELay?

Return format: <NR3><NL^END>

### 7.1.9 FETCh? subsystem commands

The FETCh? subsystem commands are mainly used to direct TH2817B+ to input a measurement result.

Command tree:



The FETCh[:IMP]? query directs TH2817B+ to input the last measurement result to the output buffer zone.

Query syntax: FETCh[:IMP]?

For example:    WrtCmd (“TRIG:SOUR BUS”)

                  WrtCmd (“TRIG”)

                  WrtCmd (“FETC?”)

TH2817B+ applies ASCII to delivery result, details are follows.

On measurement display page, bin NO. display page, bin count display page, ASCII data output format are described as below:

`SN.NNNNNESNN` , `SN.NNNNNESNN` , `SN` , `SN or SNN` `NL^END`  
<DATA A>                    <DATA B>                    <Status>                    <BIN number>

Where,

<DATA A>, <DATA B> format: <DATA A> (primary measurement data), <DATA B> (secondary measurement data)

12-digits ASCII format are as below:

SN.NNNNNESNN

(S:+/-.N: from 0 to 9, E: Exponent Sign)

Status	Description
-1	(In data buffer memory) no data
0	Common measurement data
+1	Analog LCR unbalance
+2	A/D converter is not working.
+3	Signal source is over loading.
+4	Constant voltage cannot be adjusted.

<status> format: When above measurement data is used, <status> data will display measurement status.

The output format of the <Status> display data uses 2-digits ASCII: SN (S: +/-, N: from 0 to 4)

**NOTE: When <status> is -1, 1 or 2, the measurement data is 9.99999E37. When <status> is 0, 3 or 4, the real measurement data is beyond the limits.**

Data	Sort result
0	Out of tolerance
+1	Bin 1
+2	Bin 2
+3	Bin 3
+4	Bin 4
+5	Bin 5
+6	Bin 6
+7	Bin 7
+8	Bin 8
+9	Bin 9
+10	Auxiliary bin

<Bin No.> format: The data displays the sorting results of the displayed bin, shown as above.

Only when the instrument compare function is set as ON, <bin No.> data can be displayed.

The output format of <bin No.> data applies 2 to 3 digits ASCII: SN or SNN (S: +/-, N: from 0 to 9).

**On list sweep display page, the ASCII data output format is shown as below, that is, the return-circuit replaces sweep point number.**

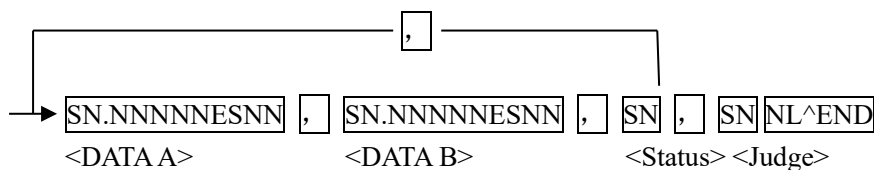


Figure 6 ASCII format 2 (list sweep)

Where,

Descriptions for <DATA A>, <DATA B>, <Status> are the same described before. <Judge> format is

---

as below:

<Input/Output> format: The data displays the compare result of the list sweep..

Data	Result
-1	low
0	pass
+1	high

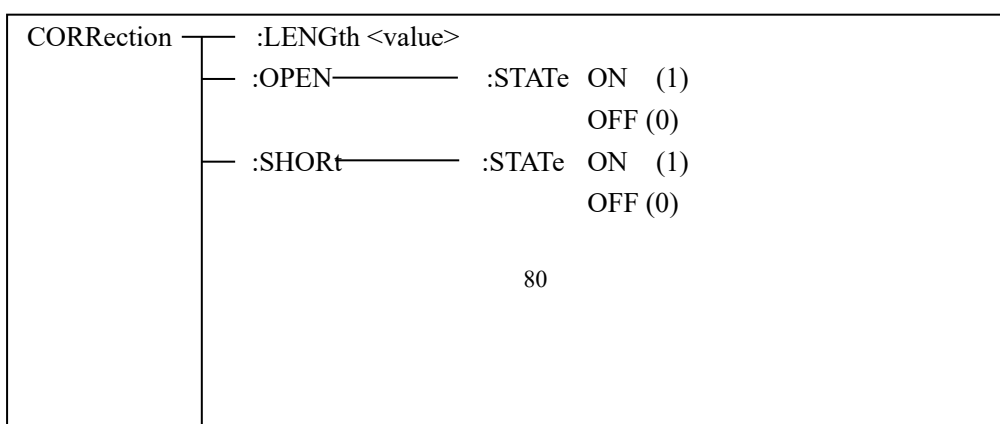
When the compare function of the list sweep measurement is turned off, the output result of <Input/Output> is 0.

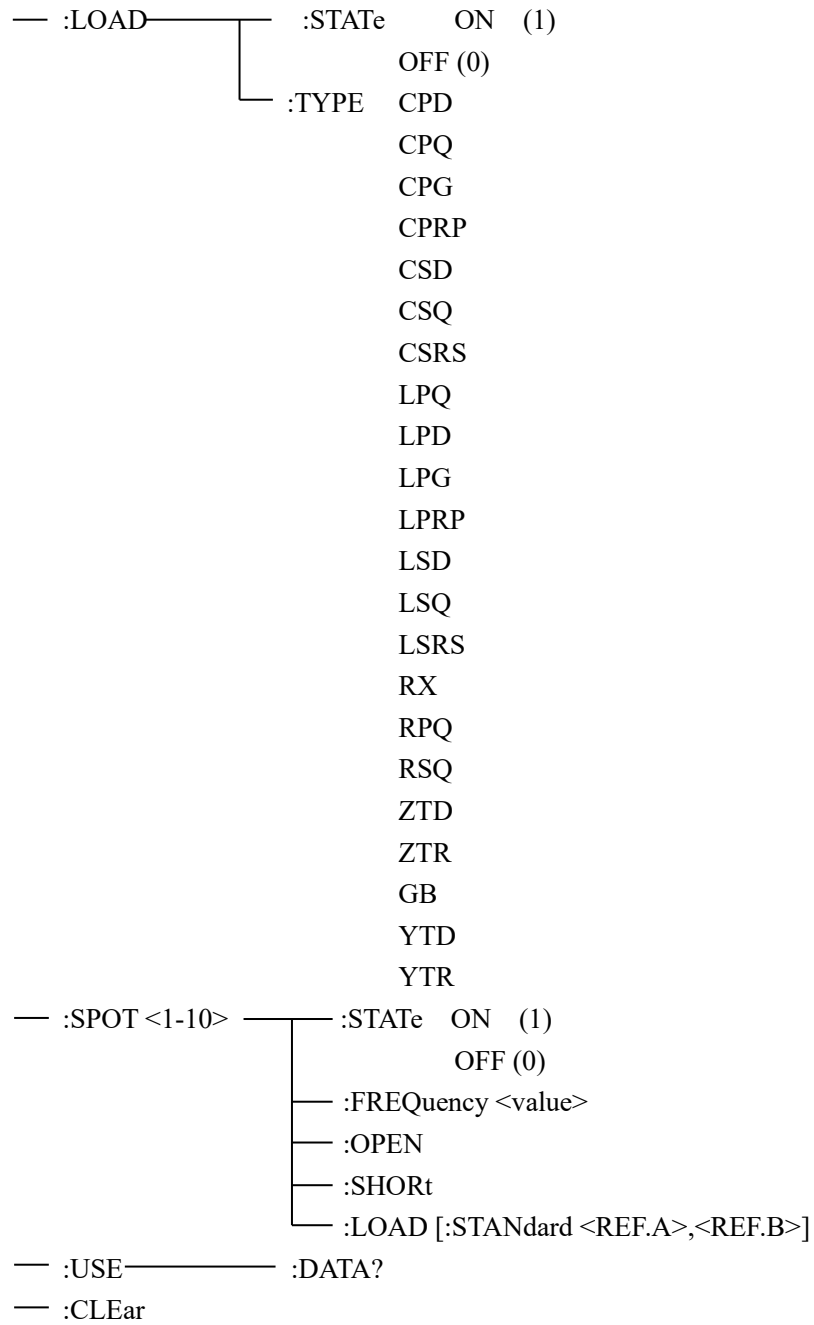
<Input/Output> data output format applies 2-digits ASCII format: SN (S: +/-, N: from 0 to 1)

### 7.1.10 CORRection subsystem commands

The CORRection subsystem commands are mainly used to set the correction function, OPEN, SHORT, LOAD.

Command tree:





The CORRection:LENGth command is used to set the correction cable length. The CORRection:LENGth? query returns the current set cable length.

Command syntax: CORRection:LENGth<value>

Where,

<value> is 0, 1, 2 or 4 followed by M.

For example: WrtCmd (“CORR:LENG 1M”)      Set the cable length as 1 meter.

**(At present, only 0M data is available.)**

---

Query syntax: CORRection:LENGth?

Return format: <NR1><NL^END>

The CORRection:OPEN command is used to execute open correction for 10 preset test points (TH2817B+ has 10 preset test points).

Command syntax: CORRection:OPEN

For example: WrtCmd (“CORR:OPEN”)

The CORRection:OPEN:STATe command is used to set the open correction ON or OFF. The CORRection: OPEN:STATe? query returns the current open correction status.

Command syntax:

CORRection:OPEN:STATe  $\left\{ \begin{array}{c} \text{ON} \\ \text{OFF} \\ 1 \\ 0 \end{array} \right\}$

Where,

1 (decimal 49) is equal to ON.

0 (decimal 48) is equal to OFF.

For example: WrtCmd (“CORR:OPEN: STAT ON”)

Query syntax: CORRection:OPEN:STATe?

Return format: <NR1><NL^END>

The CORRection:SHORT command is used to execute short correction for 10 preset test points (TH2817B+ has 10 preset test points).

Command syntax: CORRection:SHORT

For example: WrtCmd (“CORR:SHOR”)

The CORRection:SHORT:STATe command is used to set the short correction status. The CORRection:SHORT:STATe? query returns the current short correction status.

Command syntax:

CORRection:SHORT:STATe  $\left\{ \begin{array}{c} \text{ON} \\ \text{OFF} \\ 1 \\ 0 \end{array} \right\}$

Where,

1 (decimal 49) is equal to ON.

0 (decimal 48) is equal to OFF.

For example: WrtCmd (“CORR:SHOR:STAT ON”)

Query syntax: CORRection:SHORT:STATe?

Return format: <NR1><NL^END>

The CORRection:LOAD:STATe command is used to set load correction. The CORRection:LOAD:STATe? query returns the current load correction status.

Command syntax:

CORRection:LOAD:STATe  $\left\{ \begin{array}{l} \text{ON} \\ \text{OFF} \\ 1 \\ 0 \end{array} \right\}$

Where,

1 (decimal 49) is equal to ON.

0 (decimal 48) is equal to OFF.

For example: WrtCmd (“CORR:LOAD:STAT ON”)

Query syntax: CORRection:LOAD:STATe?

Return format: <NR1><NL^END>

The CORRection:LOAD:TYPE command is used to set the tested parameter type. The CORRection:LOAD:TYPE query returns the current parameter type.

Details of function are as follows:

CPD	Set the function as Cp-D	LPRP	Set the function as Lp-Rp
CPQ	Set the function as Cp-Q	LSD	Set the function as Ls-D
CPG	Set the function as Cp-G	LSQ	Set the function as Ls-Q
CPRP	Set the function as Cp-Rp	LSRS	Set the function as Ls-Rs
CSD	Set the function as Cs-D	RX	Set the function as R-X
CSQ	Set the function as Cs-Q	ZTD	Set the function as Z-θ°
CSRS	Set the function as Cs-Rs	ZTR	Set the function as Z-θr
LPQ	Set the function as Lp-Q	GB	Set the function as G-B
LPD	Set the function as Lp-D	YTD	Set the function as Y-θ°
LPG	Set the function as Lp-G	YTR	Set the function as Y-θr
RPQ	Set the function as Rp-Q	RSQ	Set the function as Rs-Q

For example: WrtCmd (“CORR:LOAD:TYPE CPD”)

Query syntax: CORRection:LOAD:TYPE?

Return format: <function><NL^END>

The CORRection:SPOT<n>:STATe command is used to set the specific frequency spots. The CORRection:SPOT<n>:STATe query returns the current state of each frequency spot (FREQ 1, FREQ 2).

Command syntax:

CORRection:SPOT<n>:STATe  $\left\{ \begin{array}{l} \text{ON} \\ \text{OFF} \\ 1 \\ 0 \end{array} \right\}$



---

Where,

1 (decimal 49) is equal to ON.

0 (decimal 48) is equal to OFF.

<n>:

1 refers to frequency spot 1.

2 refers to frequency spot 2.

For example: WrtCmd (“CORR:SPOT1:STAT ON”)

Query syntax: CORRection:SPTO<n>:STATe?

Return format: <NR1><NL^END>

The CORRection:SPOT<n>:FREQuency command is used to set the specific correction point frequency. The CORRection:SPOT<n> query returns the current specific correction point frequency.

Command syntax: CORRection:SPOT<n>:FREQuency<value>

Where,

<value> can be NR1, NR2 or NR3 data format followed by HZ, KHZ and MHZ.

For example: WrtCmd(“CORR:SPOT1:FREQ 1KHZ”) Set the frequency of frequency spot 1 as 1KHZ.

**NOTE: <value> should be 100HZ,120,1K,10KHZ, or return format will report errors.**

Query syntax: CORRection:SPOT<n>:FREQuency?

Return format: <NR3><NL^END>

The CORRection:SPOT<n>:OPEN command is used to execute open correction for specific correction point.

Command syntax: CORRection:SPOT<n>:OPEN

Where,

<n>: 1-10

For example: WrtCmd (“CORR:SPOT1:OPEN”) Execute open correction for correction point 1.

The CORRection:SPOT<n>:SHORT command is used to execute short correction for specific correction point.

Command syntax: CORRection:SPOT<n>:SHORT

Where,

<n>:1-10

For example: WrtCmd (“CORR:SPOT1:SHOR”) Execute short correction for correction point 1.

The CORRection:SPOT<n>:LOAD:STANdard command is used to set the standard reference of specific correction point which are taking load correction. The CORRection:SPOT<n>:LOAD:STANdard query returns the current standard reference of specific

---

correction point.

Command syntax: CORRection:SPOT<n>:LOAD:STANdard <REF. A><REF. B>

Where,

<n>:1-10

<REF. A> can be NR1, NR2 or NR3 data format and taken as the standard reference of the primary parameter.

<REF. B> can be NR1, NR2 or NR3 data format and taken as the standard reference of the secondary parameter.

For example: WrtCmd (“CORR:SPOT1:LOAD:STAN 100.7, 0.0002”)

Query syntax: CORRection:SPOT<n>:LOAD:STANdard?

Return format: <NR3><NL^END>

The CORRection:USE:DATA? query returns the OPEN/SHORT/LOAD correction measurement data of all the correction points.

Command syntax: CORRection:USE:DATA?

Return format: <open (n) A>,<open(n) B>,<short (n) A>,<short (n) B>,<load (n) A>,<load (n) B>

Where,

<open (n) A> is NR3 data format and the primary open correction data at frequency spot.

<open (n) B> is NR3 data format and the secondary open correction data at frequency spot.

<short (n) A> is NR3 data format and the primary short correction data at frequency spot.

<short (N) B> is NR3 data format and the secondary short correction data at frequency spot.

<load (n) A> is NR3 data format and the primary load correction data at frequency spot.

<load (n) B> is NR3 data format and the secondary load correction data at frequency spot.

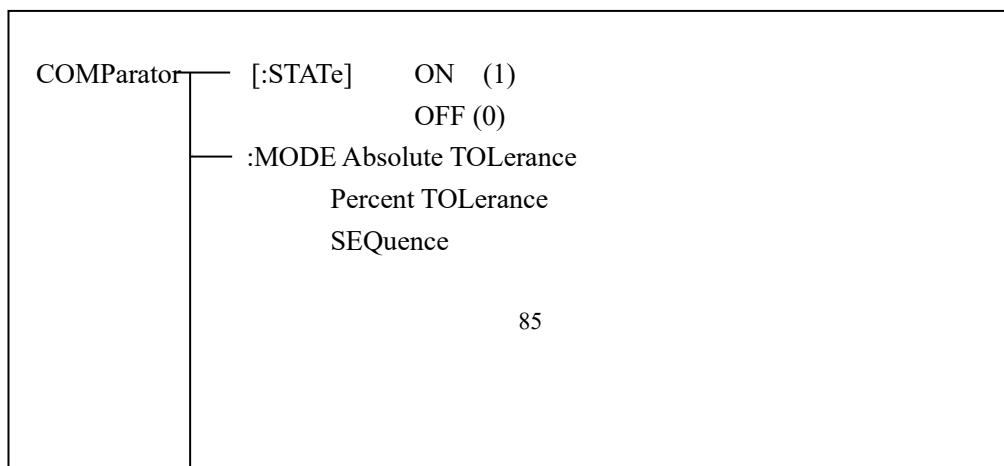
The CORRection:CLEAR query is used to clear all the correction data.

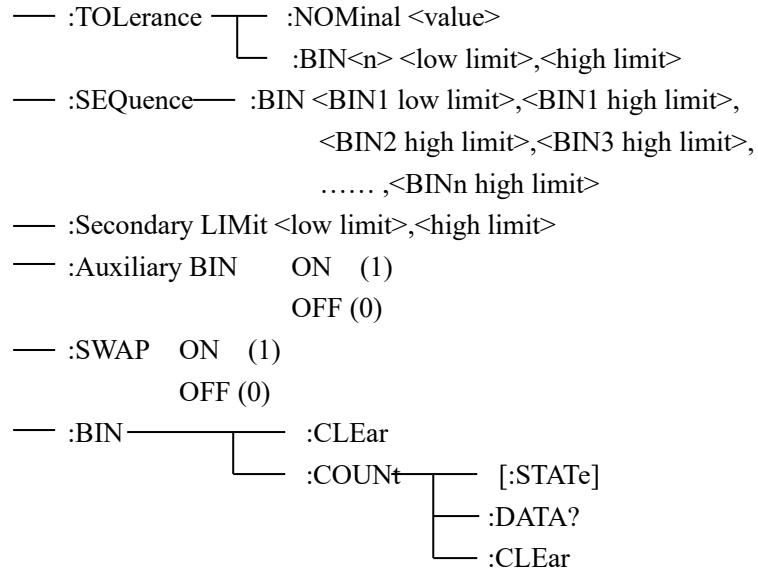
Query syntax: CORRection:CLEAR

### 7.1.11 COMParator subsystem commands

The COMParataor subsystem commands are used to set the bin comparator function including ON/OFF setting, Limit table setting.

Command tree:





The COMPArator[STATe] command is used to set the comparator function as ON or OFF. The COMPArator[STATe]? query returns the current comparator state.

Command syntax:

$$\text{COMPArator}[:\text{STATe}] \left\{ \begin{array}{l} \text{ON} \\ \text{OFF} \\ 1 \\ 0 \end{array} \right\}$$

Where,

1 (decimal 49) is equal to ON.

0 (decimal 48) is equal to OFF.

For example: WrtCmd (“COMP ON”)

Query syntax: COMPArator[:STATe]?

Return format: <NR1><NL^END>.

The COMPArator:MODE command is used to set the comparator mode. The COMPArator:MODE? query returns the current mode.

Command syntax:

$$\text{COMPArator:MODE} \left\{ \begin{array}{l} \text{ATOLerance} \\ \text{PTOLerance} \\ \text{SEQuence} \end{array} \right\}$$

Where,

ATOLerance means absolute tolerance mode.

PTOLerance means proportional tolerance mode.

SEQuence means sequential tolerance mode.

---

For example: WrtCmd (“COM:MODE ATOL”)

Query syntax: COMPArator:MODE?

Return format:  $\left. \begin{array}{l} \text{ATOL} \\ \text{PTOL} \\ \text{SEQ} \end{array} \right\} \langle \text{NL}^{\wedge} \text{END} \rangle$

The COMPArator:TOLerance:NOMinal command is used to set the nominal value (this function is valid only when the limit mode is set as deviation mode). The COMPArator:TOLerance:NOMinal? query returns the current nominal value.

Command syntax: COMPArator:TOLerance:NOMinal<value>

Where,

<value> is a nominal value in NR1, NR2 or NR3 data format.

For example: WrtCmd (“COMP:TOL:NOM 100E-12”)

Query syntax: COMPArator:TOLerance:NOMinal?

Return format: <NR3><NL^END>

The COMPArator:TOLerance:BIN<n> command is used to set the high and the low limits of each bin (this function is valid only when the limit mode is set as deviation mode). The COMPArator:TOLerance:BIN<n>? query returns the current high and the low limits of each bin.

Command syntax: COMPArator:TOLerance:BIN<n><low limit><high limit>

Where,

<n> is the bin number from 1 to 9.

<low limit> is the low limit in NR1, NR2 or NR3 data format.

<high limit> is the high limit in NR1, NR2 or NR3 data format.

**NOTE: The low limit should be smaller than the high limit, or error information will be reported.**

For example: WrtCmd (“COMP:TOL:BIN1 -5,5”)

WrtCmd (“COMP:TOL:BIN2 -10,10”)

Query syntax: COMPArator:TOLerance:BIN<n>?

Return format: <low limit><high limit><NL^END>

The COMPArator:SEQuence:BIN command is used to set the high and the low limits of sequential mode (this function is valid only when the limit mode is set as the sequential mode.). The COMPArator:SEQuence:BIN? query returns the current high and the low limits of each bin.

Command syntax: COMPArator:SEQuence:BIN <BIN1 low limit>, <BIN 1 high limit>, <BIN2 high limit>, ..., <BINn high limit>

Where,

<BIN1 low limit> is the low limit of BIN 1 in NR1, NR2 or NR3 data format.

<BIN1 high limit> is the high limit of BIN1 in NR1, NR2 or NR3 data format.

<BINn high limit> is the high limit of BINn (the maximum of n is 9) in NR1, NR2 or NR3 data format.

**NOTE: The low limit should be smaller than the high limit, or error information will be reported.**

---

For example: WrtCmd (“COMP:SEQ:BIN 10, 20, 30, 40, 50”)

Query syntax: COMPArator:SEQuence:BIN?

Return format: <BIN1 low limit>, <BIN1 high limit>, <BIN2 high limit>, ...,  
<BINn high limit><NL^END>

The COMPArator:Secondary LIMit command is used to set the high and the low limits of the secondary parameter. The COMPArator:Secondary LIMit query returns the current high and the low limits of the secondary parameter.

Command syntax: COMPArator:SLIMit<low limit><high limit>

Where,

<low limit> is the low limit in NR1, NR2 or NR3 data format.

<high limit> is the high limit in NR1, NR2 or NR3 data format.

**NOTE: The low limit should be smaller than the high limit, or error information will be reported.**

For example: WrtCmd (“COMP:SLIM 0.001, 0.002”)

Query syntax: COMPArator:SLIMit?

Return format: <NR3>, <NR3> <NL^END>

The COMPArator:Auxiliary BIN command is used to set the auxiliary bin as ON or OFF. The COMPArator:Auxiliary BIN? query returns the current auxiliary bin state.

Command syntax:

COMPArator:Auxiliary BIN  $\left\{ \begin{array}{c} \text{ON} \\ \text{OFF} \\ 1 \\ 0 \end{array} \right\}$

Where,

1 (decimal 49) is equal to ON.

0 (decimal 48) is equal to OFF.

For example: WrtCmd (“COMP:ABIN ON”)

Query syntax: COMPArator:Auxiliary BIN?

Return format: <NR1><NL^END>

The COMPArator:SWAP command is used to set the swap mode ON or OFF. For example: the original function parameter is Cp-D, after the SWAP mode is set as ON, the function parameter will be changed as D-Cp. In this case, the limits from BIN1 to BIN9 become the high and the low limits of D, the original secondary limits become that of Cp. That is to say, this function is to make swap comparison between the primary and the secondary parameters. On the contrary, If OFF is selected, the comparison will be made according to the original sequence. The COMPArator:SWAP? query returns the current state of the swap function.

Command syntax:

$\left\{ \begin{array}{c} \text{ON} \\ \end{array} \right\}$

---

COMParator:SWAP            OFF  
                                  1  
                                  0

Where,

1 (decimal 49) is equal to ON.

0 (decimal 48) is equal to OFF.

For example: WrtCmd (“COMP:SWAP ON”)

Query syntax: COMParator:SWAP?

Return format: <NR1><NL^END>

The COMParator:BIN:CLEar command is used to clear all limits on limit table setup page.

Command syntax: COMParator:BIN:CLEar

For example: WrtCmd (“COMP:BIN:CLE”)

The COMParator:BIN:COUNT[:STATe] command is used to set the bin count function as ON or OFF.

The COMParator:BIN:COUNT[:STATe]? query returns the current state of the bin count function.

Command syntax:

COMParator:BIN:COUNT[:STATe]       $\left. \begin{array}{c} \text{ON} \\ \text{OFF} \\ 1 \\ 0 \end{array} \right\}$

Where,

1 (decimal 49) is equal to ON.

0 (decimal 48) is equal to OFF.

For example: WrtCmd (“COMP:BIN:COUN ON”)

Query syntax: COMParator:BIN:COUNT[STATe]?

Return format: <NR1><NL^END>

The COMParator:BIN:COUNT:DATA? query returns the current comparison result of the bin count.

Query syntax: COMParator:BIN:COUNT:DATA?

Return format: <BIN1 count>, <BIN2 count>, ..., <BIN9 count>, <OUT OF BIN count>, <AUX BIN count><NL^END>

Where,

<BIN1-9 count> is the count result of BIN1-9, in NR1 data format.

<OUT OF BIN count> is the count result of the OUT OF BIN, in NR1 data format.

<AUX BIN count> is the count result of the auxiliary bin, in NR1 data format.

The COMParator:BIN:COUNT:CLEar command is used to clear all bin count results.

Command syntax: COMParator:BIN:COUNT:CLEar

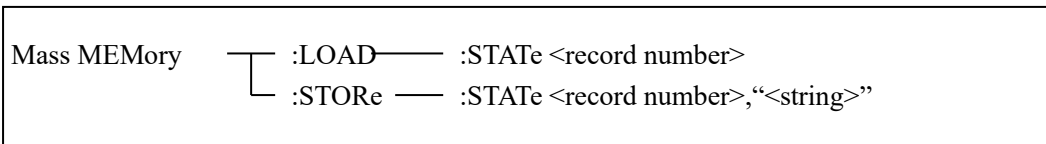
---

For example: WrtCmd (“COMP:BIN:COUN:CLE”)

### 7.1.12 Mass MEMory subsystem commands

The Mass MEMory subsystem commands are used for file storing and load.

Command tree:



The MMEMory:LOAD:STATe command is used to load the existed file.

Command syntax: MMEMory:LOAD:STATe<value>

Where,

<value> is the file number ranging from 0 to 39 (NR1).

For example: WrtCmd (“MMEM:LOAD:STAT 1”)

The MMEMory:STORE:STATe command is used to storing the current setting to a file.

Command syntax: MMEMory:STOR:STATe<value>,”<string>”

Where,

<value> is the file number ranging from 0 to 39 (NR1).

<string> can be ASCII character string (maximum length is 16).

For example: WrtCmd (“MMEM:STOR:STAT 1,”Resistor meas”)

or WrtCmd (“MMEM:STOR:STAT 1”), **IF “,”<string>” has not been input, the default file name will be stored.**

## 7.2 GPIB Common Commands

- \*RST
- \*TRG
- \*IDN
- \*TST
- \*ESE
- \*SRE
- \*ESR
- \*STB
- \*OPC
- \*CLS

- The \*RST command resets the instrument.  
For example: WrtCmd (“\*RST”)
- The \*TRG command triggers the measurement and then sends the result to the output buffer.  
For example: WrtCmd (“\*TRG”)
- The \*CLS command clears the standard event status register and the service request status register.  
Command syntax: \*CLS  
For example: WrtCmd (“\*CLS”)

- The \*IDN? query returns TH2817B+ ID.

Query syntax: \*IDN?

Return format: <manufacturer>,<model>,<firmware><NL^END>

Where,

<manufacturer>      Name of Manufacturer ( Tonghui)  
 <model>                Instrument Model (TH2817B+)  
 <firmware>            Firmware Version (VER1.0.0)  
 <HW\_version>        Hardware Version (Hardware Ver A5.0)

For example: WrtCmd(“\*IDN?”);

- The \*TST? query executes an internal self test and returns the test result as the sum of all existing errors codes. If there are no error TH2817B+ returns 0.

Query syntax: \*TST?

Return format: 0<NL^END>

Where,

0            0 (NR1 format)

For example: WrtCmd(“\*TST?”);

- The \*ESE (standard Event Status Enable command) command sets each open bit of the standard event status register. This command returns setups of each open bit for the standard event status permission register.

Command syntax: \*ESE<value>

Where,

<value>    NR1 format: decimal expression for each bit of operation status register.

Descriptions for each byte of the standard event status register are shown as follows:

Bit number	Description
7	Power On(PON) Bit
6	User Request(URQ) Bit
5	Command Error(EME) Bit
4	Execution Error(EXE) Bit
3	Device Dependent Error(DDE) Bit
2	Query Error(QYE) Bit
1	Request Control(RQC) Bit
0	Operation Complete(OPC) Bit

Query syntax: \*ESE?

Return format: <value><NL^END>

For example: WrtCmd ( “\*ESE?”)

- The \*SRE (Service Request Enable command) command sets each open bit of the service



status byte register. This command returns the current setups for each open bit of the status byte permission register.

Command syntax: \*SRE<value>

Where,

<value> NR1 format: decimal expression for each permission bit of the status byte register.

Descriptions for each byte of the status byte register are shown as follows:

Bit number	Description
7	Operation Status Register Summary Bit
6	RQS(Request Service) Bit
5	Standard Event Status Register Summary Bit
4	MAV(Message Available) Bit
3-0	Always 0(zero):

Query syntax: \*SRE?

Return format: <value><NL^END>

For example: WrtCmd(“\*SRE?”);

- The \*ESR? query returns the contents of the standard event status register.

Query syntax: \*ESR?

Return format: <value><NL^END>

Where,

<value> NR1 format: decimal expression for contents of the standard event status register.

Descriptions for each bit of the standard event status register

Bit number	Description
7	Power On(PON) Bit
6	User Request(URQ) Bit
5	Command Error(EME) Bit
4	Execution Error(EXE) Bit
3	Device Dependent Error(DDE) Bit
2	Query Error(QYE) Bit
1	Request Control(RQC) Bit
0	Operation Complete(OPC) Bit

For example: WrtCmd (“\*ESR?”)

- The \*STB? query returns contents of the standard service status byte register. The execution of this command will not affect contents of the standard status byte register.

Query syntax: \*STB?

Return format: <value><NL^END>

---

Where,

<value> NR1 format: decimal expression for contents of the standard status byte register.

Descriptions for each bit of the standard status byte register

Bit number	Description
7	Operation Status Register Summary Bit
6	RQS(Request Service) Bit
5	Standard Event Status Register Summary Bit
4	MAV(Message Available) Bit
3-0	Always 0(zero)

For example: WrtCmd (“\*STB?”)

- The \*OPC command equals to set the OPC bit of the standard event status register when TH2817B+ finishes all parameter measurements. Ever since all pending operations have been completed, this command will inform the instrument to add a ASCII number “1” (decimal number: 49) into the output buffer.

Command syntax: \*OPC

For example: OUTPUT 717; “\*OPC”! Set the OPC bit of the instrument when the last command is done.

Query syntax: \*OPC?

Return format: 1 <NL^END>

Where,

1 ASCII number 1 (decimal number: 49)

For example: WrtCmd (“\*OPC?”)

---

# Chapter 8 The description for Handler (optional)

The TH2817B+ provides the Handler interface for you. The interface is mainly used for the output of the sorted result. The interface offers the communication signal and the signal for the output of the sorted result. The separator result is corresponding to the output of BIN 10. The design for the Handler interface is very smart with the status of the output signal can be defined according to your application target.

## 8.1 Technical description

The following table shows the description for TH2817B+ HANDLER.

The output signal: low effective, open collector output, optoelectronic isolation
Output signal judgment:
BIN comparator: good, over the standard, not good
List sweep comparator: IN/OUT for every sweep point and pass/fail for all the compared result.
INDEX: AD Conversion ended
EOC: end of one test and comparison
Alarm: alarm for circuit interruption
The input signal: optoelectronic isolation
Keylock: lock the keys on the front panel
External Trigger: pulsewidth $\geq 1\mu\text{S}$
Table 1 Technical description

## 8.2 The operation description

### 8.2.1 Introduction

The information provided in this chapter includes the necessary descriptions of using the Handler interface signal lines and electrical features.

### 8.2.2 The definition for the signal line

The Handler interface has 3 signal lines: comparison output, control output and control input. The signal line's definition for the BIN comparison or list sweep comparison is below:

#### Comparison signal lines:

- Comparison output signal  
/BIN1 - /BIN9, /AUX, /OUT, /PHI (the main parameter is higher), /PLO (the main parameter is lower), /SREJ (the secondary parameter is not good). The signal line distribution for comparison out

is shown in the figure above.

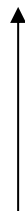
- Control output signal  
/INDEX (analog test finished signal), /EOM (test ended and the compared data effective), /ALARM (the circuit interruption)
- Control input signal  
/EXT.TRIG (external trigger signal), /Keylock (the key lock).

The signal distribution for the pins is described in Table 2:

Pin	Signal name	Description
1	/BIN1	BIN sorted result /BIN (BIN number) output are all open collector output.
2	/BIN2	
3	/BIN3	
4	/BIN4	
5	/BIN5	
6	/BIN6	
7	/BIN7	
8	/BIN8	
9	/BIN9	
10	/OUT	
11	/AUX	
12	/EXT.TRIG	External trigger: when the trigger mode is EXT.TRIG, TH2817B+ will be triggered by the positive-edge pulse signal in this pin.
13		
14	EXT.DCV2	External DC voltage 2: The DC provider pin for the optoelectronic coupling signal(/EXT_TRIG, /KeyLock, /ALARM, /INDEX, /EOM)
15		
16	+5V	The internal power +5V: to use the internal power is not recommended. If you use the internal power, please ensure that the current is lower than 0.3A and the signal line is far from the disturbance source.
17		
18		
19	/PHI	The main parameter is higher: the test result is greater than the high limit in BIN1 to BIN9.
20	/PLO	The main parameter is lower: the test result is less than the low limit in BIN1 to BIN9.
21	/SREJ	The secondary parameter is not good: the test result is not in the range of the high limit and the low limit.

22	NC	Not connect.
23	NC	
24	NC	
25	/KEY LOCK	When this line is effective, the keys in the front panel are locked.
27 28	EXT.DCV1	The external DC voltage 1: the pull-up DC power provider pin for optoelectronic coupling signal(/BIN-/BIN9,/AUX, /OUT,/PHI,/PLO,/SREJ).
29	/ALARM	When circuit is interrupted, /ALARM is effective.
30	/INDEX	When the analog test is finished and the UNKNOWN terminal can be connected to another DUT, /INDEX is effective. But the comparison signal is effective until /EOM is effective.
31	/EOM	End Of Measurement: when the test data and the compared result are effective, this signal is effective.
32,33	COM2	The reference ground for external power EXTV2.
34,35,36	COM1	The reference ground for external power EXTV1.

Table 2 signal distribution for the pins

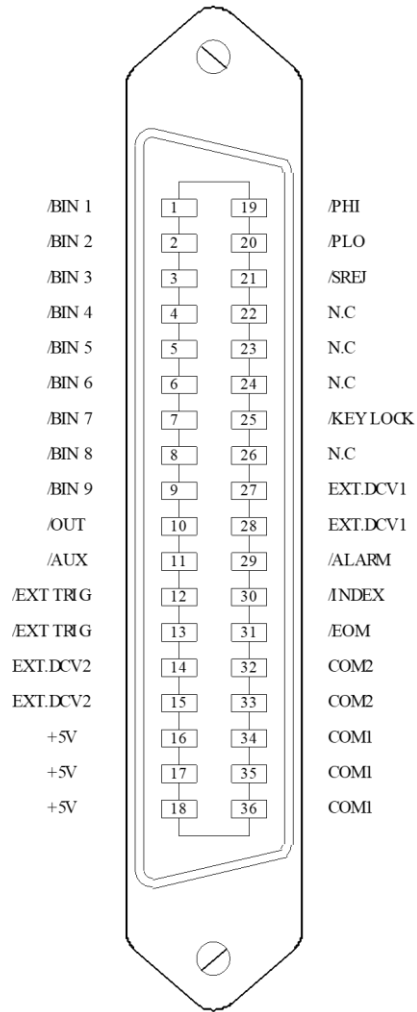


The main parameter

PHI (OUT)		
SREJ (AUX)	BIN 1	SREJ (AUX)
	BIN 2	
	BIN 3	
	BIN 4	
	BIN 5	
	BIN 6	
	BIN 7	
	BIN 8	
	BIN 9	
PLO (OUT)		

→  
The secondary parameter

Figure 1 The /PHI, /PLO, /SREJ signal distribution for BIN comparison



Note: the signal to /BIN1 - /BIN9, /OUT, /AUX, /PHI, /PLO and /SREJ in the list sweep comparison is different from that in the BIN comparison.

Figure 2 The pin definition for HANDLER

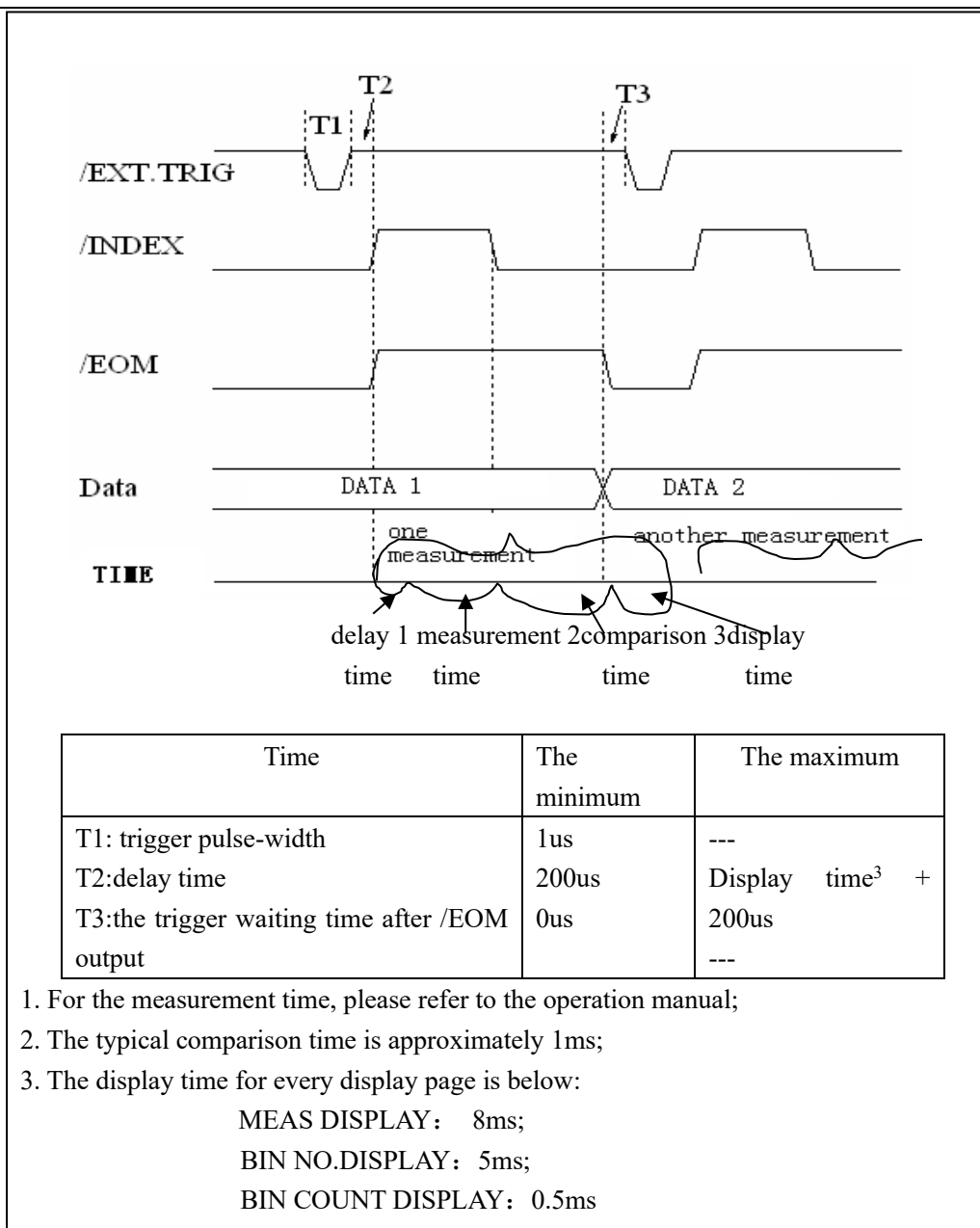


Figure 3-The timing chart

**List sweep comparison signal line**

The definition for list sweep comparison is different from that for the BIN comparison.

- Comparison output signal

/BIN-/BIN9 and /OUT show the IN/OUT (good or over the standard) judgment. /AUX shows PASS/FAIL judgement.

When a sweep test is finished, these signals will be the output signal.

- Control output signal

/INDEX (analog test finished), /EOM (the test ended).

The timing is below when /INDEX and /EOM are effective:

SEQ sweep mode:

/INDEX is defined as the effective signal when the last sweep point of the analog test is finished.



/EOM is defined as the effective signal when all the test results are effective after every list sweep task is finished.

STEP sweep mode:

/INDEX is defined as the effective signal when the analog test of every sweep point is finished. /EOM is defined as the effective signal when the test and the comparison of every step are finished.

The pin distribution for list sweep is shown in table 3 and figure 2. (The pin definition for the list sweep comparison is the same to that for the BIN comparison). The timing chart is shown in figure 5.

Table 3 the pin distribute for the list sweep comparison

pin	signal	description
1	/BIN1	out of the limit of sweep point1
2	/BIN2	out of the limit of sweep point2
3	/BIN3	out of the limit of sweep point3
4	/BIN4	out of the limit of sweep point4
5	/BIN5	out of the limit of sweep point5
6	/BIN6	out of the limit of sweep point6
7	/BIN7	out of the limit of sweep point7
8	/BIN8	out of the limit of sweep point8
9	/BIN9	out of the limit of sweep point9
10	/OUT	out of the limit of sweep point10
21	SREJ	Overall PASS/FAIL Signal
11	/AUX	/AUX is defined as the effective signal when at least one is not good in the list.
30	/INDEX	SEQ: when the analog test of the last sweep point is finished and the UNKNOWN terminal can be connected to another DUT, /INDEX is effective. But the comparison signal is effective until /EOM is effective.(see Figure 5) STEP: when the analog test at each sweep point is finished, /INDEX is effective. But the comparison signal is effective until /EOM is effective.(see Figure 5)
31	/EOM	Test ended: SEQ: when the test is finished and the compared results are effective, this signal is effective. (see Figure 5) STEP: When the test of every sweep point is finished, /EOM is finished. the comparison result signal is effective until /EOM is effective.(see Figure 5)
others		The definition is the same to that of the comparison.

/BIN1 /BIN2 /BIN3 /BIN4 /BIN5 /BIN6 /BIN7 /BIN8 /BIN9 /OUT



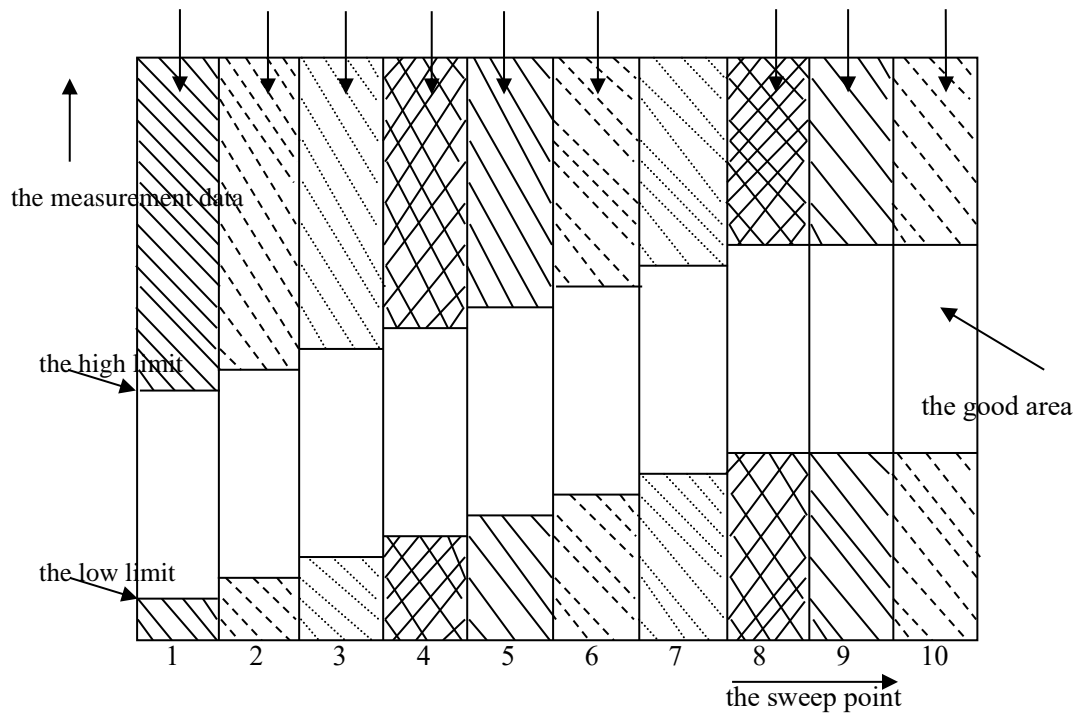


Figure 4 the signal area of the list sweep comparison

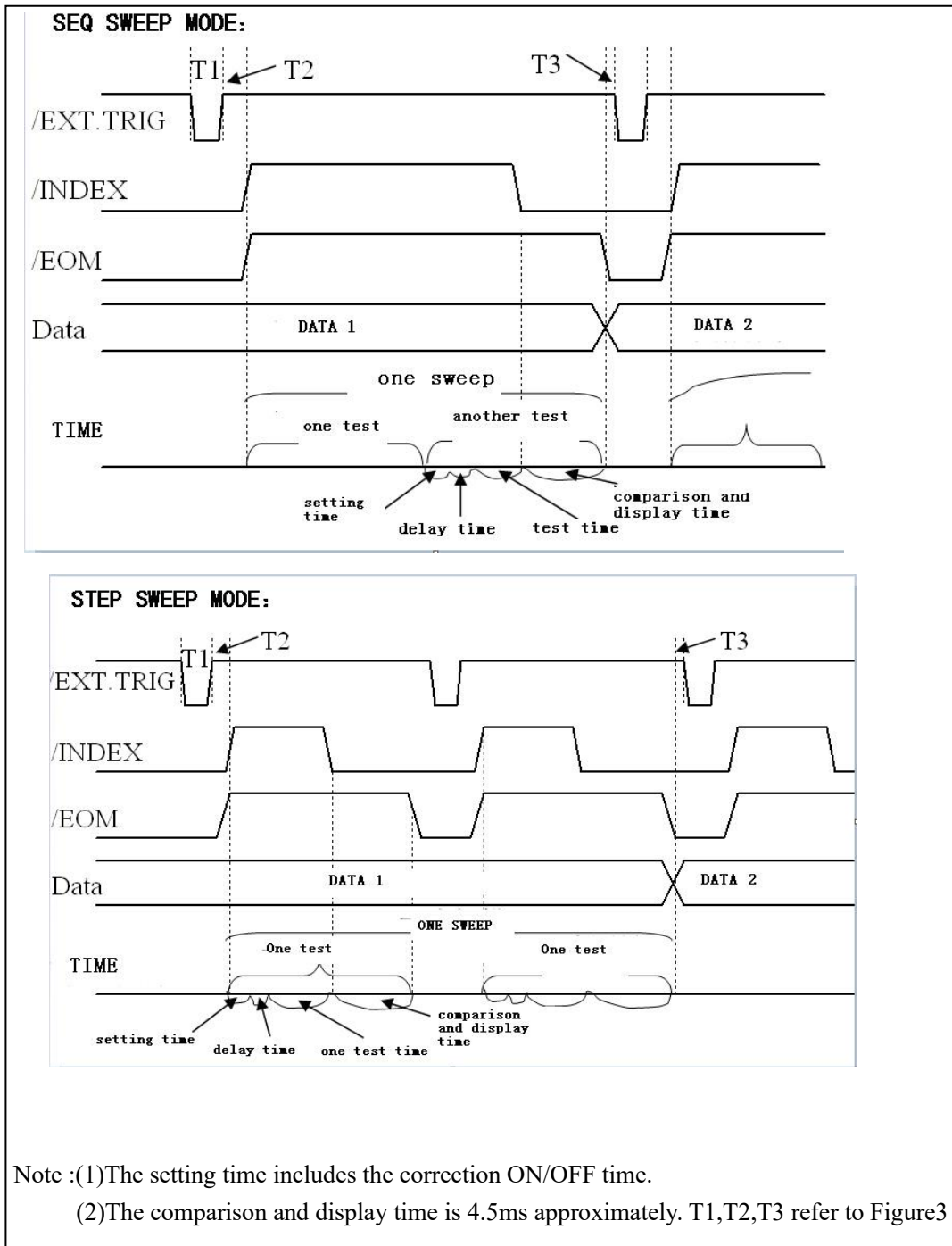


Figure 5 the time counting

### 8.2.3 Electrical feature

As it is shown above, the signal definition for the comparison and the list sweep comparison are different. But the electrical feature is same. So the description can be applied to BIN comparison and list sweep comparison.

DC isolation output: the DC isolation output (pin1 to pin16) generates the isolation by the optoelectronic coupler with the collector open. The output voltage on every line is set by the pull-up

resistance on the HANDLER interface board. The pull-up resistance is connected to the internal voltage (+5v), or the external voltage (EXTV: +5V).

The electrical feature of the DC isolation output can be divided into 2 types shown in Table 4.

Table 4 the electrical feature of the DC isolation output

the output signal	the output rated voltage		the maximum current	the reference ground for the circuit
	LOW	HIGH		
compared signal /BIN1 - /BIN9 /AUX /OUT /PHI /PLO	$\leq 0.5V$	+5V--+24V	6mA	Internal pull-up voltage: TH2817B+ GND  EXTV1: COM1
control signal /INDEX /EOM /ALARM	$\leq 0.5V$	+5V--+24V	5mA	Internal pull-up voltage : TH2817B+ GND  EXTV2: COM2

#### 8.2.4 HANDLER Interface board circuit

The output circuit for the comparison result is shown in the figure 6 below.

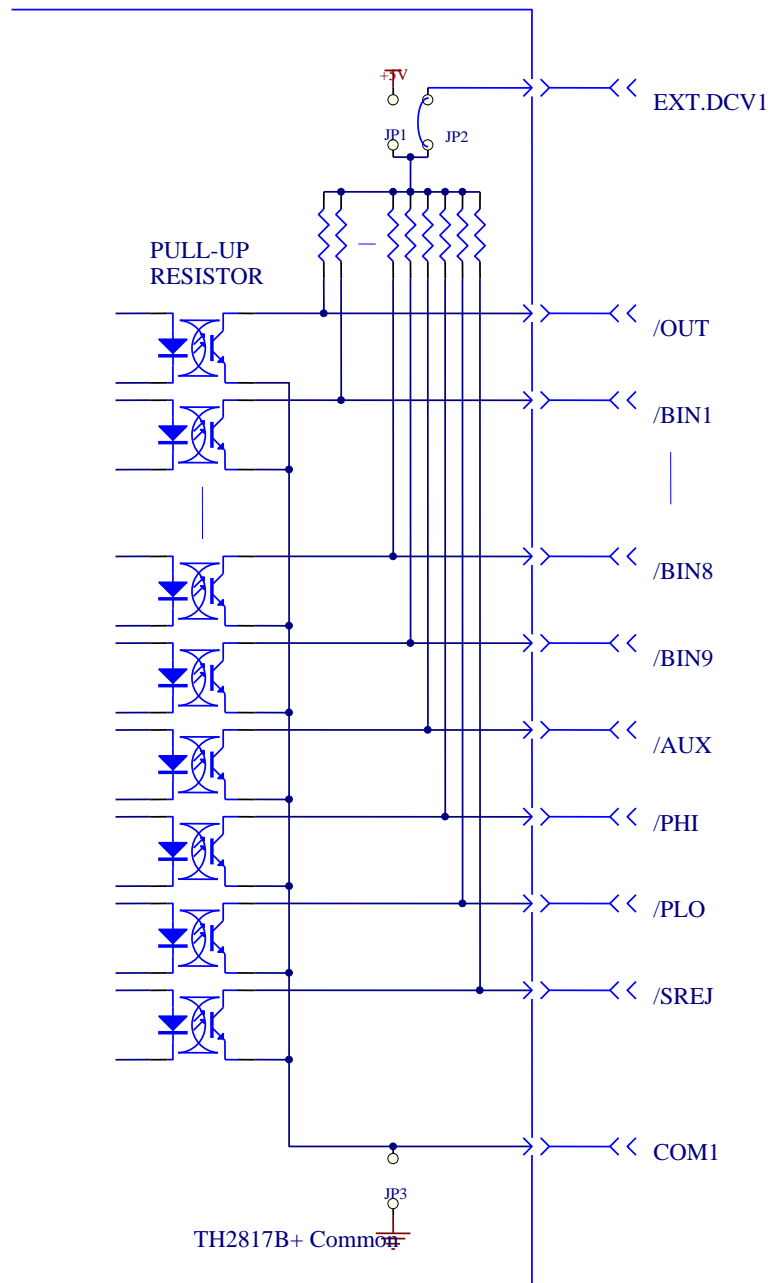


Figure 6 the output circuit for the comparison result

The output circuit for control signal is shown in the figure 7 below.

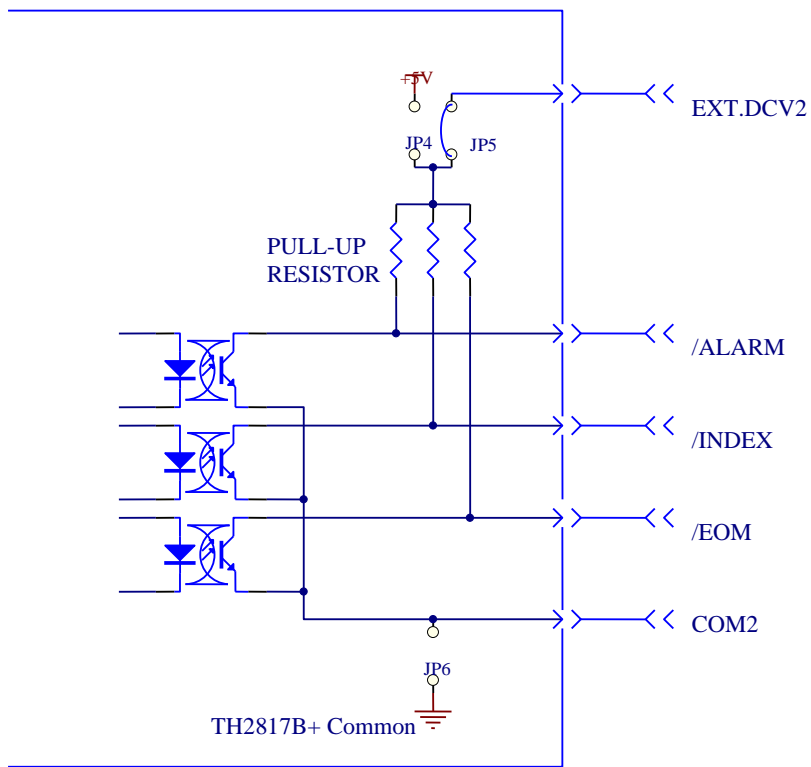


Figure 7 the output circuit for control signal

The input circuit for control signal is shown in the figure 8 below.

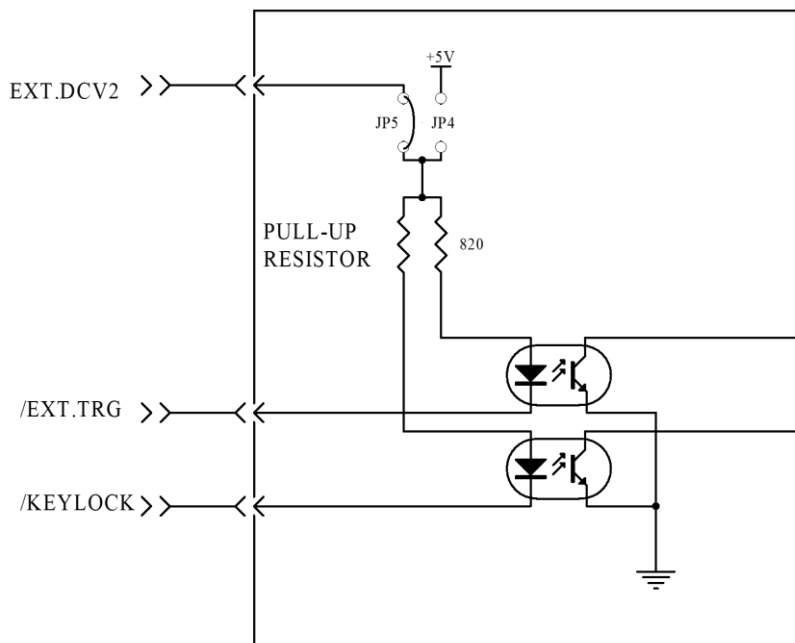


Figure 8 the input circuit for control signal

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## 8.2.5 Operation

Before you use the HANDLER function, you should ensure that your instrument has install the HANDLER interface board. The following procedure will show you how to use the interface comparison and the list sweep comparison.

The procedure for comparison setting :

- (1) Press the softkey [LIMIT TABLE]. LIMIT TABLE SETUP page will be displayed.
- (2) Set the standard value and the high limit and the low limit in LIMIT TABLE SETUP.  
Refer to the LCR menu key description to see more details.
- (3) Move the cursor to COMP field. The softkey area will display :
  - ON
  - OFF
- (4) Press the softkey ON to enable the comparison function.
- (5) Press [DISP], and then press the softkey BIN NO. or BIN COUNT, the DUT will be tested; at the same time, you can set the counter for the DUT and the auxiliary.

Note: COMP ON/OFF can be set in BIN COUNT page.

The procedure for list sweep comparison:

- (1) Press LIST SETUP, LIST SWEEP SETUP page will be displayed.
- (2) Set the sweep mode, sweep frequency point, reference value, the high limit and the low limit. Refer to the LCR menu key description to see more details.
- (3) Press [LCRZ]. and then press the soft key LIST SWEEP, LIST SWEEP DISP page will be displayed. Refer to the LCR menu key description to see more details.

Note: the following methods can be used to improve the speed:

- (1) Set the range to the maximum that the capacitance may be, and lock this range.
- (2) Set Vm: OFF and Im: OFF in the MEAS SETUP page.
- (3) Test the DUT in the BIN COUNT page.